A Complete Bibliography of Publications in *Technometrics* for the decade 1990–1999

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26 June 2014
Version 1.00

Title word cross-reference

(≥ 2) [Sin92]. 2^{k-p} [BH97, Bis94]. $2^{k-p} \times s$ [BS97]. 2^n [SWC97]. 2^{n-k} [SCF97]. 2^{n-p} [SWC97]. 3 [Ber98]. * [DL90a]. C_P [Mal95, vdVtBM97]. D [AB97, DJ94, Ney94]. D_s [AB97]. F [Ano00, SBD98]. k [Ode90, Sin92]. $k(\geq 2)$ [Sin83]. L_p [Spo90]. M [Gri97b, Ode90]. $N \neq 2^k$ [LIV96]. P [GK90, ME99, Cha93, Lin93a, Lin95a, ZM94]. $\prod$ [Bre91a, Bre91b, Fri91, Gu91, HT91]. X [WJ92]. Y [WJ92].

- [AB97]. **-D** [Ber98]. **-efficient** [Lin95a, Lin93a]. **-Estimators** [Gri97b]. **-Norm** [Spo90]. **-Optimal** [DJ94]. **-Optimality-Based** [Ney94]. **-Optimum** [AB97]. **-Spline** [ME99]. **-Value** [Cha93].

1 [Fam95, Zie98o]. **100** [Zie94a]. **101** [Zie99a]. **1750** [Zie92a]. **1930** [Zie99b]. **1984** [Zie91f, Zie91e]. **1988** [Zie90d].

2 [Ber96b, Sch93a, Zie98p, Zie99-44]. **20th** [Bro90b]. **25** [Sin92]. **29** [Ste90b].

3 [Fox91, Kus93, Sar93, Zie99-45]. **31** [BT98]. **34** [HR94]. **35** [DPL+94, Lin95a].

40 [Sen99b].

5 [Zie90f, Zie99n]. **5.0** [Zie96m].

84g [Sin92]. **88e** [Ste90b].

9000 [Zie93n]. **90f** [BT98]. **'92** [Zie95r]. **94c** [DPL+94]. **'96** [Zie98u]. **97** [Zie99k]. **99h** [Sen99b].

Aage [Kel97]. **Abarbanel** [Sti97]. **Aberration** [BS99, HCV98, SCF97]. **Abraham** [Zie98-35]. **Abrupt** [Rie94a, Yas95]. **Abuse** [Zie90z]. **Accelerated** [BE94, DH92, EM95, ML95, MEL98, MM94, Sch91c, Spe91, Mee91b, Sam90]. **Acceptance** [HL95, MT92, Tan93, Wes90]. **Acceptance-Sampling** [MT92]. **Accompany** [Gun90]. **Accountants** [Zie95-40]. **Accumulation** [Hab90, HW90b, HW90a, Hir90, Nai90b, YDB90]. **Accuracy** [CB93, ES94, OUH93]. **Accurate** [AKO94]. **Achieving** [Dun96]. **Action** [BL94]. **Active** [VS96, VS98]. **Adams** [Zie95-50]. **Adaptive** [HP97, Har92a, ST90a, Zha94, Har91d, Por97b]. **Added** [Coo96a]. **Added-Variable** [Coo96a]. **Additional** [ES94, Nel93]. **Additive** [dV92]. **Adelchi** [DeV99, Lei99]. **Adequacy** [Zie94c]. **Adhikari** [Loh94]. **Adjusted** [Ano91f, Haw91b]. **Adjustment** [BK92a, BK92b, BL94, JV93, Luc98, LG99, Mac92, Tuc92, VV92, WG92, Cha93, Fal99]. **Administrators** [Pro93b]. **Adrian** [DeV99]. **Adrienne** [Bru94]. **Advanced** [Ada96, Dea95, Tho90a, Zie94d]. **Advances** [Wol96, Zie96-34, Tor99, Zie94e, Zie96a, Zie98c, Zie98d, Zie98e]. **Advection** [MS95]. **Advection-Dispersion** [MS95]. **Adventures** [Wen93]. **Afifi** [Zie92e, Zie97h]. **Aft** [Rol93, Zie99o]. **after** [GS92]. **Aggarwal** [Kha95]. **Agresti** [Hap91]. **Ahlbom** [Zie95i]. **AI** [Zie95c]. **Aided** [And90, LaL95, WC92, Zie98f, Zie92e, Zie97h]. **Air** [GK93]. **Aitken** [Zie96-42]. **Aitkin** [Moo91]. **Akaike** [Zie99-36, Zie99-36]. **Alain** [Cab98]. **Alan** [Hap91, Lee90, Sea94, Win93, Zie98r]. **Albert** [Eas90, Goo92a, Zie98-34, Zie98i]. **Alberto** [Fal99, Job99, Lei91]. **Albright** [Zie99z]. **Alessandro** [Dog99]. **Alexander** [Goo95, Jac95, Sha97a, Weh91]. **Algebra** [Zie98-30, Zie99w]. **Algorithm** [Kus98, MN95, QY98, RvD99]. **Algorithmic** [Mad96, Ngu96a, TFV93, VTFD92]. **Algorithms** [LW97, Was97, Jon92, IHMT95, Sar90, Wol91]. **Aliasing** [CHW97]. **All-or-None** [VV94]. **Allan** [Mul97, Nan94, Sar94a]. **Alldredge** [Zie94m]. **Allen** [Gra90, Bax92]. **Allison** [Zie97-38]. **Allocation** [ES94, Yin91]. **Alreck**

[Zie99-52]. **Alsultan** [Zie99y]. **Alsup** [McL95]. **Alternative** [Fai94]. **Alvin** [Boo98, Mat96]. **American** [Lew92, Zie99-33]. **Amitava** [Bem96]. **Amount** [McA90]. **Analyses** [Bar92a, Ko95a, Sch91c, VV99, Dri92, Mee91b, Zie97y]. **Analysing** [Zie96b]. **Analysis**
[ACV99, Alb93, Alt99, Ano99e, Bar95, Bas97, Bax96b, BNC87, BS97, Bla94, Bow91, Boy90, Boy96, Bro92, Bry92, Cab94, Cal94, Cam90, Car97, CHB90, Che94, CH96a, Chi91, Chu91, Cob91, Cox93, Cox96, CB94, Dea91, Deh90, Dic91, DS93, Dre91, Elt90, Emp99, Eub90, Fai91, Far97, FL97, Fot96, Fox98, FL95, Fre95, Gle91, Goo95, Got92, Gra98, Gre98, GC91, Gru90, Hab90, Hag96, HW90b, HW90a, HW91, HS93, Han98, Hap92, Har92a, Has91, Hec96, Hir90, Hir96, HS97, Jac95, Jol90, KLR91, Kia92b, Kia93b, Kii92, KTTS90, LN95, Law98, Lee99, Lin92, Lwi94, Lyn97b, Lyn99, MW90, Maz93, McA90, MEL98, MME98, Mil90, MMY93, MS95, Nai90b, NW93, Nel93, OUH93, Pap95, Per92, Per98, Pet93, Pet99, Pri98, Pro92a, Rao98]. **Analysis**
[Ray93, Rig93, STC99, Sau98, Sch95, Sch96b, Sch93c, Sch93b, Sch91d, Sco91, Sha97c, Sim91, Sri92, Ste91, SP95, Taa91, Tam96, Tan98, Tom95, Vin92, WL97, Wat96, Weh95, Wel90, WN97, YDB90, Yas92, ZP94, Zie90-27, Zie90v, Zie90q, Zie90f, Zie90b, Zie91q, Zie91h, Zie91o, Zie92f, Zie92q, Zie93h, Zie93g, Zie93f, Zie94o, Zie94-29, Zie94p, Zie95y, Zie95j, Zie95-46, Zie95-50, Zie95-36, Zie96m, Zie96t, Zie96i, Zie96-29, Zie96-39, Zie96-38, Zie96l, Zie97-38, Zie97x, Zie97p, Zie97-36, Zie97c, Zie97j, Zie97z, Zie97-30, Zie97-40, Zie98-44, Zie98g, Zie98r, Zie98b, Zie99-38, Zie99-31, Zie99i, Zie99d, Zie99x, vN90, Bay99, Ber92a, Boo97, DeV99, Dea94, Dov93, Geo94, Geo98, Gol99, Goo92a, Gra90, Gro99, Gun99, Had92, Ham96, Han90, Han97, Hap91, Hec95, Hei90, Job99]. **Analysis**
[Jol93, Koh94, LaL95, Lin90, Liu92b, Mat96, Mat97, Mat98, Nai94, Nan94, Not92b, Por93, Pri93, Ruk97a, Sam99b, Sau94, Sch96a, Sch96c, Sen94b, Ter92, Tim95, Ver90, Web90, Win90, Wol96, Zel94, Zha92, Zie90o, Zie90c, Zie92k, Zie92e, Zie93-27, Zie94u, Zie94f, Zie94x, Zie94-36, Zie95-48, Zie95v, Zie95l, Zie96-50, Zie96a, Zie96c, Zie97h, Zie97r, Zie97l, Zie97f, Zie97-36, Zie97-33, Zie97t, Zie97-37, Zie98-39, Zie98m, Zie99-34, Zie99c, Zie99-35, Zin93, Car95, Cra94, Kia93a, Len93, Sti97, Tsa91, Zie91q, Zie95d, vT91]. **Analysis-of-Means-Type** [WN97]. **AnalysisPart** [Sha95]. **Analysts** [LeP90b]. **Analytic** [BR95]. **Analytical** [Hil95, LaL95, RL95, Zie93l]. **Analyzing** [CHW97, Pat91, Gro96]. **and/or** [CR91]. **Anders** [Kel97, Zie92a, Zie99b]. **Andersen** [Kle94, Sau98, SG99]. **Anderson** [Moo91, Gre94, Hap92, Lee90, Zie94-36]. **Andor** [Sea91]. **Andre** [Zie94d, Zie97y, Zie98t]. **Andreas** [Zie98-46]. **Andrej** [KB94]. **Andrew** [Ang92, Cox96, Ens95, Han98, Lar95, Pri93, Zie97-33]. **Andrzej** [Mor93b]. **Ani** [Loh94]. **Anil** [Mat98, Sar90]. **Ann** [Soy95, Zie99r]. **Anne** [Bor97b, Gun90]. **Annealing** [Deu96]. **Annie** [Bor97b]. **Announcement** [Mor98b]. **ANOVA** [BT98, BT89, Van92b, Nai96, Zie93b]. **Ansell** [Han97]. **Anthony** [Cal94, LeP90a]. **Antoniadis** [Zie97-43]. **Anxiety** [Cly94]. **Any** [Zie99a]. **Anyone** [God90]. **Aoki** [Zie98f, Zie92p]. **APC** [HP92].

Application
[Ano98e, BCL98a, BCL98b, CR98, DP97, ET96, Jen92, Kaf94, Lam92, LT96, Oma91, Rob98, Sch98a, SP95, TH93, VTFD92, Bor98, Der90, Rie94a, Zie98v].
Applications
[Ber96a, Boo90, Bow91, Bru93a, Cal94, CR96, Cox96, CC95, Dea97, Gla98, Hag90, HR92, Hea94, HL97, Kan95, LaL92, LPR92, LW97, LLP+99, LN96, McC94, Nan94, OM96a, OM96b, Pig91, Rie94b, Smi93, Spe96b, Ste91, Swe96, Tho90a, Tuc96, Weh91, Won98, Wyc96, Zie92a, Zie94d, Zie94-27, Zie96-37, Zie99w, HR94, Zie95-50, Zie98s, Bar92b, Bar95, Bax92, Bax96a, Boo94b, Boo98, Bro90a, Chi91, Dea95, Dob96, Fai91, Gri99, Gue90, Jac95, Jon91a, Kah94, Kir92, LuV90, Mas99, Mil90, Mor93a, Not92a, Sar94b, Sin97, Tor95, Van92a, Was97, Zie91d, Zie92m, Zie95o, Zie95y, Zie98d, Zie99e, Jon90, Zie98f, Zie98g].
Applied [Bil91, Dre91, Goo91, Gra94, Jam96, Liu92a, Mat98, Mor93b, Nel95, NO96, Rie97, Sau97, Sen94b, Ste96a, Ste96b, Ver90, WVYB97, Zie91j, Zie91b, Zie94t, dVU96, Zie97-44, Ale95, Cuc92, DeV99, Dri92, Elt90, Eub93, Gas94, Gol99, Gra98, Gri97a, Gun99, Han98, Hec95, Jan94, Kia90, Kia92b, Kia93b, LC98, Lyn97b, Mar97, Nai94, Rag91, Ste98, Tho99, Wat90, Win90, Woz91, Zie90b, Zie90c, Zie90a, Zie92b, Zie93c, Zie95e, Zie96d, Zie96c, Zie97-44, Zie98h, Zie99c, Zie99d, vN90]. **Apply** [Pro92a]. **Applying** [Che98].
Approach [Cam98, CHW97, CM93b, CM93a, EH96, FL97, Gri96, Gun93, HO93, Hah93, Hec96, HLD98, LST93, ME99, Mar99, Mil94, Mor92, Ngu96a, Pet93, Sam99a, Ste99, Tho90b, USM99, VS96, VM91, Won92, Zie93-34, Zie94j, Zie95b, Ada91, Bal93, Bor97c, Boy90, Bul96, Deh90, Edg92, Fre92, Gre94, Haw90, Lar95, Liu92a, Lyn95, Mad96, MA92, Qiu95, Sar94a, Stu94, Vin92, Wil98, Zie91j, Zie93-29, Zie94t, Zie94s, Zie94z, Zie95-29]. **Approaches** [Ale98, Sim97]. **Appropriate** [HC91]. **Approximate** [CDKS92, DS93].
Approximation [KM99, Jol90]. **ARCH** [Zie99e]. **Archer** [Zie99-48].
Archetypal [CB94]. **Architecture** [Ara92]. **Argentesi** [War90]. **Arising** [MS95]. **Arlene** [Zie96-47, Zie99-52]. **Arlinghaus** [Zie98-33]. **Armed** [Yin91]. **Armstrong** [Zie97n, Zie90i, Zie92h]. **Arnljot** [Van96b]. **Arnold** [Bax92, Far93, Zie99-37, Wol92]. **Arrays** [HS99, Ngu96b, WW92]. **Art** [Gut92]. **Arthur** [Gil92, Law98, Spo90, Zie98f, Fai91]. **Articles** [Bor97a].
Artificial [Zie95f]. **Ashish** [Chi91]. **Aspects**
[MS90, O'D97, Zie98-41, Zie94-28, Bas99, Zie95g]. **ASQC** [Zie97o, Zie97-31].
Assembled [Bis97]. **Assessing** [TC90]. **Assessment**
[Dow94, GD94, Got94c, Got94b, Jou94, Liu99, Rut94, Tor94, Wad99, WB94, Zie95n, Zie99-28, Pla96, Zie91n, Zie95m, Zie98y, Zie99j]. **Assessments** [Zie90y]. **Assignments** [Zie91b]. **Association** [Jol97]. **Assumed** [DJ94].
Assumption [Kun97]. **Assumptions** [Col92, Lau94b]. **Assurance**
[Lew92, Spa99, Zie93l, Zie99-33, Bru93b, Gan97, Jai95, Sea94, Sha92].
Astrom [Har91d]. **Astronomy** [Zie98g, Coa94]. **Astrostatistics** [Sin98].
Asymptotic [Ang90b, Ano90f, SS89]. **Asymptotically** [Sch92b].
Asymptotics [SP95]. **Athanasios** [Gro92]. **Atkinson** [Whe93].
Atmospheric [Ram96, Zie96-38]. **Attributes** [Car93, NW93]. **Auditing**

[Zie96q]. **Augmenting** [RH95]. **Autocorrelations** [ZP94]. **Automated** [Kir93, Run90]. **Availability** [Pla96]. **Avenhaus** [Dav99, War90]. **Average** [Bax90, DP91, FHT90, Gan95, Hes95, Hun90b, LWCR92, LS90b, LS90c, MH90, Van96a, WM90]. **Averill** [Dea94]. **Award** [Zie96-46]. **Ayton** [Zie95-42]. **Ayyub** [Bry99]. **Azzalini** [DeV99, Lei99].

B [Alb93, Bar92b, Ber97, Bod97, Bru95, Bzi97, Cox96, Cra94, Die92, Dow95, Edg92, Ful97, Gri90, Hap92, Har91d, Hin97, Jam96, Jen92, Jen93, Koe92, Lee99, Mac90a, MA92, Ord96, Pri93, Qiu95, Run90, Rut93, Sau97, Sau98, Smi91, Spa99, Tsa91, Zie91c, Zie92t, Zie93j, Zie94u, Zie94e, Zie94-38, Zie96q, Zie96-37, Zie96-40, Zie96g, Zie96s, Zie96z, Zie97p, Zie98-36, Zie98g, Zie98b, Zie98w, Zie99-52]. **Baafi** [Zie98u]. **Babu** [Sin98, Coa94]. **Back** [Ano90a, Ano90b, Ano90c, Ano90d, Ano91a, Ano91b, Ano91c, Ano91d, Ano92a, Ano92b, Ano92c, Ano92d, Ano93a, Ano93b, Ano93c, Ano93d, Ano94a, Ano94b, Ano94c, Ano94d, Ano95a, Ano95b, Ano95c, Ano95d, Ano96a, Ano96b, Ano96c, Ano96d, Ano97a, Ano97b, Ano97c, Ano97d, Ano98a, Ano98b, Ano98c, Ano98d, Ano99a, Ano99b, Ano99c, Ano99d]. **Backwards** [Ano90e, Sim88]. **Backwards-Stepping** [Ano90e, Sim88]. **Badavas** [Zie94-34]. **Badoux** [Zie96e]. **Bailar** [Zie98-42]. **Bain** [Bry92]. **Bajaria** [Pro93a]. **Bakeman** [Ber92a]. **Balakrishnan** [Far93, Sin97, Ber96b, Fam95, Glo93, Pos98, Sen97, Zie96-34, Zie98d, Zie98e]. **Balanced** [AD96, BT89, Van92b, Zie98-45, BT98]. **Baldeo** [Joh91]. **Baldrige** [Zie96-46]. **Band** [Luc98, LG99]. **Bandit** [Yin91]. **Bands** [Dal90, Spu93]. **Banks** [Mil91, Zie98o, Zie98p]. **Barbara** [Bel95]. **Bare** [Kal93, Kal93]. **Barker** [Edg92, Zie95-30]. **Barkman** [Pla90]. **Barlow** [Gru95, Hes91, McC99]. **Barnard** [Die92]. **Barndorff** [Zie94-28, Har91c, Zie97-42]. **Barndorff-Nielsen** [Har91c, Zie97-42]. **Barndorff-Nielson** [Zie94-28]. **Barnes** [Boy90]. **Barnett** [Bre95b, Cam98, Zie94-42, Zie99-45, Zie99-44, Min93]. **Barrentine** [Jen93]. **Barrett** [Bru92a]. **Barrie** [Col93]. **Barry** [Bor97c, Far93]. **Bartell** [Zie94q]. **Bartoszynski** [Cha98]. **Based** [Ano91f, Boy90, CWWR97, CH96b, DH92, EMSD91, EM99, GK90, Glo95, Gri96, Haw91b, Kle94, Lei99, MS90, Mee90a, ML95, Ney94, ST90a, Sen98, Sin83, YE94, Zie99-31, Sen99b, Sin92, Cha93]. **Basford** [Raz91]. **BASIC** [Tho90a, Mil94, Moo96, Zie94-45, LC94, Nem92, Zie94h, Zie94g, Zie97b]. **Basics** [Zie98-46, Zie91h]. **Basilevsky** [Jac95]. **Basseville** [Rie94a]. **Basu** [Sin97]. **Batch** [MB98, NM95]. **Batches** [RH92]. **Bates** [Mil90]. **Batteries** [Wal92b]. **Battery** [Tho94]. **Bayes** [Ang91a, Ruk97a, MKA96, Ruk97a]. **Bayesian** [Deh90, Fox98, Rie97, Sam99b, Yak97, Zie96h, Zie98l, Zie99-27, CH96a, CHW97, CDKS92, DJ94, EMS98, HS93, MW90, MMY93, MT92, USM99, Ber92b, Fox91, Gru90, Gue90, Mar99, Ruk98, Wel90, Wes92, Zie96e, Zie97e, Zie97c, Zie97d, Zie98j, Zie98i]. **Beating** [Smi91]. **Beauregard** [Bel95]. **Bebe** [Kal93]. **Bechhofer** [Tam96]. **Becker** [Sco90]. **Beckman** [Ano90g]. **Beebe** [Tob99]. **before** [Zie92a]. **Beginning** [Lee94]. **Behavior**

[ST90b]. **Behnken** [Bor95a, DDPG94]. **Belief** [Ter92]. **Bell** [Law98]. **Belle** [Zie94i]. **Belsley** [Gol93]. **Bemowski** [Zie99a]. **Benchmarking** [Zie96f]. **Bendat** [Nan94, Taa91]. **Benjamin** [Fre95]. **Bennett** [Beg90]. **Benson** [Pit92]. **Bent** [Bor95b, Sen99a]. **Benzecri** [Zie93g]. **Beran** [Glo97]. **Berenson** [Wat90, Zie96-52]. **Berestizhevsky** [Zie99-31]. **Berger** [Ang91c, Zie93v, Zie96-40]. **Berk** [Zie97j, Zie99i]. **Bernard** [Cob91, Geo98, Har91b, Lal99, Zie90x, Zie97-35]. **Bernardo** [Fox91]. **Bernd** [Bay92]. **Bernhard** [Haw90]. **Berry** [Har91b, Zie91r, Zie97-35, Zie97c, Zie97d, Lau94b]. **Berthouex** [Gat96]. **Bertram** [Maz93]. **Best** [Pro92b, Kin91, PBR92]. **Besterfield** [McC91]. **Beta** [Roc93, Zie91c]. **Beth** [Tob99]. **Bethea** [Bzi97, Jan94]. **Betteley** [Pan96]. **Better** [Alm95, Bre95a, CR93, Kel97]. **Betty** [Kim91]. **between** [Arm90, Atk96, Box90, DL90a, God90, Hah90, HK90, Hoo90, Hun90a, KMP95, Mac90b, Moo90, Sch91d, SW95, Tri90, Wan90, Zie95y]. **beyond** [Kra90]. **Bhattacharya** [Kir92]. **Bhattacharyya** [Boo93]. **Bhote** [Hoc94]. **Bible** [Car96, Spe96a]. **Biemer** [Zie90-28, Zie93r, Zie98-43]. **Bilal** [Bry99]. **Bilateral** [God95]. **Billard** [KR93]. **Bimal** [Roh91]. **Binary** [ET96, Tho93, Zie91q]. **Binder** [Zie96g]. **Binomial** [EMSD91, MW90]. **Bioavailability** [Zie94p]. **Bioequivalence** [Zie94p]. **Biological** [Zie93-28, Zie94-37, Zie96t]. **Biology** [Tho90a, Zie98-42, Nik93, Zie98-36]. **Biometry** [Zie94-27]. **Biostatistical** [Tso92, Zie95-27]. **Biostatistics** [Zie94-30, Zie96v, Zie97d, Zie94i, Zie95i, Zie95h]. **Biotechnology** [Jen91]. **Biplot** [SC93]. **Biplots** [Tro97]. **Birkes** [Fai94]. **Birnbaum** [RN91]. **Birolini** [Dog99]. **Bishop** [Web90]. **Bissell** [Boo94a]. **Bivariate** [GI92, Not92a, Not92c, Wel93]. **Bjørn** [SG99]. **Blaisdell** [Lyn94]. **Blank** [Hem99]. **Block** [Hol98, Khu92, Ngu94]. **Blocked** [Bis94, SCF97]. **Blocking** [Ros99, SWC97]. **Blocks** [DPL$^+$93, Hol98, DPL$^+$94]. **Bluman** [Sar94a]. **Bob** [Zie95w, Zie98-31]. **Bolasco** [Zie92k]. **Bond** [Zie90-27]. **Bonett** [Gil92]. **Book** [Aba98, Acr97, Ada91, Ada92, Ada93, Ada94, Ada96, Ajm99, Alb93, Ale91, Ale95, Ale98, Ale99, All96, Alt96, Alt99, Amm92, And90, Ang90a, Ang90b, Ang91a, Ang91b, Ang91c, Ang92, Ara92, Arm92, Arm93, Arm97, Arn90, Aye98, Bab98, Baj98, Bak98, Bal93, BR95, Bar91, Bar92b, Bar92a, Bar95, Bas90, Bas97, Bas99, Bat99, Bax92, Bax95, Bax96b, Bax96a, Bay92, Bay95, Bay99, Beg90, Bel95, Bel99, Bem96, Ben93, Ber91, Ber92a, Ber96b, Ber97, Ber92b, Bie92, Bil91, Bil92, Bil94, Bla94, Bla92, Bli91, Bod97, Bog92, Boo90, Boo95, Boo92, Boo93, Boo94b, Boo94a, Boo97, Boo98, Boo99, Bor97a, Bor94, Bor97b, Bor95b, Bor97c, Bor98, Bos92, Bow91, Boy90, Bre95b, Bre97, Bre90, Bre96, Bri91, Bri96, Bro90a, Bro90b, Bro92, Bru91, Bru92a, Bru92b]. **Book** [Bru93b, Bru93a, Bru94, Bru95, Bru96, Bru97, Bry92, Bry99, Buc90, Bul91, Bul96, Bur91, Bzi97, Cab94, Cab98, Cal94, Cal98, Cam90, Cam96, Cam98, Car90a, Car90b, Car92, Car93, Car95, Car96, Car97, Cha95, Cha92, Cha98, Cha93, Che92, Che94, Che98, Che91, Chi91, Chr97, Chu91, Cly94, Coa94, Cob91, Coh92, Col92, Col93, Coo96b, Cox93, Cox96, Cra94, Cro94, Cro99, Cry90, Cuc92, Czi92, Das93, Dav99, DeV99, Dea91, Dea94, Dea95,

Dea96, Dea97, Deh90, Der90, Dic91, Dic97, Die92, Dob96, Dog93, Dog99, Dom90, Don90, Dov93, Dow95, Dre91, Dri91, Dri92, Dun90, Dun96, Dun97, Eas90, Eas99, Edg92, Edg98, Elt90, Emp92, Emp93, Emp97, Emp99, Ens95, Eub90, Eub93, Fai91, Fai94, Fal99, Fam95, Fam97, Fam99, Far90]. **Book** [Far92, Far93, Fot95, Fot96, Fox91, Fox94, Fox97, Fox98, Fre92, Fre99, Fre93, Fre94, Fre95, Fre97, Fri97, Ful95, Ful97, Gal95, Gal92, Gal93, Gan97, Gas97, Gas94, Gat96, GR97, Geo94, Geo98, Gho93, Gho94, Gib91, Gil92, Gla98, Gle91, Gle96, Glo93, Glo95, Glo97, Glo99, God93, God95, Goi96, Gol99, Gol95, Gol93, Gol98, Gol90, Goo91, Goo92a, Goo95, Goo92b, Got92, Got94a, Gov92, Gra90, Gra94, Gra98, Gre94, Gre98, Gri90, Gri96, Gri97a, Gri99, Gri98, Gri95, Gro92, Gro96, Gro99, Gru90, Gru95, Gru97, Gue90, Gun90, Gun96a, Gun99, Gun94b, Gun94a, Gun96b, Gut90, Gut92, Hab92, Had92, Hag90, Hag91, Hag96, Hal95, Hal98, Hal94, HH96, Ham96, Han90, Han93, Han97, Han98, Hap91, Hap92, Har91a, Har91b, Har91d, Har91c]. **Book** [Har92a, Has91, Haw90, Hea94, Hec90, Hec95, Hec96, Hec99, Hei90, Hem99, Hes91, Hes93, Hes97, Hey92, Hey98, Hey93, Hig98, Hil95, Hin97, Hoc94, Hof95, Hor98, Hul92, Huz95, Hwa92, IHMT95, Ing92, Iye98, Iye90, Ize90, Ize91, Jac95, Jai95, Jam96, Jan94, Jen90, Jen91, Jen92, Jen93, Job99, Joh91, Jol90, Jol93, Jol96, Jol97, Jon90, Jon91b, Jon91a, Jon92, Jon93, Kah94, Kal93, Kal98, Kan95, Kat91, KR93, KB94, Kat98, Ked96, Ked98, Kel97, Kha95, Kia90, Kia92a, Kia92b, Kia93a, Kia93b, Kia94, Kia95a, Kia95b, Kim91, Kin91, Kin93, Kin97, Kir92, Kir93, Kle94, Ko95b, Ko95a, Koe92, Koh90, Koh94, Koo90, KY91, Kot92, Kra90, Kra92, Kus92, Kus98, Kus93, LaL92, LaL95, Lal99, Lam90, Lar95, Lau94b, Law95, Law92]. **Book** [Law98, Law96, LC94, LC98, LeP90a, LeP90b, Lee90, Lee93, Lee94, Lee99, Lei91, Lei92, Lei93, Lei97, Lei99, Len90, Len93, Len95, Lew92, Lew93, LH97, Lin99, Lin92, Lin90, Lit91, Liu92a, Liu92b, Liu99, Loh92, Loh94, Lor92, Lor93, Lor99, LuV90, Lyn94, Lyn95, Lyn97a, Lyn97b, Lyn99, Mac90a, Mad96, Mad98, Mag90, Mag96, Mar97, Mar94, MA92, Mar99, Mas99, Mat96, Mat97, Mat98, Maz93, Maz98, McA90, McC90, McC91, McC98, McC94, McC99, McG94, McL95, Mee91a, Mee91b, Men91, Mi97, Mi99, Mil91, Mil94, Mil99, Mil90, Mil98, Min93, Moo91, Moo96, Moo99, Mor93a, Mor99a, Mor92, Mor99b, Mor97a, Mor93b, Mul97, Mye91, Mye96, Nai94, Nai96, Nan94, Nar93, Nay98, Nel98, Nem92, Nem95, Nem97, Neu99, Nik93, Nik95, Nip92, Not92a, Not92c, Not92b, O'D97]. **Book** [O'D99, Oli97, Oli98, Ord96, Osb97, Ott90, Owe91, Owe96, Pan92, Pan96, Pap95, Pap96, Par92, Pat91, Ped98, Per92, Per98, Per97, Pet99, Pfa92, Pfa99, Pie90b, Pie90a, Pig91, Pit92, Pit96, Pla90, Pla96, Pol93, Por93, Por97b, Por97a, Pos98, Pot93, Pri93, Pri98, Pro90, Pro92b, Pro92a, Pro93a, Pro93b, Pro94, Pro96, Qiu95, Rab92, Rag91, Rag93, Rag95, Ram99, Ram93, Ram91, Ram94, Ram96, Rao98, Ray93, Raz91, Rea93, Rie94b, Rie94a, Rie97, Rig92b, Rig92a, Rig93, Rig99, Rob90, Roh91, Rol93, Roz93, Ruk97a, Ruk97b, Ruk98, Run90, Rus94, Rut93, Sac93, Sai96, Sam90, Sam99b, Sam99a, San98, San92, San99, Sar90, Sar93, Sar94b, Sar94a, Sau92, Sau94, Sau97, Sau98, Sch91a, Sch92a, Sch96a, Sch91b, Sch95, Sch92c, Sch93a].

Book [Sch94a, Sch96b, Sch92d, Sch93c, Sch93b, Sch94b, Sch96c, Sco90, Sco91, Sco92, Sea90, Sea91, Sea93, Sea94, Sen99a, Sen94b, Sen94a, Sen95, Sen97, Sha92, Sha93, Sha95, Sha97c, Sha97b, Sha97a, Sha98, She90a, She90b, Sho90, Sim97, Sim91, Sin90a, Sin90b, Sin97, Sin98, Smi91, Smi93, Soy95, Spa99, SN95, Spe96a, Spe91, Spo90, Spr91, Sri92, Sri93, Ste90a, Ste91, Ste90c, Ste98, SG99, Ste99, Sti97, Sto96, Sto92, Str96, Stu94, Sys99, Taa91, Taa99, Tam96, Tan98, Tan93, Ter92, Thi91, Tho99, Tho90a, Tho93, Tho90b, Tho92b, Tim95, Tim96, Tim99, Tob99, Tom95, Tor95, Tor99, Tro97, Tsa91, Tso92, Van92a, Van91, Van96b, Ver90, Vin92, Voe94, Vuk98, Wad99, Wal92a, Wal92b, Wan94, War90, Was91, Was97, Wat90, Wat96]. **Book** [Web90, Weh91, Weh93, Weh95, Wei90, Wei94, Wel90, Wel93, Wen93, Wen94, Wes92, Wha95, Whe93, Wil90a, Wil90b, Wil98, Win90, Win93, Wit94, Wol91, Wol96, Wol92, Won94, Won98, Woo91, Woo92, Woz91, Wu99, Wyc96, Yak97, Yan96, Yan97, Yeh93, Yin91, Zei94, Zel94, Zha92, Zie90l, Zie90p, Zie90-28, Zie90x, Zie90-27, Zie90i, Zie90m, Zie90o, Zie90v, Zie90h, Zie90q, Zie90j, Zie90z, Zie90e, Zie90y, Zie90s, Zie90d, Zie90f, Zie90n, Zie90t, Zie90r, Zie90w, Zie90u, Zie90b, Zie90c, Zie90a, Zie90k, Zie90g, Zie91g, Zie91n, Zie91i, Zie91m, Zie91q, Zie91r, Zie91p, Zie91l, Zie91k, Zie91f, Zie91e, Zie91a, Zie91c, Zie91j, Zie91d, Zie91b, Zie91h, Zie91o, Zie92b, Zie92j, Zie92f, Zie92a, Zie92t, Zie92h, Zie92g, Zie92d, Zie92q, Zie92k, Zie92e, Zie92c, Zie92x, Zie92i]. **Book** [Zie92r, Zie92w, Zie92v, Zie92p, Zie92m, Zie92l, Zie92n, Zie92o, Zie92u, Zie92s, Zie93-30, Zie93e, Zie93c, Zie93j, Zie93t, Zie93b, Zie93-28, Zie93-31, Zie93o, Zie93w, Zie93l, Zie93-37, Zie93p, Zie93v, Zie93h, Zie93d, Zie93x, Zie93-33, Zie93r, Zie93-29, Zie93m, Zie93z, Zie93-27, Zie93-38, Zie93a, Zie93u, Zie93q, Zie93k, Zie93g, Zie93f, Zie93i, Zie93s, Zie93-32, Zie93-36, Zie93n, Zie93-34, Zie93-35, Zie93y, Zie94o, Zie94u, Zie94e, Zie94h, Zie94f, Zie94k, Zie94-42, Zie94d, Zie94w, Zie94r, Zie94t, Zie94x, Zie94-28, Zie94-29, Zie94j, Zie94a, Zie94v, Zie94-30, Zie94-41, Zie94-39, Zie94y, Zie94-31, Zie94-45, Zie94g, Zie94l, Zie94-44, Zie94b, Zie94s, Zie94-32, Zie94-40, Zie94-38, Zie94-43, Zie94-33, Zie94-36, Zie94-37, Zie94-27, Zie94z, Zie94i, Zie94p, Zie94c, Zie94m, Zie94n, Zie94-34, Zie94q, Zie94-35, Zie95q]. **Book** [Zie95-48, Zie95p, Zie95-30, Zie95u, Zie95r, Zie95-33, Zie95g, Zie95-42, Zie95-29, Zie95d, Zie95-41, Zie95i, Zie95t, Zie95-35, Zie95-45, Zie95-31, Zie95o, Zie95-38, Zie95e, Zie95-49, Zie95-32, Zie95b, Zie95h, Zie95-40, Zie95z, Zie95s, Zie95y, Zie95v, Zie95f, Zie95l, Zie95n, Zie95j, Zie95x, Zie95w, Zie95-37, Zie95-47, Zie95-46, Zie95-28, Zie95-50, Zie95m, Zie95-39, Zie95-36, Zie95-27, Zie95-34, Zie95k, Zie95c, Zie95a, Zie95-44, Zie95-43, Zie96m, Zie96-47, Zie96-34, Zie96-32, Zie96o, Zie96q, Zie96b, Zie96-28, Zie96t, Zie96d, Zie96-45, Zie96w, Zie96-30, Zie96n, Zie96-37, Zie96-41, Zie96e, Zie96-31, Zie96-44, Zie96-50, Zie96j, Zie96-43, Zie96i, Zie96h, Zie96-40, Zie96-27, Zie96a, Zie96x, Zie96-33, Zie96-35, Zie96k, Zie96-51, Zie96-52, Zie96g, Zie96-48, Zie96-29, Zie96-39, Zie96-42, Zie96p, Zie96-38, Zie96r, Zie96s, Zie96c, Zie96u, Zie96l]. **Book** [Zie96-46, Zie96f, Zie96z, Zie96-49, Zie96-36, Zie96v, Zie96y, Zie97-39, Zie97b, Zie97h, Zie97-32, Zie97-27, Zie97-38, Zie97m, Zie97-29, Zie97s, Zie97r,

Zie97-34, Zie97-28, Zie97l, Zie97e, Zie97u, Zie97f, Zie97x, Zie97p, Zie97-36, Zie97-33, Zie97-42, Zie97-35, Zie97o, Zie97v, Zie97c, Zie97d, Zie97t, Zie97-37, Zie97-43, Zie97q, Zie97j, Zie97-41, Zie97z, Zie97g, Zie97-30, Zie97a, Zie97w, Zie97-31, Zie97k, Zie97i, Zie97y, Zie97-44, Zie97-40, Zie97n, Zie98o, Zie98-42, Zie98-45, Zie98-48, Zie98-39, Zie98h, Zie98-34, Zie98-41, Zie98-32, Zie98-27, Zie98a, Zie98-38, Zie98t, Zie98s, Zie98y, Zie98j, Zie98n, Zie98-35, Zie98q, Zie98p, Zie98-29, Zie98-47, Zie98v, Zie98-31, Zie98-33, Zie98-46, Zie98c, Zie98f, Zie98-43, Zie98l, Zie98m, Zie98-36, Zie98-44, Zie98-28, Zie98-40, Zie98g, Zie98-37, Zie98-30, Zie98i, Zie98r, Zie98x, Zie98d, Zie98e]. **Book** [Zie98k, Zie98z, Zie98b, Zie98w, Zie98u, Zie99-27, Zie99l, Zie99-42, Zie99k, Zie99-38, Zie99-31, Zie99-47, Zie99w, Zie99f, Zie99-45, Zie99-46, Zie99z, Zie99-49, Zie99-43, Zie99u, Zie99i, Zie99-28, Zie99-34, Zie99v, Zie99-29, Zie99-33, Zie99-37, Zie99e, Zie99-39, Zie99j, Zie99-36, Zie99s, Zie99c, Zie99-51, Zie99d, Zie99t, Zie99p, Zie99q, Zie99-52, Zie99r, Zie99-35, Zie99-50, Zie99a, Zie99b, Zie99o, Zie99y, Zie99n, Zie99-44, Zie99m, Zie99g, Zie99-48, Zie99h, Zie99-30, Zie99-41, Zie99-32, Zie99-40, Zie99x, Zin93, dV92, dV93, dC99, vN90, vT91, vT95]. **Boostrapping** [Zie94j]. **Booth** [Zie99q].
Booth-Kewley [Zie99q]. **Bootstrap**
[LPR92, Zie98-36, GJMS$^+$95, Gri95, Hes97, KR93, Len95]. **Bootstrapping** [JR99]. **Borgan** [Kle94]. **Boris** [Cro94, Hig98, Pap96]. **Boros** [Sea91].
Borowiak [Iye90]. **Bose** [Rie94b]. **Bothe** [McC98]. **Bouleau** [SN95].
Boullion [Bzi97]. **Bounds** [BBT90, JD92]. **Bouvier** [Bor97b]. **Bovas** [Zie98-35]. **Bowen** [Beg90]. **Bowerman** [Zie91j, Zie94t]. **Bowman** [DeV99, Sin90a]. **Box**
[Die92, Fal99, Zie95-46, Zie98q, Bor95a, DDPG94, GJMS$^+$95, KSJ96].
Box-Behnken [Bor95a]. **Box-Jenkins** [GJMS$^+$95]. **Boxplot** [GI92].
Bozdogan [Zie95-29]. **Brad** [Zie99a]. **Bradley** [Gri95, Ruk97a, Zie96y].
Branham [Bro92]. **Brashers** [Nai96]. **Braun** [Zie95-43]. **Breakdown** [HL97, MSH94]. **Breakdown-Voltage** [HL97]. **Breakthrough** [Zie94-45, Zie94-45]. **Breakthroughs** [Zie98k]. **Brecht** [Gil92]. **Breckling** [Ste91]. **Breen** [Fox97]. **Brereton** [Zie92c, Zie94k, Nem95, Smi93].
Bretthorst [Gru90]. **Brettner** [Dog93]. **Brewer** [Gan97]. **Breyfogle** [Pol93]. **Brian** [Gre98, Ko95a, Koh94, Moo91, Nai94, Sha93, Zie95q].
Bridging [Zie95y]. **Brillinger** [Zie99t]. **British** [Jon90]. **Britt** [Kel97]. **Bro** [Wal92b]. **Brock** [Zie98y]. **Brockwell** [Sha97b, Zie92v]. **Brooker** [Zie94b].
Brown [Gun90, Che91, Col93, Gat96, Gle96]. **Bruce** [Han98, Zie91j, Zie94t].
Brush [Wil90a]. **Bryan** [Car96, Nem97, Nik93, Zie95-48]. **Bryk** [Cal94].
Bucklew [Par92]. **Buehler** [JD92]. **Bugaj** [Cha98]. **Building** [Pie90a, Bel99]. **Buja** [Zie93e]. **Bunday** [Sha93]. **Bunke** [Zie91l, Zie91l].
Burch [Zie95-32]. **Burdick** [Pot93, Ste98]. **Burger** [Bla92]. **Burke** [Zie94-43]. **Burman** [LD92]. **Burn** [Sam99a]. **Burn-In** [Sam99a]. **Burr** [Owe91, Pro94]. **Bus** [MSF95]. **Bus-Motor-Failure** [MSF95]. **Business** [Elt90, HH98a, HH98b, MTV98, Nem98, Zie90-27, Zie95q, Zie95-50, Zie97m, Zie97v, Zie96-52, Zie96-52, SG99, Zie96g, Zie96f]. **Butler** [Zie96-49].

Buydens [Zie98w, BR95]. **Byron** [Gal93, Zie91q].

C [Aba98, Ale95, Ang92, Bak98, Bar92b, Bar92a, Ber91, Bie92, Bod97, Boo95, Boo98, Bor98, Chr97, Cro94, Dic91, Dow95, Dre91, Eas99, Ens95, Far93, Ful95, Gat96, GR97, Gra94, Gun96a, Gun94a, Hei90, Hil95, Hul92, Jen90, Ked98, Kir92, KY91, LaL92, LuV90, Mad96, Mar94, Mat96, Mat97, Maz98, Nar93, Not92a, Not92c, Ord96, Per97, Por93, Pro92a, Rag93, Rie94b, Sam90, Sar90, Sau92, Sch91b, Sch93c, Sch93b, Sha95, Sha97c, Sin90b, Spr91, Sri92, Sys99, Tim95, Tim99, Tro97, Wal92b, Wei94, Wel90, Whe93, Wol92, Yan96, Yin91, Zha92, Zie90h, Zie90e, Zie90u, Zie90k, Zie91k, Zie91a, Zie92f, Zie92g, Zie92c, Zie93-28, Zie94k, Zie94j, Zie94v, Zie94g, Zie95-41, Zie95s, Zie95n, Zie95k, Zie96t, Zie96-37, Zie96-41, Zie96-31, Zie96i, Zie96h]. **C** [Zie96a, Zie96-33, Zie96-42, Zie96p, Zie96-49, Zie97g, Zie97-44, Zie98o, Zie98-39, Zie98-32, Zie98p, Zie98-43, Zie98x, Zie99l, Zie99-35, dV93, vT95]. **Cable** [Jen92]. **Calculus** [Zie94d]. **Calibration** [Ano90f, CV97, JR99, MER91, ME96, Oma91, Sea94, SS89, Tho91, Tho92a, Gle96, Hag91]. **California** [GK93]. **Cameron** [Pet99]. **Camil** [Mas99]. **Camp** [Zie96f]. **Campbell** [Ber97]. **Canavos** [Zie95-50]. **Canonical** [Kii92]. **Cantor** [Zie98r]. **Canty** [Dav99]. **Capability** [Cha95, Sto92, McC98]. **Captive** [GK93]. **Captive-Air** [GK93]. **Carbon** [Ano98e, DP97]. **Cardoso** [Zie98-38]. **Care** [God90]. **Carey** [Zie97j, Zie99i]. **Carl** [Beg90, Hec95]. **Carley** [Zie92d]. **Carlin** [Ruk97a]. **Carlo** [Gas97, Gru95, Nik93, Was97, Zie96-27, Zie98-32, Zie98-36]. **Carlson** [Emp97, Zie97f]. **Carpenter** [Zie96-33]. **Carr** [Hey93, Wat96]. **Carroll** [Arm97, Mat98, Wei90, Ano90g]. **Cary** [Hei90]. **Case** [BH93, CPJ92, Kaf94, Nem95, RH95, Zie90i, Zie98-40, Zie99-37, Zie96h, Zie98l, Zie99f]. **Case-Deletion** [CPJ92]. **Casella** [Ang91c, Gho93, Zie99-49]. **Cases** [Kra92, Zie97f]. **Castillo** [Ang90a]. **Catalog** [Tür94]. **Categorical** [Cal98, CH96a, Cob91, Hap92, Kia93b, KTTS90, Sau98, Hap91, Zie96i]. **Categorized** [CR98]. **Categorized-Components** [CR98]. **Caudill** [Zie96-49]. **Caulcott** [Zie91h, Zie92u]. **Caulcutt** [Dun96]. **Causal** [OUH93, Zel94]. **Cause** [AWS94, Fel94, Kva96, Luc94, WMP94a, WMP94b, Zie94-36]. **Cell** [Oeh94]. **Cells** [Ano90e, Sim88]. **Censored** [EM99, HW91, Mor93a, Rao98, Sin83, VB94b, Sin92]. **Censoring** [HLS98]. **Centered** [Zie96-35]. **central** [Bor95a]. **Century** [Zie96r]. **Cepstral** [Ano00, SBD98]. **Certain** [WC92]. **Cervetz** [Zie95k]. **Chacko** [Liu92a]. **Chain** [Bru96, Gas97]. **Chakraborti** [Zie93s]. **Chakraborty** [Zie93-28]. **Challenges** [Coa94, HH98a, HH98b, MTV98, Nem98]. **Chaloner** [Zie97c]. **Chambers** [Hes93, Sco90, Bat99, Zie93-38, Zie96-44]. **Chamont** [Das93]. **Chance** [Ara92]. **Chang** [Kin93]. **Change** [TW96]. **Changes** [Rie94a, Yas95]. **Changing** [GSH98]. **Chaos** [Zie94-28, Voe94]. **Chaotic** [Sti97]. **Chap** [Gol99]. **Characteristics** [AAK99, EMSD91, Viv91]. **Characterization** [Li97, Cab94]. **Characterizing** [CCC90]. **Charles**

[Bre97, Gho93, Hey98, Ize90, Kal98, Mag90, Pit96, Vin92, Zie97-33, dC99]. **Chart** [LWCR92, Pap95, Zha98, Zie90h]. **Charts** [AWS94, BC95, Emp93, Fel94, FB94, Gan95, HD95, Hea90, Lau94a, LS90a, Luc94, NM95, PD95, RAA90a, RAA90b, RD95a, RD95b, ST90b, SGW96, SWG95, Tat96, Tat97, WMP94a, WMP94b, Wes90, Woo90, Ada96, Kel97]. **Chase** [Gun90]. **Chatfield** [Dic91, Don90, Zie96-31, Zie97-40]. **Chatterjee** [Maz93]. **Chaturvedi** [Mat98]. **Chaudhuri** [Zie93-32]. **Cheeseman** [Zie95-33]. **Chemical** [Ano97f, AB97, Emp97, Koh90, Lew92, Ram94, Sch95, Wol93, Zie91h, Zie92d, Zie93l, Zie94o, Zie97-31, Zie98y, Zie99-33]. **Chemistry** [CDKS92, LaL95, Rig92a, RL95, Tho90a, Zie96j, BR95, Bla94, Hil95, Mor93b]. **Chemists** [McC94, Wol91]. **Chemometric** [McA90, Zie94s, Bay99]. **Chemometrics** [Bur91, FF93b, FF93a, HM93, Nem95, Zie98w, Bay95, LaL95, Mac90a, Smi93, Tob99, Zie92c, Zie93d, Zie94k, Zie96j, Zie98m]. **Chen** [Joh91]. **Chhikara** [Bas90]. **Chi** [Kin97]. **Chi-Squared** [Kin97]. **Chien** [Sam99a]. **Chinnappa** [Zie96g]. **Choe** [Zel94]. **Choi** [Ale98]. **Choice** [Emp93]. **Choose** [Wil90a]. **Choosing** [Ste90a]. **Chow** [Zie94p, Zie96-39, Dea95, Nay98, Zie99-40]. **Chris** [Zie95-34, Zie97-40]. **Christensen** [Hab92, Nip92, Zie98-27]. **Christian** [Cab98, Zie99z, Zie99e, Zie99j]. **Christianson** [Zie96g]. **Christine** [Pri98]. **Christopher** [Bor98, Don90]. **Chui** [Ize90]. **Chung** [Dea95]. **Circuit** [HNF97, TH93]. **Circular** [WL97, Weh95]. **Claims** [KLR91, Woo91]. **Clark** [Neu99, Zie92e, Zie97h]. **Clarke** [Por97a]. **Clarotti** [Gru95, Sam90]. **Class** [BE94, CR93, EMS98, Gol98, Hoc94, Lin93b, Rea93]. **Classical** [Zie91d]. **Classification** [Hig98, Hol98, Sha97c, Sim97, Wad99, Ful95, Mag90]. **Clayton** [Zie95-39, Zie98t]. **Clemen** [Liu92b]. **Clements** [Bru92a, Kra90, Rut93]. **Cleveland** [Buc90, Gun94b, Zie97-41]. **Clifford** [All96, Kim91, Mor93a, vT95]. **Climatology** [Mi97]. **Clinical** [Zie94n, Zie96b, Zie99g]. **Clive** [Gun96b]. **Clogg** [vT95]. **Cluster** [Had92, Koh94]. **Clustered** [HNF97]. **Clustering** [Koh90, Rou95, Sar90, STR99, Hig98]. **Clyde** [Alt96]. **Clymer** [Dea91]. **Coal** [BH93]. **Coating** [CR98]. **Cobb** [Lyn99]. **Cody** [Zie96-36, Zie98h]. **Coefficient** [Gal95]. **Cohen** [Kim91, Zie99t, Bli91, Mor93a, Zie96-32]. **Cohn** [Woo91]. **Coleman** [Aba98]. **Colin** [Pet99, Zie91f, Zie91e]. **Collaní** [Tor99]. **Collected** [Zie95-43, Zie91f, Zie91e]. **Collection** [Wen94]. **Collections** [Mor98a]. **Colledge** [Zie96g]. **Collett** [Tho93, Zie95x]. **Collinearities** [CGG92]. **Collinearity** [Gol93]. **Collins** [Zie98-43]. **Color** [VD94]. **Column** [GD91, Tür94]. **Columnwise** [LW97]. **Columnwise-Pairwise** [LW97]. **Combinations** [CL93]. **Combining** [Viv91, Sri93]. **Comment** [BZM96, PBR92, PGT95]. **Commentary** [Arm90, Box90, God90, Hah90, Hoo90, Hun90a, Mac90b, Moo90, Sne90, Tri90, Wan90]. **Comments** [Ano93f, FMQ92, HSPF92, Lau94a, LW98, LC90, LLW$^+$96, Mal95, MLV92, Sch98b, SDP$^+$95, WKWL95, YWMP95, vdVtBM97]. **Committee** [Zie97-31]. **Common** [Kva96, Mee90b, Zie99g]. **Communication** [Zie99h]. **Communications** [Arm90, Box90, Hah90, HK90, Hoo90, Hun90a, Mac90b,

Moo90, Tri90, Wan90, God90]. **Companion** [Wit94, Rut93]. **Comparative** [Ang91b, YE94]. **Comparing** [Spu92]. **Comparison** [HL95, KM99, ME96, RH92, Spu93, Vin92, ZZ91]. **Comparisons** [Chr97, DS93, MME98, SE93, TI99, Tür94, Zie94-27, Tam96, Zie95-43]. **Competition** [Smi91]. **Competitive** [Zad95]. **Complementary** [Zad95]. **Complete** [Tür94]. **Complex** [CHW97, FL97, MW90, Zie96-29, Ano97e, LH97, Weh93]. **Compliance** [Dav99]. **Component** [EMSD91, Rag98, RM95, RL95, Tat96, Viv91, Jol90]. **Component-Test** [EMSD91]. **Components** [CR98, DPL$^+$93, KM94, MW90, SS97, Yas94, DPL$^+$94, ZM94, Gho93, Lei93, Pot93]. **composite** [Bor95a]. **Composites** [Ano98e, DP97]. **Compound** [AB97, HS99, Ros96, Ros99]. **Compression** [JS99]. **COMPSTAT** [Zie90d]. **Computation** [Zie98i, Zie92d]. **Computational** [Mor91, Sch96a, Wei94, Zie98-34, Zie98-41, Mi97, Zie97g]. **Computationally** [Bro90b]. **Computations** [EMS98, Thi91, Sco91]. **Computer** [And90, Bax92, Bla92, Boy90, Hal95, LLW$^+$96, MMY93, Mor97a, Ngu94, WBS$^+$92, Zie95-49, Zie95-50, Zie95c, Zie97z, Zie98f, Zie90e, Len90, Len95, Zie92e, Zie97h, Zin93]. **Computer-Aided** [Zie92e, Zie97h]. **Computer-Based** [Boy90]. **Computer-Interactive** [Zin93]. **Computing** [Amm92, Bro90b, Gri93, Hin97, KM99, Tho90a, Wal92a, Zie96-27, Zie93e]. **Comrey** [Pri93]. **Concepts** [Bar92b, Bar95, Cro99, Pit96, VTFD92, Was97, Iye98, Kat91, Zie96o, Huz95, Jen93]. **Conceptual** [Wil98]. **Concise** [Sch91a, Zie91g]. **Conditional** [Dow94, GD94, Got94c, Got94b, HR92, HR94, Jou94, Rut94, Tor94, WB94, Won92]. **Conditioning** [Gol93]. **Condra** [Fox94]. **Conduct** [Zie99q, Zie99-52]. **Conference** [Zie95-29]. **Confidence** [BBT90, CCC90, Dal90, DS93, JD92, Len93, Nel95, Pet93, Spu93, Pot93]. **Configurations** [Mil97]. **Confounding** [Fed96, JD96, MSB96a, MSB96b, Tob96]. **Connection** [Sch91d]. **Connections** [DL90a]. **Conrad** [Zie91b]. **Consciousness** [Zie95q]. **Considerations** [GC91]. **Constantine** [Zie98l]. **Constrained** [Deu96]. **Constraints** [Won98]. **Construct** [Bru92b]. **Constructing** [CL93, MN95, Ngu96a]. **Construction** [ACV99, Jac92, Jac93, LW97, LIV96, Ngu94, Ngu96b, Wad99]. **Consul** [LuV90]. **contain** [Ode90]. **Contemporary** [Pig91]. **Contingency** [Alb93, Ano90e, Sim88, Zie99x]. **Continual** [Bel99, Zie93i]. **Continuous** [CFRH99, Gun96b, Kra92, MT91, Nem92, Not92c, Sto96, Woo92, Zie94h, Ber96b, Fam95, Not92a, Van91, Zie94l]. **Contouring** [Zie90e]. **Contrasts** [VS96, VS98]. **Control** [Acr97, Ada94, AWS94, Ada96, Ano91f, BR95, Bax90, Bem96, Bon95, CFRH99, Col93, Dun97, FHT90, Fal99, Fel94, Fre99, FB94, Gan95, Gho94, God95, Han93, Haw91b, Hun90b, KD97, Kal93, Kra90, Lau94a, LWCR92, LS90b, LS90c, Luc94, MH90, Mas99, McC90, McG94, McL95, MME98, Mil94, Pie90b, Pla90, Ram91, Roz93, Run90, SE93, Sar94b, She90a, Sin90b, ST90b, SGW96, Tat96, Tat97, Tor95, TWN98, TFV93, Tür94, VTFD92, WVYB97, WMP94a, WMP94b, Wes90, WM90, Yas92,

Yas93, Zha98, Zie90l, Zie92r, Zie94-43, Zie94-33, Zie97-32, Zie97w, Zie99n, Lew92, Pro92a, Ada93, Bos92, Car90b, Car93, Edg98, GR97, Hal94, Har91d, Kal98, Kin93, McC91, Mil91, O'D97, Pan96, Rol93, Sau92, Vuk98, Zei94, Zie90t, Zie92w, Zie93-38, Zie94-34, Zie95-46, Zie96-37]. **Control** [Zie96-41, Zie97o, Zie99o, Zie99y, Zie93f]. **Controlled** [JR99]. **Controllers** [Har92b]. **Controversies** [Woo91]. **Conventional** [Cox96]. **Convergence** [Zie99j]. **Cook** [Gol95, Bog92, LC90, Moo99]. **Cooper** [Zie95-44]. **Coordinate** [DGTZ97a, DGTZ97b, Hul97, MN95, PE97, WH97]. **Coordinate-Exchange** [MN95]. **Copp** [Pro93a]. **Coppi** [Zie92k]. **Corbett** [Zie99-43]. **Cornell** [Pro92a, Czi92, Zie92i, Zie97y]. **Correction** [Ano90e, Ano90f, Ano91e, Ano91f, Ano93e, Ano93f, Ano97f, Ano97e, Ano98e, Ano99e, Ano00, BT98, DPL$^+$94, Lin95a, Sen99b, Sin92, Ste90b, Tho92a]. **Corrections** [Ano90g, HR94]. **Correlated** [AWS94, AAK99, Fel94, Luc94, Mee90a, WMP94a, WMP94b, Wes90, Yas93, Zie99t]. **Correlation** [Gov92, MQ91, Nan94, SW95, Zha94, Zie94z]. **Correspondence** [Jol90, Zie93g]. **Corresponding** [ZZ91]. **Cortada** [Zie96o]. **Corter** [Jol97]. **Cost** [Cro92, MW98, Nel95]. **Cost-Driven** [MW98]. **Costs** [Coo96b, ST90a, Zie90-28]. **Cothern** [Zie95n]. **Cottman** [Zie93-36]. **Council** [Sri93]. **Cound** [Zie93a]. **Count** [Owe96, Pet99]. **Counting** [Kle94]. **Couper** [Zie99v]. **Course** [Dre91, Far93, Gra94, Gun94a, Jon90, Jon91b, Kia92a, Lal99, Lor92, Mee91a, Pri93, Ste98, Zie98a, Dri91, Wat90]. **Courts** [Zie90y]. **Covariance** [RvD99, Sha97c]. **Covariates** [Kia95b]. **Coverage** [Sea90]. **Covering** [DM98]. **Cox** [Die92, Fre93, Jol96, Weh93, Zie91q, Zie96g, Zie97-42, Jol96, KSJ96, Zie99f]. **Crain** [Jen90]. **Creating** [Kel97]. **Creighton** [Gun94a]. **Cressie** [Zie94-41, dV93]. **Creveling** [Alt96, Bak98]. **Criteria** [ME96]. **Critical** [Hab90, HW90b, HW90a, Hir90, Nai90b, Nel93, YDB90]. **Crocker** [Pro92a]. **Cromwell** [Dow95, Ord96]. **Cross** [Zie91q, Zie94m, Zie94n]. **Cross-Over** [Zie91q, Zie94m, Zie94n]. **Crossed** [Hol98]. **Crossed-Classification** [Hol98]. **Crossings** [Fre95]. **Crowder** [Bar92a, Lin92, Zie97t]. **Cryer** [Zie95-50, Zie96-52]. **Cumulative** [Ano98e, DP97, SGW96, Zie90h]. **Current** [Sen98, Yas95, Sen99b]. **Curvature** [Coo96a]. **Curve** [BB95, Wha95]. **Curves** [Ann99, Ano99f, JFM99, KK99, ME99, PM99, Zie96s, And90]. **Customer** [San98, Zie95w, Zie96y, Zie97s, Zie98-31, Zie96k, Zie97i]. **Customer-Focused** [Zie96k]. **CUSUM** [Hea90, LS90a, RAA90b, Woo90, RAA90a, Yas92, Yas93]. **Cyclic** [Mor97a]. **Cyclical** [ST90b]. **Cyrus** [Dob96, O'D97]. **Czerminski** [Mor93b]. **Czitrom** [Zie98-40].

D [Ale99, Arm97, Bax96b, Boo97, Bri91, Car90a, Cha92, Coa94, Cuc92, Die92, Fai91, Fot96, Fox91, Fox98, Fre93, Ful95, Ful97, Gas97, Got94a, Gov92, Gri90, Hei90, Hey92, Jam96, Jen91, Kia92b, Kia93b, Kia95a, Kin91, Kle94, Koe92, Lau94b, LH97, Lin92, Mac90a, Mag96, McA90, Mil94, Mye91, Not92a, Not92c, Per97, Rag93, Rag95, Sac93, Sam90, Sch96b, Sea93, Sha93, Sin98,

Smi91, Sti97, Sys99, Tho93, Tro97, Ver90, Voe94, Wat90, Weh93, Wei90, Wha95, Zel94, Zha92, Zie90-28, Zie90e, Zie90d, Zie91q, Zie92c, Zie92r, Zie92s, Zie93-30, Zie93p, Zie93-29, Zie93-38, Zie93f, Zie94k, Zie94y, Zie94c, Zie94m, Zie95p, Zie95-41, Zie95f, Zie95x, Zie95-50, Zie95-39, Zie95c, Zie95a, Zie96d, Zie96-37, Zie96-51, Zie96-52, Zie96g, Zie97-38, Zie97-42, Zie97c, Zie97d]. **D** [Zie97t, Zie97-37, Zie97a, Zie98o, Zie98-45, Zie98p, Zie98-43, Zie98l, Zie98-40, Zie98w, Zie99-27, Zie99-42, Zie99-37, Zie99t, Zie99q, Zie99-35, Zie99-32, Zin93, Ber98]. **D'Agostino** [Goi96]. **Dagpunar** [Gol90]. **Dale** [Iye90, McC91, Nai96, Zie96z]. **Dallas** [vT91]. **Daly** [Zie95a]. **Damage** [Ano98e, DP97]. **Dana** [Zie93a]. **Daniel** [Aye98, Goi96, Har92a, Ram96, Weh91, Woz91, Zie95h]. **Data** [Bat99, Boy96, Bre91b, Bro92, Cal94, Cam90, CH96a, Cob91, Cox93, Dav99, DeV99, DS93, Dov93, Dre91, EMSD91, EM99, Fri91, Geo98, Gol93, Got92, Gra90, Gre98, Gri96, Gu91, GS94, Had92, HR92, HW91, Ham96, Han97, HNF97, Hap91, Has91, HT91, HL97, JS99, Kel97, KM94, Kia92b, Kia93b, Kii92, KTTS90, Kva96, LaL95, LPY97, Lwi94, MA92, Mee91b, MSF95, Nai94, Nel95, Nem95, Not92b, Oli97, Ruk97a, Sau94, Sch91b, Sch96c, SC93, SGW96, SP95, Viv91, VB94b, Wen94, Zha98, Zie90o, Zie90v, Zie92q, Zie92k, Zie93-27, Zie94f, Zie94-29, Zie94-37, Zie94z, Zie95y, Zie95v, Zie95x, Zie95-50, Zie95a, Zie96b, Zie96-50, Zie96i, Zie96a, Zie96-38, Zie97r, Zie97f, Zie97x, Zie97-33, Zie97t, Zie97z, Zie98c, Zie99-47, Zin93, vT91, Bre91a, HR94, All96]. **Data** [Bar92a, Bas97, Bre95b, Cra94, Eub90, Gal92, Gro96, Gun94b, Hap92, Hec99, Lee90, Lee99, Mul97, Nel98, Nip92, Owe96, Pat91, Pet99, Pfa99, Ram91, Rao98, Sar90, Sau98, Sim91, Sti97, Taa91, Tho93, Tim96, Weh95, Zie91q, Zie94-41, Zie95-33, Zie95d, Zie95-36, Zie97-41, Zie99t, dV93, Che94, Fox98, Law98, Mar94, Ram94, Vin92, Zie90-27, Zie90f, Zie90g, Zie91h, Zie92f, Zie93h, Zie94o, Zie96m, Zie96l, Zie97j, Zie98n, Zie99i]. **Data-Based** [Gri96]. **Data-Sequential** [SGW96]. **David** [Arn90, Bru93a, Bru97, Car97, Cro94, Dea94, Dun90, Edg98, Fot96, Gol93, Gri98, Koo90, Law98, Len93, Loh94, Mil98, Moo96, Pan96, Rag95, Ram93, San99, Sau97, Sch93c, Sch93b, Tam96, Tim96, Wad99, Zie91i, Zie93-31, Zie98-30, Zie98b, Zie99-43, Zie99-34, Zie99d, Zie99t, Zie99-41]. **Davidian** [Tim96]. **Davidson** [Oli97]. **Davies** [Sch95]. **Davis** [McC98, Zie94-43, Zie96i, Hof95, Sac93, Sha97b, Zie92v]. **Days** [Zie95p]. **Dead** [Luc98, LG99]. **Dean** [Zie99c, SDP$^+$95]. **Debarred** [CL93]. **Decision** [Bax95, Gru95, Han90, Liu92b, Par92, Ter92, Zie98-39, Zie98d, Deh90, Liu92a, Mag90]. **Decision-Making** [Liu92a]. **Decisions** [Liu92b, Zie98n, Zie90g, Zie96n]. **Defect** [GS92, Bru91]. **Defects** [FRY96, HNF97, Lam92]. **Defensive** [Hes95]. **Defined** [BCL98a, BCL98b, Rob98, Sch98a]. **Definition** [Bis94]. **Deformation** [CHB90]. **Degradation** [BE94, LM93, LPY97, MEL98]. **Degrees** [DDPG94]. **DeGroot** [Fox91]. **Dehnad** [Pie90b]. **Deistler** [Cry90]. **DeJong** [Zie98w]. **del** [Ram99]. **Delaney** [Pat91]. **Delay** [Ano00, SBD98]. **Delay-Fired** [Ano00, SBD98]. **Deletion** [CPJ92]. **Dell** [Zie94-36]. **DelMar** [Zei94].

Deming [Ada91, Mac90a, Pfa92, Pro93b, Zie94s, Pro96, Zie95p, Zie93i]. **Denker** [Lin99]. **Dennis** [Car96, Gol95, Kan95, Moo99, Zie97-32]. **Density** [Ram93]. **Dependence** [DJ94, Iye98]. **Dependent** [Cal98, Cox93, Gri99]. **Deployment** [Zie96-32]. **Derek** [Boo94a]. **Derivatives** [MMY93]. **Derived** [LPY97]. **Derman** [O'D97, Dob96]. **Descriptive** [Wol96]. **Deshpande** [Bas97]. **Design** [Ano97f, Bak98, BS97, Bor94, BE94, Bow91, CH96b, Der90, Edg92, Emp97, EH96, Fox94, Fre99, Hoc94, Hol98, Jen91, Job99, Kin93, LN97, Lyn99, McC94, MS90, MW98, MMY93, MS95, NAM+92, O'D99, Pie90b, Pit96, Ram99, Rig99, RJ97, Ros96, Sch95, STW91, Tan98, Van91, Web90, WT98, Zie90q, Zie91o, Zie94s, Zie96-29, Zie96-39, Zie99-38, Zie91q, Alt96, And90, Gil92, Hwa92, Kia92b, Kia93a, Men91, Pro92b, Sac93, San99, Tom95, Zie93w, Zie93d, Zie95-30, Ano97f, Ano97e, Emp97, Gan97, Gle91, Gre94, Oli98, Sri92, Tam96, Tom95, Yeh93, Zie93j, Zie94p, Zie95j, Zie97k]. **Designed** [CHW97, CM93b, CM93a, FL95, Gre98, Gun96a, Gun93, HO93, Hah93, LST93, Pan92, Sco91, Zie96-48]. **Designing** [Aye98, Bis97, RM95, Pat91, Pro92b]. **Designs** [ACV99, Atk96, AD96, AB97, BH97, BS99, Bis94, BL97, CL93, DM98, DL90a, DL90b, DPL+93, DDPG94, DJ94, Fed96, FL97, HCV98, JD96, Kun97, LW97, LIV96, LD92, Lin93b, Lin95b, MB98, MN95, MSB96a, MSB96b, Ngu94, Ngu96a, Pan99, SCF97, Spu92, SWC97, Tob96, Tür94, VM91, Zie97y, Bor95a, DPL+94, Lin93a, Lin95a, Mor97a, Whe93, Zie92f]. **Dessy** [Zie92c, Zie94k]. **Destructively** [SW95]. **Desu** [Sea93]. **Detect** [Cro94]. **Detecting** [Ano90e, Ano00, SBD98, Sim88, ST90b, TH93]. **Detection** [PF91, QY98, Tat96, Rie94a]. **Determinant** [RvD99]. **Determination** [Jac92]. **Determine** [Hul92]. **Determining** [AB97, HC91, USM99]. **Deterministic** [JV93]. **DeToro** [Zie93-37, Zie97u]. **Deutsch** [Zie95s, Zie98t]. **Dev** [Sha92]. **Developing** [Bak98, Zie95k]. **Development** [Kaf94, Pol93, Sch95, Zie91r, Sam99a, Zie92u, Zie93u, Zie97w, Zie99-39]. **Developments** [Zie95l]. **Deviation** [Par92, Tat97]. **Device** [Bla92]. **Device-Level** [Bla92]. **Devices** [CB93]. **DeVor** [Kin93]. **Devore** [Zie92l]. **Dey** [Zie99-27]. **Diagnostic** [Ber98]. **Diagnostics** [Ano91e, BNC87, CS92, CPJ92, Gol93, Haw91a, KSJ96, Sch91d, TW90, TW92, Zie93k, Zie93x]. **Diagrams** [Ter92]. **Dialogue** [Bur91]. **Diane** [Sim91]. **Diaz** [Job99]. **Dickey** [Zie99d]. **Dickinson** [Gro99]. **Dictionary** [Zie91a]. **Diday** [Zie90f]. **Dieck** [Kah94]. **Diesel** [MKA96]. **Differences** [Gol98]. **Different** [Kva96]. **Digby** [Dri91]. **Diggle** [Zie95d, Zie99t, Tso92]. **Digital** [Gru97, Sen94a]. **DiIorio** [LaL92]. **Dijkstra** [Tsa91, Zie90p]. **Dimension** [Jol90, Pfa92]. **Dimensional** [Kii92, WVYB97]. **Dimitrakopoulos** [Zie96r]. **Dimitri** [Sch92c, Sch93a, Sch94a]. **Dippo** [Zie98-43]. **Direction** [Ste91]. **Directional** [Cob91, Ste91]. **Directions** [Zie94-29, Zie93k]. **Discovery** [Mul97, Zie98c]. **Discrepancy** [PJ90]. **Discrete** [Bax95, BL94, Bru94, Gol98, Luc98, Mar99, Ped98, Rag95, Sim91, TWN98, Wel93, Goo95, Pos98]. **Discrete-Event** [Rag95]. **Discrete-Valued** [Ped98]. **Discretization** [Zie99j]. **Discriminant** [Hec95, Hir96, VB94a, Ray93]. **Discriminating** [Atk96]. **Discrimination**

[HS97, Iye90]. **Discussion**
[AWS94, Alm95, Ann99, Atk96, Bax90, Ber96a, BC95, Bon95, BK92a, Che95, CH96b, CM99, CR96, Dow94, FHT90, Fed96, Fel94, Fri91, Gib99, GD94, Gil99, Gu91, Gun93, HO93, Hab90, Hah93, HD95, HT91, HM93, Hea90, Hir90, HP92, Hul97, Hun90b, JFM99, JD96, Jou94, KMP95, KTTS90, KK99, Lam98, LST93, LS90a, Luc94, MH90, Mac92, MTV98, Nai90b, NAM+92, Nem98, NO96, PD95, PE97, Rob98, Rou95, Rut94, Sch98a, Sne98, Spe96b, SWG95, Swe96, Tob96, Tor94, Tuc92, Tuc96, VV92, VV94, Van99, WG92, WB94, Wol93, WH97, Woo90, WM90, YDB90, Zad95, dVU96]. **Disjunctive** [Cam96]. **Dispelling** [Cly94]. **Dispersion**
[BH97, MS95, NLB+98, Pan99, Ros96, Ros99, Sen99a, WT98].
Dispersion-Effects [Pan99]. **Displays** [SC93]. **Distinction** [KMP95].
Distributed [Mee90a, WJ92]. **Distribution**
[DH92, Gri93, HLS98, KGK90, LM93, LPY97, RN91, Sin97, USM99, WI94, WL91, Won92, Ode90, Zie94-45, Bas90, Ber97, Glo93, Ize91, Sin90a, Ste90c].
Distribution-Free [USM99]. **Distributional** [Col92]. **Distributions**
[AWS94, Ber96b, Bru97, CDKS92, DS93, Fam95, Fel94, Hes95, LuV90, Luc94, Lwi94, Not92a, ST90a, Sha95, WMP94a, WMP94b, Yas92, Bru94, Loh92, Not92c, Pos98, Wel93, Zie94-38, Sha97a]. **Disturbance**
[Ano90f, Luc98, SS89]. **Divergence** [Li97]. **Division** [Zie97o]. **Doane** [Dun90]. **Dobson** [Emp92]. **Dodge** [Zie90q, Fai94, Zie92q]. **Dodson** [Car96, Zie95-48]. **Does** [God90]. **Doing** [Zie99k]. **Dominique** [SN95]. **Don** [Col93, Job99, Mag96]. **Donald** [Ada96, Bel99, Bro90b, Cox96, Dog93, Fre92, God93, Har91b, Mil90, Zei94, Zie91r, Zie92x, Zie97-35, Zie98n]. **Donev** [Whe93]. **Dongsheng** [Hes97]. **Donna** [Maz98, Zie98v]. **Doran** [Zie90b].
Dorothy [Moo91]. **Doty** [Ada93, Mor99a, Vuk98]. **Dougherty** [Wal92a].
Douglas [Ale95, GR97, Gil92, Gun96a, Jen92, Mat98, Mil90, Nar93, Por93, Pro92a, Sau92, Sri92, Zie99l, Zie99-42, Zie99f, Zie99u]. **Dov** [Weh91]. **Dovich** [Ben93, Rig92b]. **Dowd** [Zie97n]. **Dowdy** [Ing92]. **down** [Coo96b].
Downtime [Bog92]. **Dr** [Zie95p]. **Drain** [Edg98, Gri98]. **Draper** [Gun99, SDP+95, Zie98q]. **Drift** [JV93]. **Driven** [MW98]. **Drug** [Zie91r, Zie99-39]. **Dshalalow** [Gla98]. **Duane** [Sen99b, Sen98].
Duane-based [Sen99b, Sen98]. **Dubes** [Sar90]. **Dudewicz** [Joh91, Law92].
Duffy [Sim91]. **Dummy** [Zie94-35]. **Duncan** [Bla92, Zie90-28]. **Dunn** [Gle91, Nai94]. **Duran** [Bzi97]. **Duration**
[BCL98a, BCL98b, Rob98, Sch98a]. **Duvall** [Zie94j]. **Dux** [Zie93l]. **Dykstra** [Sho90]. **Dynamic** [Amm92, Bax95, Bil94, Cab98, Peñ91, Wel90, Wes92, Win93, ZP94, Zie97e, Buc90]. **Dynamics** [LG99, Zie93q].

Earth [Rus94, Zie90z]. **Easy** [Bre97, Zie95-35]. **Ebeling** [Hey98]. **Eckhard** [Hal95]. **Ecological** [Zie95j, Zie94q, Zie95m]. **Econometric** [Zie95e].
Econometrics [Zie90b, Zie94v, Zie97c]. **Economic** [Elt90, Ngu96b].
Economical [STW91]. **Economics** [Pro96, Zie97m, Zie90-27, Zie95-50].
ECR [Sen99b]. **Eddy** [Len93, Mar99]. **Edge** [HT92]. **Edge-Preserving**

[HT92]. **Edgington** [Zie98-37]. **Editor** [Haw94, Kaf99, Mor97b, Mor98c, Nai90a, Nai91a, Nai91b, Nai92, Var94a, Var94b, Yas90]. **Editorial** [Mor98b]. **Edler** [Zie98x]. **Edmund** [Bla94]. **Eduardo** [Hul92]. **Education** [Pro96]. **Edward** [Baj98, Bil91, Bro90b, Joh91, Ked98, Law92, Lei93, Pan96, Ram91, Sco92, Wal92a, vT95]. **Edwards** [Mag96, Pro96, Zie90d, Zie99q]. **Effect** [CH96b, HO95, Jac92, Jac93, Sch96b]. **Effect-Based** [CH96b]. **Effect-Saturated** [HO95]. **Effects** [Ale98, Ano99e, BT89, BH97, CWWR97, Emp99, Hol98, Khu92, LBB96, LN97, LG99, Pan99, TH93, Van92b, VV99, WL97, WT98, BT98]. **Efficiency** [Fam99, TWN98, Sch95]. **Efficient** [KD97, Lin93a, Lin95a]. **Efron** [Gri95]. **Eigenvalues** [BA96]. **Einax** [Zie98m, Zie96j]. **Elaboration** [TFV93]. **Elart** [Tor99]. **Electrical** [Lei91]. **Electronics** [Dog93, Kaf94]. **Elementary** [Hei90, Joh91, Zie99-35, Far90, Hag90, Mag96, Sar94a, Wil90b]. **Elements** [Zie97-41, Tim95, Zie97l]. **Elfe** [Zie97v]. **Elisa** [Zie93-27, RJ97]. **Elizabeth** [Por93]. **Ellen** [Bor97a]. **Ellis** [Ram91, Zie99h]. **Elsayed** [She90b, Lyn97a]. **Emanuel** [Zie99-36]. **Emergency** [MKA96]. **Emmanuel** [Bor97b]. **Emphasis** [BH93]. **Emphasising** [Not92a]. **Empirical** [MKA96, Ruk97a, Yas92, Ang91a, Pie90a]. **Encyclopedia** [Zie91g, Zie90h, Zie92g, Zie96o, Zie98o, Zie98p]. **End** [Zie90h]. **Enders** [Zie95e]. **Engelhardt** [Bry92]. **Engine** [HLD98]. **Engine-Mapping** [HLD98]. **Engineer** [Car90b, Geo94]. **Engineering** [Ajm99, Alm95, Ben93, Bow91, Bru93b, Bru95, CFRH99, Car96, Che91, Cro99, Goi96, Gut90, Jan94, KY91, Lar95, LN96, Men91, Nar93, Not92c, Rag91, Sch92c, Sch93a, Sha97a, She90b, Spe96a, Wal92a, Wyc96, Zie91p, Zie92l, Zie93w, Zie93v, Zie93-36, Zie94-40, Ang90a, Ano97e, Fri97, Gla98, Hey92, Hey98, Kha95, Lei91, LH97, Lyn97a, Oli98, Pap96, Sen97, Tan98, Was91, Zie94-39, Zie97-39, Alt96, Bod97, Edg92, McC99, Nan94, Sac93, Weh91, Zie99l]. **Engineers** [Arm90, Bar91, Bax96b, Box90, Boy90, Bzi97, God90, Hah90, HK90, Hoo90, Hun90a, LeP90b, Mac90b, Moo90, Rob90, Tho99, Tri90, Wan90, Zie93c, Zie94-31, Zie99-43, Zie99p, Zie99-30, Ale95, Bru93a, Bry99, Gat96, Gut92, Lee93, Mil99, Spa99, Taa99, Zie95-28, Zie99h]. **Engineers/ Physical** [Box90, God90, Hah90, HK90, Hoo90, Hun90a, Mac90b, Moo90, Tri90, Wan90]. **Enhancements** [Bax90, FHT90, Hun90b, LS90b, LS90c, MH90, WM90]. **Enrick** [Zie94-33]. **Enrique** [Ang90a]. **Ensuring** [Soy95]. **Entropy** [KY91]. **Environment** [Amm92, Zie99-45, Zie99-44, Hin97, Zie94-42]. **Environmental** [Cam98, Gat96, Got92, Rus94, Zie90r, Zie96j, Zie98-42, Zie98s, Zie98m, Zie99f, Ham96, Zie95n, Zie96p, Zie99m]. **Environments** [KS93]. **Envisioning** [Sco92]. **Ephraim** [Tho99]. **Epidemiological** [Zie95-36]. **Epidemiologists** [Zie95i]. **Epidemiology** [Zie95-39, Zie96-43]. **Equality** [Sin83, Sin92]. **Equation** [Hec96, Zie97b]. **Equivalency** [CC99]. **Eric** [Coa94, Len90]. **Ericson** [KY91]. **Erling** [Hap92, Sau98]. **Ernest** [Lyn94]. **Error** [Arm97, CGG92, HA93, Hir96, JV93, RL95, Roe91, TW96, VM91, Zie93t, McA90]. **Error-Rate** [Hir96]. **Errors**

[BA96, Car93, CS92, GS95, LBB96, Tho91, Tho92a, WI94, Zie90-28, Zie93r]. **Errors-in-Variables** [CS92, Tho91, Tho92a]. **Erwin** [Spr91]. **Escobar** [Nel98]. **Essays** [Zie91k]. **Essential** [Zie90-27]. **Essentials** [Hal98, Zie94r]. **Estelle** [Zie99t]. **Estimate** [Hul92, Kun97, LM93, Viv91]. **Estimated** [AKO94]. **Estimates** [Gri93, TW96]. **Estimating** [Ann99, Ano99f, Bre91b, BHS90, CDKS92, Fri91, GS92, Gri90, Gu91, HT91, JFM99, Kun93, KK99, PM99, PJ90, SW95, Yas95, Bre91a, Ste90a]. **Estimation** [CR93, Har91a, Hir96, Hor98, HLS98, KM94, Kim91, Kva96, Mag90, MKA96, MPR99, Mar96, MS90, Oma91, Ram93, Roe91, RWHH97, Sen98, Sen99b, Sen95, Tat97, Tho91, Tho92a, VB94b, WT98, YE94, Gru90, Kus92, Par92, San92, Spo90, Wha95, Zie94q, Zie99-49]. **Estimations** [McA90]. **Estimator** [RvD99]. **Estimators** [Ang91b, Ano90f, BH93, Gri97b, Sin90a, SS89, ZZ91]. **Eureka** [Coo96b]. **Evaluate** [ET96]. **Evaluating** [CS93, Tho94, VM91, Bor97a, Bri91, Tor95]. **Evaluation** [Ber96a, CR96, OM96a, OM96b, Spe96b, Swe96, Tuc96, Zie96-42, Sea91, Roz93]. **Evans** [Zie94-38, Zie94m, Bru93a, McG94]. **Event** [Goo95, Rag95, Zie98-28]. **Events** [BCL98a, BCL98b, LN95, Rob98, Sch98a]. **Everitt** [Lee99, Nai94, Zie97p, Alb93, Ko95a, Koh94]. **Every** [Ada91, Car90b, Car92, Geo94]. **Everyone** [Pro94]. **Evidence** [Baj98, Glo99, Zie90y, Zie96-42, Len93, Zie98b]. **Evolutionary** [Zie98q]. **Evolving** [Zie90y]. **Exact** [MN95]. **Example** [Cob91, Maz93, Zie96-36]. **Examples** [Cha93, Zie96x, Zie97m, Zie99g]. **Excel** [Zie96m, Zie97j, Zie98n, Zie99i]. **Excel**^{TM} [Zie99k]. **Exchange** [MN95]. **Execution** [Sch96b]. **Executives** [Rea93]. **Exorcist** [Cly94]. **Expansible** [Hol98]. **Expected** [BBT90, Cro92]. **Experience** [Bod97]. **Experiment** [CM93b, CM93a, CR98, FL95, Gun93, HO93, Hah93, LST93, RH95]. **Experimental** [All96, Atk96, AD96, BE94, Emp97, EM95, Gal93, Gil92, Gri98, Job99, Kia92b, Kia93a, McC94, MN95, Pro92b, Sac93, San99, Tom95, Whe93, Zie93d, Zie95-30, Ano97f, Jen91, Web90, Zie94s]. **Experimentation** [Pap95, STW91, Cha92, Zie92x]. **Experimenter** [Rut93]. **Experiments** [BS97, Bis97, Bow91, CH96a, CHW97, Der90, DH92, Emp93, Fed96, Gan97, Gre94, GC91, GK93, HW91, HL97, Hoc94, HLD98, Hol98, Joh90, JD96, JR99, LBB96, LLW$^+$96, MB98, MSB96a, MSB96b, Mor91, MMY93, Oli98, Pat91, Ram99, Ros96, Ros99, SC93, TH93, Tam96, Tob96, Tom95, WBS$^+$92, WC92, Zie92i, Aye98, Bor94, Bru92b, Fox94, Gre98, Gun96a, Hal95, Lyn99, Pan92, Pit96, Pri98, Rig99, Sch95, Sco91, Sri92, Zie90q, Zie91o, Zie94-37, Zie94m, Zie95j, Zie96-48, Zie99-38, vT91, Czi92]. **Expert** [Jon92, Sam90, Zie90g]. **Explanations** [Baj98]. **Exploration** [Ott90, Cam90]. **Exploration-Geochemical** [Cam90]. **Exploratory** [Gra90, Sch93c, Sch93b, Not92b]. **Exploring** [Coo93, Dun90, KR93, Spr91]. **Explosives** [ET96]. **Exponential** [Kun93, Rag98, Sin83, Sin97, Sin92]. **Exponentially** [Bax90, DP91, FHT90, Gan95, Hun90b, LWCR92, LS90b, LS90c, MH90, WM90]. **Exponentials** [WL91]. **Exponentiated** [MSF95]. **Exposure** [Zie98y]. **Extended** [Nel93]. **Extending** [Zie98r]. **Extensions**

[GI92, Kus98]. **Extreme** [Ang90b, PF91, YE94, Ang90a, Zie95o]. **Extrusion** [Zie95-34].

F [And90, Ber91, Bil92, Boo95, Bow91, Bru92b, Cly94, Far90, Gan97, Jol96, Nem97, Nik93, O'D99, Por97b, Pro90, Run90, Sen94a, Sha95, Sha97c, Sho90, Ste98, War90, Zie90l, Zie90-27, Zie90w, Zie91a, Zie94-43, Zie95a, Zie96-30, Zie97x, Zie97q, Zie98n, Zie99l]. **Fabio** [Gru95]. **Fabrication** [HNF97]. **Factor**
[CL93, CH96b, DM98, Hec96, Jac95, Kun97, Lyn97b, Pri93, RH95, Bla94]. **Factor-Based** [CH96b]. **Factor-Covering** [DM98]. **Factor-Level** [CL93]. **Factor-Sparsity** [Kun97]. **Factorial** [Ano99e, BS99, Bru92b, CL93, Emp99, FL97, Joh90, LBB96, LN97, Mor91, Pan99, RH95, TH93]. **Factorials** [HO95, Mil97]. **Factors** [EM95, KM99, Nai96]. **Fahrmeir** [Glo95, Zie94e]. **Failure** [Ano98e, DP97, GS94, Hul92, Kva96, LM93, LPY97, MSF95, Rag98, USM99, Sch96b]. **Falk** [Pap96]. **Family** [MSF95, Roc93]. **Fang** [Loh92, Str96]. **Farebrother** [Thi91]. **Farnum** [Che92, Ada94]. **Fasser** [Dog93]. **Fast** [RvD99]. **Fatigue** [Ann99, Ano99f, JFM99, KK99, PM99]. **Fatigue-Limit** [Ann99, Ano99f, JFM99, KK99, PM99]. **Fausett** [Zie95-49]. **Fayyad** [Zie98c]. **Feature** [DGTZ97a, DGTZ97b, Hul97, JS99, PE97, WH97]. **Feature-Preserving** [JS99]. **Federer** [Wen94]. **Federov** [Rig99, Zie90o, Zie90q]. **Feedback**
[BK92a, BK92b, BL94, Luc98, LG99, Mac92, Tuc92, VV92, WG92]. **Feigelson** [Coa94, Sin98]. **Fellers** [Kra92, Pro93b]. **Fergenbaum** [Zie92w]. **Feridun** [Zie99-45, Zie99-44]. **Fiber** [WVYB97]. **Fibers** [Ano98e, DP97]. **Fields** [Bax96a, PH99, Woo91]. **Fienberg** [Zie90y]. **Figures** [Zie99-32]. **Filter** [Ang92]. **Filtering** [Har92a]. **Financial** [Zie99e]. **Finding** [Had92]. **Fingleton** [Cob91]. **Finish** [Bor97a]. **Finite**
[CDKS92, Ruk98, Spu93, Zie93j]. **Finite-Mixture** [CDKS92]. **Fink** [Zie99-52, Zie96-47]. **Finkelstein** [Zie92t]. **Finn** [Yak97]. **Fired** [Ano00, SBD98]. **First** [Dre91, Far93, Gun94a, Kia92a, Lal99, Pri93, Ste98, Wat90, Zie95-29, Zie98a, Lin93a, Lin95a]. **first-order** [Lin93a, Lin95a]. **Fisher** [Zie94i, Weh95]. **Fishman** [Was97]. **Fit** [Ale99, GK90, Kin91]. **Fits** [MSH94]. **Fitting** [Ram94, Bru97]. **Fitzgerald** [Rie97]. **Five** [Sto92]. **Flury** [Haw90, Lal99]. **FMEA** [Sch96b]. **Focus** [HH96]. **Focused** [Zie96k]. **Folks** [Bas90]. **Follow** [Fed96, JD96, MSB96a, MSB96b, Tob96]. **Follow-Up** [Fed96, JD96, MSB96a, MSB96b, Tob96]. **Forecasting**
[Boo94b, Che92, Wes92, Zie95-46, Zie97e, Elt90, Law98, Sha97b, Zie95n, Ang92, Win93, Zha92, Zie94t, Zie97m]. **Foreman** [Zie93-33]. **Foremen** [McC90]. **Forensic** [Zie96-42]. **Forina** [LaL95]. **Formation** [GK93]. **Forms** [RJ97]. **Formulae** [Zie90u]. **Formulation** [SDP$^+$95]. **Forrest** [Pol93]. **Forthofer** [Zie96v]. **Fotheringham** [Zie97-30]. **Foundations** [Zie94-45]. **Four** [DPL$^+$93, DPL$^+$94, Zie95p]. **Fourth** [Zie95q]. **Fowler** [Zie97q]. **Fowlkes** [Alt96]. **Fox** [Zie90-27, Zie93x, Emp93, Gra98]. **Fractional** [BS99, Bru92b, CL93, HO95, Mil97, SCF97]. **Fractionated** [HW91]. **Francis**

[Bil92, Has91, Moo91, Zie94e, Zie95z, Zie96-40]. **Frank**
[Ada91, Hal98, Kat98, LaL92, Zie96l]. **Franklin**
[Bar95, Pot93, War90, Zie95-41]. **Franz** [Tor99]. **Fred**
[Gun90, McL95, Oli97, Zie94-27]. **Frederick** [Sch93c, Sch93b]. **Free**
[Ste90c, USM99, Wha95]. **Freedback** [Fal99]. **Freedom** [DDPG94].
Freeman [Loh94, Zie95g]. **French** [Sam99b, Han90]. **Frequency**
[Bru97, Lwi94, Owe96]. **Fresh** [Fre92]. **Freund**
[Alt99, Won94, Zie92n, Zie92o, Ale91]. **Frieden** [MA92]. **Friedrich** [Bor94].
Friendly [Zie93z]. **Frigon** [San99]. **Froidevaux** [Zie98s]. **Front**
[Ano90h, Ano90i, Ano90j, Ano90k, Ano91g, Ano91h, Ano91i, Ano91j, Ano92e, Ano92f, Ano92g, Ano92h, Ano93g, Ano93h, Ano93i, Ano93j, Ano94e, Ano94f, Ano94g, Ano94h, Ano95e, Ano95f, Ano95g, Ano95h, Ano96e, Ano96f, Ano96g, Ano96h, Ano97g, Ano97h, Ano97i, Ano97j, Ano98f, Ano98g, Ano98h, Ano98i, Ano99g, Ano99h, Ano99i, Ano99j]. **Frontiers**
[Zie95-29, Zie95f, Gla98, Zie99n]. **Fu** [Zie95-49]. **Fuchs** [Mas99]. **Fuller**
[Dic97]. **Function** [Goo95, MT92, RWHH97, Zie96-32]. **Functional**
[Bla92, Far97, Jol90, Zie91l, Geo98]. **Functions**
[Bre91b, CR93, Fri91, Gu91, Har92b, HT91, IHMT95, Bre91a].
Fundamentals [Zie95-49, Wan94, Bem96, Pit96, Rol93, Sau97, Sch93c, Sch93b, Sen95, Sys99, Zie96q, Zie99o]. **Fung** [HSPF92]. **future** [Ode90].
Fuzzy [Alm95, Bon95, Che95, Kan95, KMP95, LSBW95b, LSBW95a, Rou95, STR99, Zad95, Gut90].

G [Aye98, BR95, Ber91, Bod97, Car97, Coa94, Cob91, Col93, Die92, Gil92, Glo95, Gru90, Har91a, Hec99, Kan95, Kia95a, KY91, Lyn97b, Mac90a, Mar99, Mil99, Mil90, Nan94, Nem95, Pan92, Per97, Pfa99, Ram91, Rig92a, San98, Sar94a, Sha92, She90b, Sin98, Smi93, Ste90a, Was97, Zie90-28, Zie90i, Zie90w, Zie92f, Zie93-29, Zie93-35, Zie94e, Zie94a, Zie94v, Zie94-39, Zie94y, Zie94-36, Zie94i, Zie95-42, Zie95-46, Zie95-50, Zie96i, Zie96-40, Zie96-42, Zie96p, Zie96-46, Zie97-27, Zie97r, Zie97p, Zie97-43, Zie98-41, Zie98t, Zie98-29, Zie99-42, Zie99d, Zie99t]. **Gaetano** [God95]. **Galambos** [Zie95o, Ang90b].
Gale [Zie96y]. **Galwey** [Dri91]. **Gamma** [KGK90, Sin90a, Won92]. **Gans**
[Ram94]. **Gantz** [Bro90b]. **Gao** [Han98]. **Gap** [Arm90, Zie95y]. **Garcia**
[Job99, Lei91]. **Garcia-Diaz** [Job99]. **Gardiner** [Zha92]. **Gardner**
[Zie94q, Per92]. **Gareth** [Boo94b]. **Garrity** [LC94]. **Garrote** [Bre95a]. **Gary**
[Acr97, Kra92, Pro93b, Vin92, Wil90a]. **Gatsonis** [Zie96h, Zie98l]. **Gauge**
[VV99]. **Gaul** [Zie90g]. **Gaussian** [Bas90, CWWR97, DH92, PH99, WL91].
Gauvreau [Zie94-30]. **Gavin** [Kus92, San92]. **Geert** [Ste99]. **Geiss** [Zie98m].
Geisser [Law95]. **General** [Gun90, Pet93, Zie99-51]. **Generalised** [Sch94b].
Generalized [Che98, CR98, Emp92, EH96, Glo95, Gri97b, Gri93, Mar96, ME99, PF91, Qiu95, TC90, ZM94, LuV90, Sch92d, dV92]. **Generated**
[Mor97a, WL91]. **Generating** [Lin95b]. **Generation** [Zie95q, Gol90].
Generators [MKA96]. **Genshiro** [Zie99-36]. **GENSTAT** [Dri92, Dri91].
Gentle [LaL92, Zie99w]. **Geochemical** [Cam90]. **Geodesy** [Zie91m].

GeoENV1 [Zie98s]. **Geoffrey** [Kus98, Mil99, Ray93, Raz91]. **Geoffroy** [Ott90]. **Geographical** [Sch96c]. **Geography** [Sch94b]. **Geologic** [Zie90e]. **Geological** [Wat96]. **Geology** [Zie90m, Zie90j]. **Geometric** [And90, DGTZ97a, DGTZ97b, Hul97, Mil98, PE97, WH97, Zie93-29]. **Geophysics** [Zie91m]. **Georg** [Eub90]. **George** [Ale95, Ang91c, Arn90, Cam90, Fal99, Gho93, Liu92a, Lyn99, Por97b, Zei94, Zie93u, Zie97w, Zie98q, Zie99l, Zie99-49, vT91]. **Geoscientists** [Mye91, Zie99-43]. **Geostatistical** [Zie94b, Zie95s, Zie90i, Zie97n, Zie98t]. **Geostatistics** [Zie98s, Bil91, Cam96, Mye96, Zie96-44, Zie90j, Zie92h, Zie95r, Zie96r, Zie98u]. **Geosystems** [Zie99-46]. **Gerald** [Jon93]. **Gergen** [Wil98]. **Get** [Kun97]. **Getting** [Zie98v]. **Geweke** [Zie97c]. **Ghosh** [Ruk98, Zie94u, Zie97-34, Zie91o]. **Gibbons** [Zie93s, Gov92, Gro99, Zie95-37]. **Giel** [Zie97i]. **Gifi** [Goo92a]. **Gilchrist** [Zie94e]. **Gilks** [Gas97]. **Gill** [Kle94]. **Gillies** [Bla92]. **Giltinan** [Tim96]. **Giordano** [Zie90-27]. **Girden** [Bor97a, Zie93b]. **Giri** [Mat97]. **GIS** [Zie97-30]. **Gitlow** [Bre90, Zie95-31]. **Gittins** [Yin91]. **Glasbey** [Zie96t]. **Glasserman** [Rag95]. **Glen** [Gib91, Ruk98, Stu94]. **Glenn** [Zie95m, Zie99g]. **Gleser** [Dob96]. **GLIM** [Zie94e, Moo91]. **Global** [Mar99, STC99]. **Glossary** [Zie97o]. **Gnedenko** [Pap96]. **Goble** [Tor95]. **Godfrey** [Sch91a]. **Goggin** [Zie99-43]. **Goldsman** [Tam96]. **Gomez** [Zie98s]. **Gomez-Hernandez** [Zie98s]. **Gonin** [Spo90]. **Good** [Zie99a, Nik95]. **Goodman** [Zie99-37]. **Goodness** [GK90, Kin91]. **Goodness-of-Fit** [GK90]. **Gordon** [Pan96]. **Gore** [Bas97]. **Gottfried** [Far92]. **Gottman** [Ber92a]. **Goupy** [McC94]. **Gouri** [Boo93]. **Gourieroux** [Cab98, Zie99e]. **Government** [Pro96]. **Gower** [Tro97]. **GPSS** [Law92]. **Grace** [Gal92]. **Graham** [Cob91, Gle91, Mil98, Nai94, Zie94o]. **Grant** [Zie90t]. **Graph** [WC92]. **Graph-Aided** [WC92]. **Graphical** [FL95, Pit92, VM91, Goo91]. **Graphics** [Bla92, Buc90, Gra94, Hec99, Moo99, Pfa99, Zie93e, Amm92, Gol95, Moo99, Zie93z]. **Graphing** [Zie97-41, Kel97]. **Graupe** [Har92a]. **Gravely** [Zie99-48]. **Graybill** [Bar95, Ste98, Pot93]. **Green** [Mat98, Qiu95]. **Greenfield** [Aba98]. **Greenstreet** [Lit91]. **Greenwood** [Kin97]. **Gregoire** [Zie99t]. **Gregory** [Tim95, Tim99, Zie97l, Zie98c]. **Grey** [Zie99-28]. **Griffith** [Acr97]. **Groenendaal** [Lor93]. **Groeneveld** [Tho90b]. **Grosh** [Car90a]. **Gross** [Sys99]. **Groundwater** [Zie95-37]. **Group** [Hir96, ST90a]. **Group-Testing** [ST90a]. **Grouped** [HL97, SGW96]. **Groups** [ES94, Had92]. **Groves** [Sac93, Zie90-28, Zie93r, Zie99v]. **Growth** [EMS98, Sen98, Sen99b, Zie96s]. **Gruber** [Ang91b, Fam99]. **Gruet** [Bor97b]. **Gruska** [Zie96-46]. **Gryna** [Zie90l]. **GSLIB** [Zie95s]. **Gudmund** [Wil98]. **Gui** [Dea95]. **Guide** [Aba98, Bat99, Bay95, Bel95, Coo96b, Cro99, Hea94, Hes91, Jon93, Kin97, Lei93, Lit91, Nik95, Not92c, Pit92, San99, Wan94, Woo91, Zie90w, Zie99-52, Bre97, Don90, Dun96, Hem99, Tob99, Zie95s, Zie96-31, Zie98t, Tan93]. **Gulezian** [Han93]. **Gunst** [Bow91, Bru92b]. **Gupta** [Gut90]. **Gurevitch** [Zie95j]. **Guttorp** [Rus94]. **Guyon** [Bax96a]. **Gy**

[Bil92, Zie95z, Bil94, Zie95z].

H [Arm93, Bas99, Bil91, Bre90, Bru93a, Bry99, Cha93, Dri92, Fam99, Far93, Fre92, Fre94, Gla98, Gru97, Gun96a, Gun94a, Hag90, Hag91, Hag96, Hof95, Hwa92, Iye98, Jai95, Kah94, Kan95, Kia90, Kia92a, McC91, Pat91, Per98, Pfa92, Pri98, Pro92b, Rob90, Sch96b, Sha95, Sha97c, Spo90, Ste90c, Ste98, Tan98, Vin92, Win90, Zie90o, Zie90q, Zie91l, Zie91a, Zie93-32, Zie94r, Zie94x, Zie94v, Zie94-33, Zie95-29, Zie95-31, Zie95-44, Zie95-43, Zie96-43, Zie96-27, Zie96-38, Zie97z, Zie98-29, Zie98m, Zie98i, Zie99f, Zie99-51, Zie99n, Zie99-30, Zie99-32]. **H.-J** [Jai95]. **Haaland** [Jen91, Kel97]. **Hackl** [Rig99]. **Hahn** [Jon93, Zie94-39]. **Haimes** [Liu99]. **Haining** [Got92]. **Hald** [Zie92a, Zie99b]. **Hall** [Sea90]. **Hamilton** [Zie90e, Bie92, Boo97, Dre91, Gra94]. **Hamming** [Gut92]. **Hand** [Zie95a, Zie97t, Lin92, Tro97, Wad99, Zie95f, Zie95c]. **Handbook** [Bak98, Dri92, Ko95a, LC98, Rie94b, Sch92c, Sch93a, Sin90b, Zie90-27, Zie95a, Zie95-44, Zie98-33, Has91, Sch94a, Zie90l, Zie91c, Zie93v, Zie93g, Zie96l, Zie99-52, Bar91, Ber97, Bru92a, Glo93, Gri98, Sen94a, Wei94, Zie90k, Zie91i, Zie93l, Zie94u, Zie94w, Zie94v, Zie97p, Zie98w, Zie99p]. **Handle** [Cro94]. **Handling** [Cam98, Nem95, Oli97]. **Hands** [Stu94]. **Hands-On** [Stu94]. **Hannan** [Cry90, Ord96]. **Hans** [Eub90, Haw90, Mye96, Pro93a]. **Hans-Georg** [Eub90]. **Happen** [Hoc94]. **Hard** [Liu92b]. **Härdle** [Hin97, Zie98-41, Eub93]. **Hardy** [Zie94-35, Zie97x]. **Hariharan** [Bar95]. **Harnett** [Zie98n]. **Harold** [Kia93a]. **Harrell** [Bre97]. **Harris** [Sys99, Zie91p, Zie93p, Zie98-48]. **Harrison** [Bar91, Zie99p, Wes92, Zie97e]. **Harry** [Cab94, Gun99, Rig92a, Zie90-27, Zie93h]. **Hart** [Pro90, Ale99, Pro90]. **Harvey** [Ang92, Ens95]. **Harville** [Zie98-30]. **Hasofer** [Ste90a]. **Hasselblad** [Len93]. **Hastie** [dV92, Hes93]. **Hastings** [Zie94-38]. **Haswell** [Bay95]. **Hatcher** [Zie95b, Hec96]. **Hatzinger** [Zie96-40]. **Haugh** [Zie99-37]. **Havenner** [Zie98f]. **Havlicek** [Jen90]. **Hawkins** [Ver90]. **Hayes** [Gru97, Zie95w, Zie98-31]. **Health** [Woo91, Zie94c]. **Heaphy** [Zie96-46]. **Heat** [Tho94]. **Hecht** [Rig92a]. **Hedayat** [Zie93j]. **Hedges** [Zie95-44]. **Heiberger** [Sco91]. **Heinen** [Gol98]. **Helmut** [Jol93]. **Helsel** [Got94a]. **Henk** [Mad96, Spr91]. **Henri** [Hal95]. **Henrion** [Zie95-47]. **Henry** [Sti97]. **Hernandez** [Zie98s]. **Herzberg** [Tho92b]. **hesketh** [Lee99]. **Hess** [Bow91]. **Heterogeneity** [Bil94]. **Heterogeneous** [AHT91, Bil94]. **Heteroscedasticity** [CS92]. **Hettmansperger** [Mi99]. **Heuristic** [Mar99]. **Heyde** [Bor98]. **Hiatt** [Zie96-51]. **Hicks** [Bod97, Pit96]. **Hidden** [JR91, Ped98]. **Hierarchical** [Cal94]. **Higgins** [Huz95]. **High** [Kii92, MSH94]. **High-Breakdown** [MSH94]. **High-Dimensional** [Kii92]. **Higham** [Zie94w]. **Higher** [Fre95]. **Highly** [HW91]. **Hild** [Per97]. **Hildebrand** [Koo90, Zie99-41]. **Hildrum** [Zie95y]. **Hills** [Zie95-39]. **Hinde** [Moo91]. **Hines** [Nar93]. **Hinkelman** [Tom95]. **Hinkley** [Zie92s, Zie93-30, Zie97-42]. **Hirotugu** [Zie99-36]. **Hirsch** [Got94a]. **Histograms** [Deu96]. **Histories** [Zie98-28]. **History** [Zie92a, Zie99b].

Hjorth [Len95]. **Hoaglin** [Sch93c, Sch93b, Cro94]. **Hocking** [Dea97]. **Hodges** [Zie96h, Zie98l]. **Hogg** [Zie93c]. **Hohn** [Zie90j]. **Hollander** [Cly94, Zie99u]. **Homogenizing** [Bil94]. **Hong** [Han98]. **Hong-Ye** [Han98]. **Honor** [Zie91k]. **Hopke** [Zie92c, Zie94k]. **Hoppe** [Zie94-27]. **Horgan** [Zie96t]. **Horrell** [Zie98n]. **Hosmer** [Cuc92, Zie94c]. **Household** [Zie99v]. **How-To** [Zie96-45]. **Howard** [Goo92b, Pri93, Zie90b]. **Hows** [Zie93-35]. **Høyland** [Van96b]. **Hsiang** [She90b]. **Hsu** [Chr97]. **Hubele** [Run90, Zie99l]. **Huberty** [Hec95]. **Huet** [Bor97b]. **Hunt** [Rag93]. **Hutchinson** [Not92a, Not92c]. **Hy** [Hal94]. **Hydrology** [Por97a]. **Hypercube** [PH99, Ste87, Ste90b]. **Hypotheses** [KGK90, Len90, Nik95]. **Hypothesis** [Hor98, VS96]. **Hypothesis-Testing** [VS96].

Iain [Ped98]. **IBM** [Cam90, Dun90]. **Ideas** [Moo99, Rag93, Zie99a]. **Identification** [Har92a, Pan99, STR99, Taa91]. **Identifying** [VS96, VS98]. **Idle** [GD91]. **Iglewicz** [Cro94]. **Ignition** [Tho94]. **Igor** [Gri99, Pap96, Rie94a]. **II** [HH96, Kia93b, Sin92, Zie94-45, Sin83, Bru97, Zie90v, Zie94k, Zie96h]. **III** [DL90a, Zie98l, Zie98k]. **Ildiko** [Zie96l]. **Illustrated** [Nem95]. **Ilya** [Mi97]. **Image** [Zie96t]. **Images** [Baj98]. **Iman** [Gri96]. **Immunoassay** [RJ97]. **Impact** [Pan99, Zie95c]. **Implications** [CH96b, Zie90p]. **Importance** [Hes95]. **Important** [WC92]. **Improve** [Zie99a]. **Improved** [CR93, KM94, Mee90a, MME98]. **Improvement** [AHT91, Bel95, Bre90, Bre96, Dog93, Dun96, Fox94, Gan97, Gun96b, Pan96, SG99, Zie94l, Zie97a, Zie97w, Zie98-35, Aba98, Ada94, Bel99, Bem96, Gho94, Gri98, Hal98, Lam90, LC94, McG94, Nem92, Pro90, Woo92, Zie93i, Zie93-35, Zie94h, Zie95-31, Zie98q, Zie98-40, dC99]. **Improving** [Cha92, Fam99, San98, Zie97q]. **In-Process** [Pla90]. **Inc.** [Zie99-50]. **Incomplete** [SS97]. **Incorporating** [LT96]. **Increasing** [CS93, GS94, Sne98]. **Independent** [STC99]. **Index** [Zie90h]. **Indices** [Cha95, Yin91]. **Indirect** [TW96]. **Industrial** [Bod97, Bog92, CH96a, CM93b, CM93a, Edg98, Fre99, Gun93, HO93, Hah93, LST93, Pan92, Rol93, Zie91o, Zie92x, Zie95t, Zie96-48, Zie98-40, Zie99o, Die92, Zie98x]. **Industries** [Arm93, Lew92, Zie94r, Zie97-31, Zie99-33]. **Industry** [HH98a, HH98b, Kaf94, KTTS90, MTV98, Nem98, Pan96, Pro96, Zie91h, Dog93, Jen92]. **Inference** [Boo98, CWWR97, FRY96, HO95, HP97, HL97, Koe92, Law95, Lei99, LPY97, Zie93j, Ang91c, Bas99, Cha98, Das93, Gun94a, Ruk97b, Sha95, Sha98, Sho90, Ste98, Zie92q, Zie93s, Zie94j]. **Inferences** [Won92]. **Inflated** [Lam92, LLP$^+$99]. **Influence** [Peñ91, Sch91d, TC90, Ter92]. **Influential** [SD90, STR99]. **Informatics** [Zie90f]. **Information** [Ano90l, Ano91k, Ano92i, Ano93k, Ano94i, Ano95i, Ano96i, Ano97k, Ano98j, Ano99k, JS99, Koh90, SS97, Sri93, Sco92]. **Informational** [Zie95-29]. **Infra** [Zie95y]. **Infra-Red** [Zie95y]. **Ingram** [Dob96]. **Inhomogeneity** [Cre97]. **Inputs** [GSH98]. **Inspection** [DGTZ97a, DGTZ97b, God95, GS95, HR92, Hul97, PE97, VV94, WH97, HR94, Car93]. **Institute** [Zie96x, Zie99r].

Instructional [Kal93]. **Integral** [Li97, TWN98]. **Integrated** [HNF97, TH93, Tho90b, Van96a]. **Integrated-Circuit** [TH93]. **Integrating** [HP92]. **Integration** [CFRH99]. **Intelligence** [Zie95f, Zie95-49]. **Intensity** [CS93]. **Intensive** [Bro90b, Len90, Len95, Zie97z]. **Interaction** [Ale98, Ano99e, Ber92a, FL97, Emp99]. **Interactions** [Oeh94, WC92]. **Interactive** [Hin97, Bla92, Zin93]. **Interest** [Zie97-31]. **Interface** [Bro90b]. **Intermediate** [Bal93]. **Interpolation** [VD94]. **Interpretation** [Ram91, Wen94]. **Interpreting** [Edg92, Lee90, Zie96u]. **Intersection** [Rou95]. **Interval** [BL94, Spu93, VB94b]. **Intervals** [BBT90, CR91, DS93, Hea90, Jon93, LS90a, Mee90b, MER91, Pet93, Pot93, RAA90a, RAA90b, Sch92b, WI94, Woo90, DSSU98, Ode90]. **Interview** [Zie99v]. **Introducing** [Sch94b]. **Introduction** [Ber92a, Bil91, Bro92, Dav99, Emp92, Fre94, Gol95, Gri95, Had92, Ked98, Ko95b, Liu92b, Mor92, Pro92b, Rig92a, Sau94, Sch96a, Tom95, Yak97, Zie94f, Zie95-50, Bax96b, Ber92b, Che94, Dic91, LaL92, Law95, Len90, Tso92, Zie98j, Zie99-42, Arn90, Bab98, Bos92, Cam96, Dic97, Dun97, Far92, GR97, Gil92, Hor98, Jol93, Jon91a, Lyn99, Por93, Rig93, Sau92, Sau98, Sea90, Sen94b, Sen97, Sha97b, Taa99, Wol92, Zei94, Zie94x, Zie94y, Zie95t, Zie96w, Zie96v, Zie98y]. **Introductory** [Zie95-50, Bul96, Lin99, Tho90b, Zie93m]. **Inverse** [Bas90, DH92, MS95, WL91]. **Investigation** [Gib91]. **Investigations** [Mee91a]. **Involving** [Zie96n]. **Iorio** [Zie97x]. **Irradiation** [GK93]. **Irwin** [Wyc96]. **Isaac** [Lei97]. **Isaaks** [Bil91]. **Isaksson** [Zie95y]. **Isham** [Fre93]. **Ishikawa** [Bos92]. **ISO** [Zie93n]. **Isolating** [Oeh94]. **Isolation** [DDPG94]. **Issue** [Zie91p]. **Issues** [DGTZ97a, DGTZ97b, Hul97, KTTS90, PE97, Sri93, WH97, Zie91r, Zie99-39, Pig91]. **Iteratively** [Mar96]. **Iversen** [Wil98]. **Iwasiewicz** [Mor93b]. **Iyer** [Ste98, Bar95].

J [Ada96, Alt99, Ang91a, Arm97, Bar92a, Bas90, Bas97, Bel95, Bel99, Ber91, Boo95, Boo92, Boy90, Bro90b, Bry92, Bul96, Cab94, Cal98, Cob91, Cra94, Cro99, Cry90, Deh90, Dob96, Dri92, Dun97, Emp92, Fai91, Fam99, Fox91, Fri97, Ful95, Gas97, Gil92, Gle96, God93, Goo91, Gov92, Gre94, Gri95, Gun94a, Had92, Han97, Har91a, Har91d, Hec95, Hes91, Hes93, Huz95, Jai95, Joh91, Jon93, Ked96, Kia90, Kia92a, Kia92b, Kia93b, Kia94, Kin91, KY91, Kot92, Kus92, Kus98, Law92, LeP90b, Lei92, Lei93, Len95, Lin92, Lyn95, Mar99, Mat98, Mi99, Mil98, Mor97a, Mul97, Nem92, Nem97, Neu99, Nik93, Oli98, Ord96, Ott90, Owe96, Pit92, Pro93a, Qiu95, Rag93, Ram99, Ray93, Raz91, Rie97, Run90, Sam99b, San92, Sch92a, Sch92d, Sco90]. **J** [Sha95, Sha97c, Sha97b, Sha98, Sim91, Sin98, Spa99, Ste91, Tam96, Ter92, Tob99, Tro97, Tsa91, Tso92, Wad99, War90, Wei90, Wes92, Wol96, Wol92, Won94, Yan97, Zha92, Zie90l, Zie90-28, Zie90-27, Zie90n, Zie90w, Zie91m, Zie91q, Zie92x, Zie92r, Zie92s, Zie93-30, Zie93c, Zie93t, Zie93o, Zie93l, Zie93g, Zie93s, Zie93n, Zie94r, Zie94-28, Zie94-32, Zie94p, Zie94c, Zie94m, Zie95o, Zie95-38, Zie95j, Zie95-28, Zie95-50, Zie95c, Zie96o, Zie96-37, Zie96-44, Zie96j, Zie96h, Zie96a, Zie96-51, Zie96-52, Zie96-39, Zie97e, Zie97v, Zie97c, Zie97-44,

Zie98s, Zie98m, Zie98-28, Zie98w, Zie99k, Zie99-43, Zie99t, Zie99n, dV92]. **Jaccard** [Ale98, Emp99]. **Jacek** [Gho94]. **Jack** [Bar92b, Lor93, Zie99q]. **Jackknife** [Hes97]. **Jackknifing** [Cre97]. **Jackson** [Nai96, Lei93]. **Jacoby** [Hec99, Pfa99]. **Jacqueline** [Zie99-52]. **Jacques** [Cam96, McC94]. **Jaffe** [Hec90, Zie95u]. **Jagdish** [Ber97, Fot95]. **Jain** [Sar90]. **Jambu** [Not92b]. **James** [Ale98, Bal93, Boo97, Bow91, Che98, Dea96, Emp99, Gho94, Gue90, Jol97, McG94, Pap96, Par92, Pie90a, Sen94a, She90a, Wat96, Wel90, Zie93q, Zie96n, Zie98n, Zie98l, Zie98i, Zie99w]. **Jan** [Bay92, Glo97, Jol90, Kel97, Sch91b]. **Jan-Aage** [Kel97]. **Jan-Bernd** [Bay92]. **Janacek** [Boo94b]. **Janos** [Ang90b]. **Janssen** [Zie96a]. **Jason** [Chr97]. **Jay** [Hec90, Zie92l, Zie95u]. **Jaya** [Zie90s]. **Jean** [Gro99, Zie96-38]. **Jeff** [Dow95, Ord96]. **Jeffrey** [Ale99, Che94, Zie98h]. **Jenkins** [Zie95-46, GJMS$^+$95]. **Jennrich** [Sch96a]. **Jensen** [Zie94-28, Zie99-43, Tor99, Yak97]. **Jerry** [Goo92b, Mil91, Zie99-43]. **Jersy** [Zie99k]. **Jessica** [Fam97]. **Jewell** [Zie97r]. **Jewgeni** [Gla98]. **Jill** [Zie99-29]. **Jim** [Geo98]. **Jiri** [LaL95]. **JMP** [Zie99r]. **Jobe** [Spa99]. **Jobson** [Kia92b, Kia93b]. **Joe** [Iye98]. **Joel** [Zie99-29]. **Jogesh** [Coa94]. **John** [Bat99, Bay95, Ber92a, Bro90b, Bul91, Car95, Che91, Czi92, Dav99, Dea91, Dom90, Dov93, Gol90, Gra98, Gro96, Hag96, Hes93, Kin93, Mag96, Moo91, Mor97a, Owe91, Pro92a, Pro94, Rao98, Roz93, Yin91, Zie91f, Zie91e, Zie92b, Zie92i, Zie93x, Zie95v, Zie95-43, Zie96-35, Zie97y, Zie98-42, Zie99d, Zie99r, vN90, Bru93b, SDP$^+$95, Zie99-38]. **Johnson** [Ber96b, Boo93, Bru94, Car93, Fam95, Lor99, Pos98, Zha92, Zie90h, Zie92g, Zie94-45, Zie94-44, Zie98e, Zie98z, Zie99c, Cha95, PGT95, Wil90b, Zie90e, Zie94-45, Zie98k, vT91]. **Joiner** [Zie95q]. **Joint** [Gan95, NLB$^+$98, USM99, WT98]. **Jolivet** [Bor97b]. **Jones** [Aba98, Kim91, Mor92, Zie90e, Zie91q, Yan96, Zie94z]. **Jordan** [Oli98]. **Jöreskog** [Lyn97b]. **Jorgensen** [Bor95b, Sen99a]. **Jorner** [Kel97]. **Joseph** [Ada92, Pro92b, Rie97, Zie92j, Zie98b]. **Journel** [Zie95s, Zie98t]. **Journey** [Zie93a]. **Judd** [Vin92]. **Julius** [Nan94, Taa91]. **Jump** [QY98]. **Jump-Detection** [QY98]. **Jun** [Hes97]. **Juran** [Zie90l, Zie90l]. **Jurand** [Mor93b]. **Jure** [Wol91]. **Jurgen** [Sim97, Tor99]. **Just** [Kal93, Zie99a]. **Just-In-Time** [Kal93].

K.-T [Str96]. **Kadane** [Zie98b]. **Kahle** [Tor99]. **Kai** [Loh92]. **Kai-Tai** [Loh92]. **Kai-Wang** [Loh92]. **Kaiser** [Sen94a]. **Kalivas** [Hag96]. **Kalman** [Ang92]. **Kalsbeek** [Zie93t]. **Kalton** [Zie90-28]. **Kaluzny** [Zie98-38]. **Kalvelagen** [Spr91]. **Kam** [Lor99]. **Kam-Wah** [Lor99]. **Kaminsky** [Zie94-43]. **Kane** [Bru91]. **Kanji** [Zie94a]. **Kao** [Ked98]. **Kaoru** [Bos92]. **Kaplan** [Zie98-45]. **Kapur** [Zie90n]. **Karen** [Zie99a]. **Karian** [Law92]. **Kariya** [Roh91]. **Karl** [Zie91r]. **Karlin** [Fre94]. **Karprzyk** [Zie90-28]. **Kass** [Zie96h, Zie98l]. **Kateman** [BR95]. **Kathleen** [Rab92, Wel93]. **Kaufman** [Gut90, Had92, Mac90a]. **Kay** [Sen95]. **Kaye** [Raz91, Zie99-32]. **Kazense** [Zie94-44]. **Kazmierski** [Fri97]. **Keats** [Run90, Zie92r, Zie96-37]. **Kececioglu** [Sch92c, Sch93a, Sch94a]. **Kedem** [Fre95]. **Keenan** [Dov93].

Keiding [Kle94]. **Keith** [Boo92, Zie90r]. **Keki** [Hoc94]. **Keller** [Huz95]. **Keller-McNulty** [Huz95]. **Kelly** [Zie94g, Zie96-30]. **Kelton** [Dea94]. **Kemp** [Bru94]. **Kempthorne** [Tom95]. **Kendall** [Boo92, Gov92, Zie94-28]. **Kenett** [Fre99, Mas99]. **Kenneth** [Bru96, Kan95, Sto96, Tob99, Zie99i]. **Kenward** [Zie91q]. **Keppel** [Zie92f]. **Kerim** [Bre97]. **Kernel** [Yan96]. **Kessler** [Zie97s]. **Kewley** [Zie99q]. **Key** [HH98a, HH98b, MTV98, Nem98, Voe94]. **Kharin** [Boo99]. **Khattree** [Zie96d]. **Khosrow** [Pie90b]. **Khuri** [Zie97y, Zie94d]. **Khurshid** [Zie96-43]. **Kidd** [Zie93u]. **Kiemele** [Nem92, Zie94h]. **Kim** [Zel94, Sam99a]. **Kimber** [Bar92a, Zie97r]. **Kinetics** [ML95]. **King** [Zie95-32, Zie97-32]. **Kingman** [Boo95]. **Kit** [Zie96-47]. **Kitagawa** [Zie99-36]. **Kitsos** [Zie98x]. **Klaas** [Bar92b]. **Klaassen** [Bar92b]. **Klar** [Zie94c]. **Klaus** [Tom95]. **Kleijnen** [Lor93]. **Klein** [Rao98, Arm93]. **Kleinbaum** [Car97, Kia95a]. **Klinke** [Hin97]. **Kloeden** [Hal95]. **Klugman** [Zie98-29]. **Knezevic** [Lyn95]. **Know** [Car90b, Car92, Geo94]. **Knowledge** [Zie90g, Zie98c]. **Koch** [Cam90, Zie96i]. **Kocherlakota** [Wel93, Wel93]. **Koenig** [Zie93f]. **Kokoska** [Zie90u]. **Kolmogorov** [Rag93]. **Kolosova** [Zie99-31]. **Koopmans** [Per98]. **Koronacki** [Gho94]. **Kosecoff** [Zie99-52]. **Kott** [Zie96g]. **Kotz** [Ber96b, Bru94, Car93, Cha95, Fam95, Loh92, Pos98, Zie90h, Zie92g, Zie94-45, Zie98o, Zie98p, Zie98k, Zie98z]. **Kovalenko** [Gri99]. **Kowaka** [Zie95t]. **Kragh** [Kle94]. **Kramer** [Bay99]. **Krause** [Zie98-46]. **Krewski** [Zie95-41]. **Kriging** [Cam96, HS93, ZZ91]. **Krishnaiah** [Sin90b, Zie90k, Zie91k]. **Krishnamoorthi** [Lee93, McC90]. **Krishnan** [Kus98]. **Krumm** [Zie93-35]. **Kruskal** [Zie90w]. **Krzanowski** [Sha95, Sha97c, Lin90, Wol96]. **Kshirsagar** [Zie96s]. **Kubacek** [Zie91m]. **Kubackova** [Zie91m]. **Kukuca** [Zie91m]. **Kunio** [Zie99-36]. **Kuo** [Sam99a, Zie93w]. **Kurt** [Bor97c]. **Kurtz** [McA90]. **Kutner** [Zie97-44, Kia90, Zie92b]. **Kuznetsoy** [Gri99].

L [Ajm99, Ang91c, Arm97, Aye98, BR95, Bar92b, Bar92a, Bax95, Ber96b, Bog92, Bow91, Bri96, Bro92, Bru92b, Bru94, Bul91, Bzi97, Car90a, Car93, Cha95, Dom90, Fai91, Fam95, Glo95, Gre94, Gri96, Had92, Ize91, Jen90, Jol90, Jon91a, Kot92, Lit91, Mac90a, Mar99, McC94, Nay98, Ped98, Pos98, Pri93, Rao98, San99, Sho90, Sin90a, Ste90c, Wat90, Zha92, Zie90-28, Zie91m, Zie91r, Zie91c, Zie92l, Zie93r, Zie93-35, Zie94e, Zie94-28, Zie94-44, Zie94s, Zie94-36, Zie94i, Zie95-49, Zie95-32, Zie95b, Zie95-44, Zie96-32, Zie98n, Zie98-43, Zie98x, Zie98e, Zie98k, Zie98z, Zie98w, Zie99z, Zie99-49, Zie99-43, Zie99-52, Zie99-30]. **Lab** [Spr91]. **Laboratories** [Zie94g]. **Laboratory** [Mag96, Smi93, Zie93l]. **Labys** [Dow95, Ord96]. **Lack** [Ale99]. **Lack-of-Fit** [Ale99]. **Lad** [Kat98]. **Lahey** [Zie97v]. **Lai** [Not92a, Not92c]. **Lake** [CDKS92, Zie99-43]. **Lake-Chemistry** [CDKS92]. **Lambert** [Per98]. **Lamprecht** [Zie93n]. **Land** [Coh92]. **Lane** [Dri91]. **Lang** [Hag96]. **Language** [Bat99, Sco90, Zie98h]. **Lao** [Zie96u]. **Lapin** [Ajm99, Was91]. **Large** [CCC90, FL95, Ste87, Ste90b, Par92]. **Large-Sample** [CCC90]. **Larry** [Gru90, Hec96, Jen93, Sar94b, Sch94b, Zie99-43, Zie99-37]. **Larsen** [Kot92].

Latent [Gol98, Bay92, Gol98, Zie93o]. **Latin** [Ste90b, Mor98a, PH99, Ste87]. **Lattice** [Boy96]. **Latzko** [Zie95p]. **Launsby** [Aye98, Pan92, Zie96-48, Zie97v]. **Lauter** [Zie90o]. **Lave** [Zie91n]. **LaVerne** [Che92]. **Law** [Bak96, Dea94]. **Lawrence** [Ajm99, Bie92, Dre91, Fai91, Gra94, Law96, Rol93, Was91, Zie90r, Zie99f, Zie99o]. **Lawson** [Cab94]. **Lawyers** [Zie92t]. **Layouts** [Car95]. **Leader** [Zie93a]. **Leadership** [Zie98-48]. **Leading** [Zie98z]. **Learning** [Bri96, Car97, Ful95, Kia95a, Sai96, Wu99, Ale91]. **Least** [Bay92, Mar96, Thi91, Ode90]. **Leavenworth** [Zie90t]. **Lechner** [Zie95o]. **Lecture** [Har91c, Ste99]. **Ledolter** [Zie93c]. **Lee** [Bry92, Zie97r, Ber92b, Lei92, Pri93, Zie93-27, Zie96v, Zie98j]. **Leemis** [Law96]. **Leeuw** [Zie98-43, Jol90]. **Lehman** [Zie90w, Zie99r]. **Lehmann** [Zie99-49]. **Lehtonen** [Zie96-29]. **Leitch** [Bax96b]. **Leitnaker** [Per97]. **Lemeshaw** [Zie92m]. **Lemeshow** [Zie94c, Cuc92]. **Length** [AWS94, Fel94, Luc94, WMP94a, WMP94b]. **Lentner** [Web90]. **Lenz** [Zie99n]. **Leon** [Dob96, Lei91]. **Leon-Garcia** [Lei91]. **Leonard** [Ada93, Mor99a, Vuk98]. **LePage** [KR93]. **Lepingle** [SN95]. **Leroy** [Bas90]. **Leslie** [Sch95]. **Lessi** [Zie98g]. **Lessler** [Zie93t]. **Lester** [Zie91n, Zie94-33]. **Letchford** [Zie95-40]. **Letkowski** [Zie99k]. **Letter** [Haw94, Yas90]. **Level** [BS99, Bla92, CL93, DL90a, FL97, HCV98, LIV96, Sch91c, WC92]. **Levels** [Ngu96b, WW92, Gri90]. **Levin** [Zie92t]. **Levine** [Wat90, Zie96-52]. **Levinson** [Hal98]. **Levy** [Zie92m, Wal92b]. **Lewi** [Zie98w]. **Lewis** [LeP90b, Bre95b, SDP$^+$95]. **Li** [LW98]. **Liang** [Zie95d]. **Library** [Zie95s, Zie98t]. **Life** [Bry92, DS93, DH92, EM95, EM99, Hul92, Kim91, KS93, ML95, MM94, Sam90, Sch91c, Sch94a, Spe91, VB94b, Zie95t, Zie96-34]. **Life-Data** [DS93]. **Life-Testing** [Bry92]. **Lifetime** [HLS98, Zie97r]. **Likelihood** [Glo99, Gri93, Har91c, Sin83, Sin92, Lei99, Bor98]. **Limit** [Ann99, Ano99f, BL94, JFM99, KK99, PM99]. **Limited** [Cal98]. **Limits** [AKO94, BT89, CM99, DM99a, DM99b, Gib99, Gil99, KR93, MT91, Nel95, Van92b, Van99, BT98]. **Lin** [WKWL95]. **Lind** [Zie99-42]. **Linda** [Zie90x]. **Lindgren** [Har91b, Zie97-35]. **Lindley** [Fox91, Sam90]. **Lindman** [Kia93a]. **Lindsey** [Bul96, Che98, Kia94, Owe96, Sha98]. **Line** [KD97, NW93]. **Linear** [Ano90f, Bor95b, Cal94, Cam96, Che98, Coo96a, Cry90, Dea95, Dea97, Emp92, Emp93, EH96, Gil92, Glo95, Gra98, Hir96, Kia90, Kia92a, LPY97, Mar96, ME99, PF91, Por93, Qiu95, RN91, SD90, Sch92b, Sch92d, Sch94b, SS89, TI99, TC90, Zie92b, Zie92n, Zie97-44, Zie99w, Zie99-51, Bor97c, Bro90a, Dea96, Hab92, Nip92, Ste99, Thi91, Zie91j, Zie98-27, Zie98-28, Zie99s]. **Linear-Calibration** [SS89]. **Linfield** [Gat96]. **Link** [Wol95, Zie90w]. **Linking** [OUH93]. **Lisp** [Amm92]. **Lisp-Stat** [Amm92]. **LISREL** [Ale98]. **Littell** [Hei90, Zie92n, Zie97-27, Zie92o, Zie99-35]. **Liu** [Zie94p, Zie96-39]. **Lloyd** [Cha92, Fox94]. **Loading** [SW95]. **Loads** [USM99]. **Local** [QY98, RWHH97, Sch91d]. **Local-Influence** [Sch91d]. **Location** [HC91, Pan99, Sin83, WT98, Sin92]. **Lochnar** [Pro92b]. **Lock** [Wha95]. **Locks** [Pla96]. **Loehlin** [Zie93o]. **Log** [RN91, Hab92, Zie98-27, Zie98-28].

Log-Linear [RN91, Hab92, Zie98-27, Zie98-28]. **Logic** [Alm95, Bon95, Zad95]. **Logistic** [Cuc92, Glo93, Zie96c, Zie98-27, Kia95a, Kia95b, Zie96x]. **Logothetis** [Hwa92]. **Lohmöller** [Bay92]. **Long** [Glo97, Zie98-44, Cal98]. **Long-Memory** [Glo97]. **Long-Term** [Zie98-44]. **Longford** [Gal95]. **Longitudinal** [Eub90, Zie95d, Zie97t, Zie99t, Zie94z]. **Look** [DP90, Hab90, HW90b, HW90a, Hir90, Nai90b, YDB90, Lin93a, Lin95a]. **Looking** [SC93]. **Lorenzen** [Gre94, MLV92]. **Lori** [Mag96]. **Loss** [Har92b, MT92, Zie98-29]. **Lot** [Bru96, MB98]. **Lothar** [LC98]. **Lotus** [Kus93, Sar93]. **Louis** [Kal93, Mor92, Ruk97a]. **Louise** [Boo94b]. **Lowry** [Ara92]. **Luanga** [Zie94c]. **Luceño** [Fal99]. **Luftig** [Oli98]. **Luis** [Nel98]. **Luke** [Amm92]. **Lunn** [Zie95a, Zin93]. **Lunneborg** [All96]. **Lütkepohl** [Jol93, Zie94x]. **Lwin** [Ang91a]. **Lyberg** [Zie90-28, Zie93r, Zie98-43]. **Lyday** [Bri91]. **Lyman** [Arm92, Koo90, Zie94f, Zie99-41]. **Lynch** [Zie94l]. **Lynn** [Gil92, KR93].

M
[Alt96, Bab98, Bak98, Bar91, Bar92a, Bat99, Ber92a, Ber92b, Bil94, Bru93b, Bry99, Bzi97, Cly94, Coh92, Cox93, Dea94, Elt90, Emp93, Fam97, Fox91, Fre94, Geo94, Got94a, Gov92, Gut90, Hag96, Han97, Hes93, Hof95, Jan94, Kat91, Kia90, Kus93, Law96, LC94, Len93, LH97, Lin92, Lor92, Mac90a, Mad98, McL95, Mil90, O'D97, Per97, Pit92, Rag93, Sac93, Sar93, Sch91a, Sco90, Sea93, Sen95, Soy95, Ste90a, Sys99, Tam96, Tim96, Tor95, Ver90, Vin92, War90, Wat90, Weh93, Wes92, Yan96, Zie90l, Zie90-28, Zie90-27, Zie90i, Zie90g, Zie91k, Zie92t, Zie92h, Zie92p, Zie93w, Zie93z, Zie94h, Zie94-30, Zie94-38, Zie94m, Zie94-35, Zie95t, Zie95-47, Zie95-39, Zie96b, Zie96i, Zie96-52, Zie96g, Zie96s, Zie96-46, Zie96-49, Zie97r, Zie97-28, Zie97e, Zie97t, Zie97-37]. **M** [Zie97-44, Zie97n, Zie98-41, Zie98j, Zie98v, Zie98c, Zie98f, Zie98-43, Zie98g, Zie99k, Zie99-43, Zie99v, Zie99p, Zie99y]. **Mac** [Gat96]. **MacDonald** [Ped98]. **Machin** [Zie97-37]. **Machine** [Ful95, Sto92]. **Machine/Process** [Sto92]. **Machines** [DGTZ97a, DGTZ97b, Hul97, PE97, WH97]. **Macros** [Wit94]. **Madansky** [Eas90]. **Maddala** [Zie94v]. **Maddox** [Zie90-27]. **Made** [Bre97, Zie95-35]. **Madhav** [Men91]. **Magdalena** [Cha98]. **Mager** [Bur91, Yeh93]. **Main** [Jac92, Jac93]. **Main-Effect** [Jac92, Jac93]. **Maintainability** [Hey98, JD92, Lyn95, Pla96]. **Maintenance** [Zie96-35]. **Make** [Hoc94]. **Making** [Gru95, Liu92a, Liu92b]. **Mal** [Woo92]. **Malay** [Ruk98]. **Malcolm** [Zie96-46]. **Malinowski** [Bla94]. **Maller** [Zie98-44]. **Mallios** [Pig91]. **Mallows** [Zie91f, Zie91e, vdVtBM97]. **Malone** [Zie90x]. **Mamzic** [Zie96-41]. **Management** [Gut90, HH96, Kal98, Mar94, Nar93, Zie91n, Zie95q, Zie95-31, Zie97k, Zie99z, Beg90, Dog99, Dun97, Liu99, Wyc96, Zie93-37, Zie93-36, Zie97i, Zie99-28]. **Manager** [Bre97, Car92, Coo96b, Lit91]. **Managerial** [Zie97f]. **Managers** [Zie96-52, Ada92, Koo90, Rea93, Zie90-27, Zie93h, Zie99-41]. **Managing** [Voe94, Zie97s, Rea93, Zie93p, Zie93q, Zie96z, Zie96y]. **Mancuso** [Zie92j].

Mandel [Car95, Roz93]. **Manfred** [Cry90, Lin99]. **Manly** [Nem97, Nik93, Zie98-36]. **Mann** [Zie93m, Zie95-50]. **Manton** [Kan95]. **Mantz** [Ang91a]. **Manual** [Mag96]. **Manufacturing** [Fot96, Kir93, Lam92, Sam99a, Sto92, TH93, Bru92a, Che91, Kal93, McL95, Mor99a, Pla90, Pol93, Run90, Won98, Zie92r, O'D99]. **Many** [Oma91, vdVtBM97]. **Map** [HA93, HNF97]. **Mapping** [HLD98]. **Marazzi** [IHMT95]. **Marchal** [Zie99-42]. **Marcus** [Spa99]. **Marden** [Gro96]. **Marie** [Bor97b, Tim96, Zie99q]. **Marie-Anne** [Bor97b]. **Marilyn** [Pro90, Zie99k]. **Mario** [Far90, Pap95, Sto92]. **Mark** [Goo92b, Nem92]. **Market** [Zie96w, Zie97-36, Zie98v]. **Markov** [Dea91, Ped98, JR91, Yas92, Bax95, Gas97, Hof95]. **Markov-Type** [Yas92]. **Marr** [Ano93f, FMQ92]. **Marriott** [Sha95, Sha97c, Zie91a]. **Marsal** [Mye91]. **Martens** [Hag91]. **Martin** [Bax95, Mee91a, Ruk97b]. **Marubini** [Zie96b]. **Marvin** [Ang91b, Fam99, Van96b, Web90]. **Marx** [Kot92]. **Mary** [Gil92, Tob99, Wil98]. **Mary-Lynn** [Gil92]. **Marylees** [Wyc96]. **Marylyn** [Buc90]. **Masanao** [Zie98f]. **Masking** [FRY96]. **Mason** [Bow91, Zie99-42, Bru92b]. **Massart** [Mac90a, Zie92c, Zie94k, Zie98w]. **Massey** [Zie90-28]. **Mastering** [Hec90, Zie92j, Zie95u]. **Matar** [Pro92b]. **Material** [Beg90, Bil94]. **Materials** [USM99, Zie95t]. **Mathematical** [Gut90, RM95, Zie91f, Zie91e, Zie94w, Zie99b, Zie90-27, Gri99, Hag96, Hig98, Mat98, War90, Zie90m, Zie90n, Zie95v]. **Mathematics** [Smi93, Zie91c, Rig92a]. **Matheron** [Ste90a, Zie90i]. **Mathew** [BZM96]. **Mathews** [San99]. **Mathiowetz** [Zie93r]. **Matrix** [Zie98-30]. **Matter** [Ano90a, Ano90b, Ano90c, Ano90d, Ano90h, Ano90i, Ano90j, Ano90k, Ano91a, Ano91b, Ano91c, Ano91d, Ano91g, Ano91h, Ano91i, Ano91j, Ano92a, Ano92b, Ano92c, Ano92d, Ano92e, Ano92f, Ano92g, Ano92h, Ano93a, Ano93b, Ano93c, Ano93d, Ano93g, Ano93h, Ano93i, Ano93j, Ano94a, Ano94b, Ano94c, Ano94d, Ano94e, Ano94f, Ano94g, Ano94h, Ano95a, Ano95b, Ano95c, Ano95d, Ano95e, Ano95f, Ano95g, Ano95h, Ano96a, Ano96b, Ano96c, Ano96d, Ano96e, Ano96f, Ano96g, Ano96h, Ano97a, Ano97b, Ano97c, Ano97d, Ano97g, Ano97h, Ano97i, Ano97j, Ano98a, Ano98b, Ano98c, Ano98d, Ano98f, Ano98g, Ano98h, Ano98i, Ano99a, Ano99b, Ano99c, Ano99d, Ano99g, Ano99h, Ano99i, Ano99j]. **Matusita** [Zie90v]. **Mauch** [Mil94]. **Maura** [Zie98v]. **Maurice** [Boo92]. **Max** [Bry92, Kan95]. **Maximal** [Zha94]. **Maximum** [Gri93, KY91]. **Maxwell** [Pat91]. **McBride** [Mor92]. **McCabe** [Arn90, Zie94y]. **McClave** [Zie95-28]. **McClelland** [Vin92]. **McConway** [Zie95a]. **McCuen** [Bry99]. **McCullagh** [Sch92d]. **McCulloch** [Zie98l, Gho93]. **McElrath** [Bod97]. **McGill** [Buc90]. **McKean** [Mi99]. **McLachan** [Raz91]. **McLachlan** [Kus98, Ray93]. **MCMC** [Zie99j]. **McNeese** [Arm93]. **McNeil** [Zin93]. **McNulty** [Huz95]. **McPherson** [Gib91]. **McReynolds** [Zie95-35]. **MDF** [DPL+94]. **Mead** [Der90]. **Mean** [BBT90, Bor97c, Gan95, NLB+98, VM91, Yas95]. **Means** [CC99, Nel93, Tsa91, WN97]. **Mears** [Bre96]. **Measure** [JD92]. **Measured** [SW95]. **Measurement**

[Bri91, BHS90, CGG92, RL95, San98, Sch94b, TI99, Tim96, WI94, Zie97i, Zie98-43, LeP90a, Arm97, Gle96, Kah94, Sea91, Sea94, Zie93r]. **Measurement-Error-Model** [CGG92]. **Measurement-Methods** [TI99]. **Measurements** [Oma91, TW96, WL97, Kia94, Roz93, Sha97c]. **Measures** [Li97, LN96, LM93, Lin92, Zie93b]. **Measuring** [CB93, DGTZ97a, DGTZ97b, Hul97, Peñ91, PE97, WH97, McC98, Zie95w, Zie97s, Zie98-31]. **Mechanics** [Zie94-44]. **Mechanized** [Van91]. **Medhi** [Ked96]. **Medical** [Zie93-28, Zie95x, Zie98r]. **Meeden** [Ruk98]. **Meeker** [Nel98, Jon93]. **Meier** [Hil95]. **Meloun** [LaL95]. **Melvin** [Rao98, Zie98-46]. **Memory** [Glo97]. **Menard** [Zie96c]. **Mendenhall** [Zie94-40, Arm92, Lee94]. **Menzefricke** [Zie96-52]. **Messy** [vT91]. **Meta** [Len93]. **Meta-Analysis** [Len93]. **Metcalfe** [Lar95]. **Meteorology** [CC95, Zie98g]. **Method** [Bre91b, Fri91, GD91, Gu91, HT91, Len93, STC99, WC92, Zie98q, Bre91a, Goo95, Pie90b]. **Methodology** [Gun96a, LeP90b, SE93, Sto92, Zie91r, Zie94-45, Zie90-28, Pro92a, Sea93]. **Methods** [Alt96, Arm93, Bar91, Beg90, Ber96a, Boo94a, Bre90, Bro90b, Bru92a, Bru93b, Bzi97, CHB90, Cha93, Che91, Chi91, Coh92, CR96, Coo96b, CDKS92, Edg98, Fai94, Got94a, Gri97a, Gri98, Gro99, Hab90, HW90b, HW90a, HL95, Han97, Hes91, Hil95, Hir90, HS97, Jac95, Jai95, Kah94, KLR91, KMP95, Kat91, KY91, KM99, Lam90, LSBW95b, LSBW95a, LN95, LeP90a, Lee93, Len90, Len95, Mil99, Mil98, Mor93b, Nai90b, Nel98, Nem97, Nik93, Nik95, OM96a, OM96b, Pol93, Pro90, Pro92b, Ram96, Rie97, Ruk97a, Ruk98, Sch94b, Sha93, STW91, Sin97, Spa99, SN95, Spe91, Spe96b, Str96, Stu94, Swe96, TI99, Tho90b, Tuc96, Van92b, Wal92b, War90, Wyc96, YDB90, Yan97, Zie90z, Zie91p, Zie92d, Zie92m, Zie93-28, Zie93-29, Zie93-27, Zie94f, Zie95-31, Zie95-38]. **Methods** [Zie95-37, Zie96e, Zie96-27, Zie96-29, Zie98-36, Zie99p, Zie99g, dC99, Acr97, Ang91a, Bla92, Boo93, Cal94, Che92, Chr97, Chu91, Gas94, Gov92, Gra98, Har91b, Jon91b, Kat98, Kia93b, Law96, Lor99, Mi99, Min93, Osb97, Rig92a, Rig93, Van96b, Won94, Zie91l, Zie92v, Zie95-27, Zie96j, Zie96g, Zie97-35, Zie97z, Zie98-35, Zie99u, Dea97, Mat96, McC94]. **Metric** [CC95]. **Metterick** [Pan96]. **Meyers** [Zie99-30, Zie99-30]. **Michael** [Beg90, Bel95, Jol96, Ord96, Rag91, Wha95, Zie90j, Zie91q, Zie92b, Zie96m, Zie98-48]. **Michel** [Dow95, Not92b, Ord96]. **Michele** [LaL95, Rie94a]. **Michie** [Ful95]. **Michotte** [Mac90a]. **Mick** [Zie99v]. **Micro** [Spr91]. **Microcomputer** [Sar94b]. **Microelectronics** [Sam99a]. **Microsoft** [Zie96m, Zie97j]. **Microsoft(R)** [Zie99i]. **Middleton** [Zie96m]. **Mieczkowski** [Zie99-51]. **Mikel** [Cab94]. **Mikhail** [Kin97]. **Mikulak** [Bel95]. **Milan** [LaL95]. **Milík** [Gri97a]. **Militky** [LaL95]. **Millard** [Zie99m]. **Miller** [Wyc96, Zie90-27, Zie93-35, Zie95-50, Zie96-52, Bro90b, Bru97, Sch92a, Wyc96]. **Milliken** [Zie97-27, vT91]. **Million** [Gri90]. **Milton** [Wol92, Kia92a]. **Mine** [BH93]. **Mine-Product** [BH93]. **Mineral** [Ott90]. **Minimal** [Jac92, Jac93]. **Minimizing** [Cro92]. **Minimum** [BS99, HCV98, RvD99, SCF97]. **Minimum-Aberration** [BS99, HCV98]. **Mining** [Van91, Zie98c]. **MINITAB** [Wit94, Zie90-27, Tho90b, Zie98i, Gun90]. **Minja** [Zel94].

Mirkin [Hig98]. **Miron** [Zie96-45]. **Misclassified** [HR92, HR94]. **Missing** [HLS98, Kia95b]. **Mitchell** [Pla96]. **Mitra** [Sen94a, Bem96]. **Mittag** [Jai95]. **Mixed**
[BNC87, BL97, CPJ92, KM94, Ngu96b, Ste99, WW92, WL97, Zie97-27]. **Mixed-Effects** [WL97]. **Mixed-Model** [BNC87]. **Mixture**
[CR98, CDKS92, DPL$^+$93, DPL$^+$94, Hes95, SC93, WL91, Zie92i, Raz91]. **Mixtures** [Czi92]. **Mockus** [Mar99]. **Modal** [Cox93]. **Modarres** [Geo94]. **Mode** [Sch96b]. **Model** [Ann99, Ano99f, BNC87, Bor97c, CGG92, CR98, CDKS92, Cro92, DJ94, JFM99, KK99, LT96, Len95, ML95, PM99, PJ90, Pie90a, RN91, RL95, STC99, Sen98, SS97, TW92, Van92b, Vin92, WL97, WJ92, Zie90p, Sen99b, Sch91b, Iye90, Rig99, Wha95, Zie90o]. **Model-Comparison** [Vin92]. **Model-Free** [Wha95]. **Model-Independent** [STC99]. **Model-Oriented** [Rig99, Zie90o]. **Modeling**
[Alt99, Bax96a, Bay92, CH96b, CDKS92, Dea94, EH96, Fot96, Gro96, Kir93, Liu99, MEL98, NLB$^+$98, Pig91, Zie92p, Zie95-29, Zie96-44, Zie97-29, Zie98-39, Fre94, Gru97, Hec96, Huz95, Zie97g, Zie98f, All96]. **Modelling**
[Bul96, Glo95, Moo91, Por97a, Zie90-27, Zie96a, Zie90n, Zie92s, Zie93-30, Zie94e, Zie95-50, Zie96-40, Zie97b, Owe96, Tho93, Zie95x, Zie99t]. **Models**
[Ano98e, Atk96, BT89, BA96, Boo90, Bor97c, Cal94, Cal98, CPJ92, Dea95, Dob96, DH92, DP97, EMS98, Gal92, Gil92, Gla98, Gol98, Goo91, Gra98, Gue90, Gun94a, Gut90, Har91c, Hes93, HL97, Hof95, Iye98, Jol97, JR91, KM94, Khu92, Kle94, Law96, LLP$^+$99, LN96, Mad96, MSH94, Mee91b, Nip92, Ott90, Ped98, Peñ91, Qiu95, Rig93, Roe91, Sch92b, Ste99, TC90, Tim96, Tor99, Van96a, Van96b, Zel94, Zie91j, Zie94-39, Zie95-33, Zie95-39, Zie97r, Zie98-27, Zie98n, Zie98-28, Zie99-46, Zie99e, vT95, BT98, Zie97-44, Arm97, Bab98, Bor95b, Bry92, Cab98, Che98, Dea91, Dea96, Dea97, Dow95, Emp92, Emp93, Ens95, Fox97, Gal95, Glo95, Hab92, Iye90, KB94, Kia90, Kia92a, Kim91, Ord96, Raz91, Sch92d, Sch94b, Sen99a, Wel90, Wes92, Win93, Zie90a]. **Models** [Zie91i, Zie92b, Zie92n, Zie93o, Zie96u, Zie97-27, Zie97e, Zie97-42, Zie97-44, Zie98-29, Zie99s, Zie99-51, dV92, Kia94]. **Modern**
[Bal93, Coa94, Dun97, Rig92a, Was91, Zie91d, Zie95-50, Ada94, Ajm99, Dre91, Fre99, Jam96, Joh91, Law92, Osb97]. **Modification** [DJ94]. **Moen** [Cha92]. **Moeschberger** [Rao98]. **Mohan** [Bil91]. **Molchanov** [Zie99-46]. **Molenberghs** [Ste99]. **Money** [Spo90]. **Monfort** [Cab98]. **Monitoring**
[BK92a, BK92b, DP91, Fal99, Gan95, GSH98, HNF97, Mac92, NW93, NM95, Tuc92, VV92, Van96a, WG92, Yas94, Zie95-37]. **Monotone** [Rag95]. **Monson** [Gru97]. **Monte**
[Gas97, Nik93, Zie96-27, Zie98-36, Was97, Zie96-27, Zie98-32]. **Montgomery** [Ale95, Por93, Zha92, Zie99l, GR97, Gun96a, Nar93, Sau92, Sri92, Zie92r, Zie96-37]. **Mooney** [Zie94j, Zie98-32]. **Moore** [Arn90, Zie94y, Moo96]. **Moran** [Pit92]. **Morgan** [Zie95-47, Cra94, Zie92d, Zie93d, Zie94s, Zie97-33]. **Morgenthaler** [Zie94-29]. **Morris** [Aba98, Kot92, Sea94]. **Morton** [Dav99]. **Moser** [Bor97c]. **Moskowitz** [YWMP95]. **Mosteller**
[Sch93c, Sch93b, Zie90w]. **Motiska** [Zie93-34]. **Motor** [MSF95]. **Mottley**

[Zie94-33]. **Moubray** [Zie96-35]. **Moura** [Hul92]. **Moving** [Bax90, DP91, FHT90, Gan95, Hun90b, LWCR92, LS90b, LS90c, MH90, Van96a, WM90]. **Mowery** [Zie96k]. **MR0702171** [Sin92]. **MR0887702** [Ste90b]. **MR1007294** [BT98]. **Mueller** [Zie97b]. **Muller** [Pri98, Eub90, Zie99-27]. **Multi** [Pap95, Yin91]. **Multi-Armed** [Yin91]. **Multi-Vari** [Pap95]. **Multidimensional** [Jol96]. **Multifactor** [Fed96, JD96, KTTS90, MSB96a, MSB96b, Tob96]. **Multinomial** [HR92, HR94]. **Multiple** [Ale98, BB95, Cha93, CB93, Hir96, Jol93, MME98, PF91, RH92, SE93, SC93, Tam96, Tür94, USM99, Zie94x, Zie95-43, Chr97, Zie94-27]. **Multiple-Group** [Hir96]. **Multiple-Outlier-Detection** [PF91]. **Multistage** [MB98]. **Multitaper** [Cox96]. **Multivariable** [Zie92e]. **Multivariate** [Ano91f, Boy96, Bre91b, Chu91, Fri91, FB94, Goo91, Goo92a, Gu91, HL95, HT91, Haw91b, Hec99, HS97, Ize91, Kia92b, Kia93b, KM99, Lal99, LLP$^+$99, Lin90, Loh92, LWCR92, Mar97, Mat96, Mat98, Nai94, Nip92, NM95, Not92b, Pfa99, Pos98, Tho91, Tho92a, Tim95, Ver90, WL91, Wol96, Zie95b, Zie96d, Zie97h, Zie97l, Zie99c, Zie99-51, Bre91a, Boo98, Bur91, Glo95, Gra90, Hag91, Haw90, Iye98, Ize90, Mas99, Mat97, Mye96, Nem95, Nem97, Ord96, Ram93, Sha95, Sha97c, Tim99, Zie91k]. **Multiway** [Zie92k]. **Muni** [Chi91]. **Murray** [Moo91]. **Murtha** [Zie96n]. **Myers** [Gun96a, Kia92a, Rob90, Zie91d, Zie94-31]. **Myles** [Zie99u].

N [Ber96b, Fam95, Far93, Glo93, Gri99, Hwa92, Jam96, Kat91, Kir92, Kir93, Kus93, Mac90a, Pos98, Rie94b, Run90, Sai96, Sar93, Sin97, Weh95, Whe93, Wu99, Zie90m, Zie90h, Zie90d, Zie90n, Zie92g, Zie92s, Zie93-30, Zie93r, Zie94w, Zie94-45, Zie94s, Zie94-38, Zie94-33, Zie95n, Zie96-34, Zie96h, Zie96k, Zie97r, Zie98-43, Zie98d, Zie98e, Zie98u, Zie99i]. **Nachtsheim** [Zie97-44, LC90]. **Naes** [Zie95y, Hag91]. **Nagaraja** [Far93]. **Naik** [Zie96d]. **Name** [Gre94]. **Nancy** [Coo96b, Zie95-45]. **Narahari** [Kir93]. **Narayan** [Mat97]. **Narrative** [Baj98]. **National** [Sri93, Zie96-46]. **Natural** [Lyn97b]. **Nature** [Sai96]. **Naumann** [Zie97i]. **Nazem** [Elt90]. **Neapolitan** [Jon92]. **Near** [Ngu96b, Zie95y]. **Near-Orthogonal** [Ngu96b]. **Nearly** [WW92]. **Neave** [Ste90c, Pfa92]. **Needed** [Sne90]. **Neely** [Zie98y]. **Neil** [Zie99-51]. **Nelder** [Sch92d]. **Nelson** [Mee91b]. **Nenadic** [Zie94g]. **Nested** [LBB96, SS97]. **Nesting** [SS97]. **Neter** [Kia90, Zie92b, Zie97-44]. **Nets** [Ter92]. **Network** [Bax96a, BCL98a, BCL98b, Rob98, Sch98a]. **Networks** [NO96, Ste96a, Ste96b, Zie95-49, dVU96, DSSU98, Zie95-49, Ful97, Yak97, Zie96-49, Zie94-28]. **Neufelder** [Soy95]. **Neural** [Ful95, Ful97, NO96, Sim97, Ste96a, Ste96b, Zie95-49, Zie96-49, dVU96, DSSU98, Zie95-49]. **Neutrinos** [MJ91]. **Neville** [Pan96]. **Nevison** [Zie90u]. **New-Better-Than-Used** [CR93]. **Newbury** [Zie93x]. **News** [Woo91]. **Next** [HH96, Zie96r]. **Ng** [Loh92]. **Nicholas** [Ada94, Che92, Gal95]. **Nicholls** [Zie90-28]. **Nick** [Dri91]. **Nickolaj** [Gri99]. **Nickulin** [Kin97]. **Nicolas** [SN95]. **Niederreiter** [Zie96-27]. **Niels** [Kle94]. **Nielsen** [Har91c, Zie97-42]. **Nielson** [Zie94-28].

Niewiadomska [Cha98]. **Niewiadomska-Bugaj** [Cha98]. **Nigel** [Sch96c]. **Nikiforov** [Rie94a]. **NIR** [Zie95y]. **No** [Gre94, BT98, DPL$^+$94, HR94, Lin95a, Sen99b, Sin92, Ste90b, Bog92]. **No-Name** [Gre94]. **Noel** [Zie94-41, dV93]. **Noether** [Far92]. **Noisy** [Bre91b, Fri91, Gu91, HT91, Zie93f, Bre91a]. **Nolan** [Cha92, Car96]. **Non** [Cam96, Tsa91]. **Non-Linear** [Cam96]. **Non-Standard** [Tsa91]. **Nonconformance** [GS92]. **Nonconstant** [MM94]. **Nondestructive** [Ber96a, CR96, OM96a, OM96b, Spe96b, Swe96, Tuc96]. **None** [VV94]. **Nonlinear** [Arm97, Bor97b, Iye90, Kaf94, Zie91i, DSSU98, Ber91, Goo92a, KB94, Kus92, Mil90, San92, Spo90, Taa91, Tim96, Zie91l]. **Nonlinearity** [CS92]. **Nonnegative** [Bre95a, KM94]. **Nonnormal** [Bas97]. **Nonparametric** [CM99, DM99a, DM99b, ET96, Eub93, Far92, Gas94, Gib99, Gil99, HC91, HLS98, Mi99, QY98, Sch91c, Van99, Wol95, Woz91, Zie90a, Zie94j, Zie99-27, GJMS$^+$95, Ale99, Eub90, Gro99, Qiu95, Zie93s, Zie99u]. **Nonprobabilistic** [Per92]. **Nonquadratic** [Har92b]. **Nonreplicated** [vT91]. **Nonresponse** [Zie99v]. **Nonsampling** [Zie93t]. **Nonsense** [Das93]. **Nonstandard** [BC95, HD95, PD95, RD95a, RD95b, SWG95, SP95]. **Nonstationary** [Luc98]. **Nonsymmetric** [Har92b]. **Noreen** [Len90]. **Norm** [Spo90]. **Norma** [Zie99l]. **Normal** [Ber97, Ize91, KM99, Mee90b, WN97, Ode90]. **Normality** [Col92]. **Normally** [Mee90a, WJ92]. **Norman** [Ber96b, Bru94, Car93, Cha95, Fam95, Gun99, Pos98, Zie91p, Zie98q, Zie98e, Zie98k, Zie98z]. **Normand** [San99]. **Norton** [Zie98-45]. **Note** [Bis94, Jac92, KSJ96, Ngu96b, Rag98]. **Notes** [Har91c, Ste99]. **Nozer** [Zie98l]. **NU** [MQ91]. **Nuclear** [Beg90, Dow94, GD94, Got94c, Got94b, Jou94, MKA96, MPR99, Rut94, Tor94, War90, WB94]. **Nuclear-Power-Plant** [MKA96]. **Nuclear-Waste-Site** [Dow94, GD94, Got94c, Got94b, Jou94, Rut94, Tor94, WB94]. **Number** [Nel95, Str96]. **Number-Theoretic** [Str96]. **Numbers** [Woo91]. **Numerical** [Hal95, Rie97, SN95, Wat96, Zie99w]. **Nychka** [Zie99f].

O [Bax92, Pla96, Rag93, Rie97, Sin90a, Zie91l, Zie94-28, Zie97-42, Zie98g, Zie99d, vN90]. **Object** [Amm92, Zie99-31]. **Object-Based** [Zie99-31]. **Object-Oriented** [Amm92]. **O'Brien** [Sch94b]. **Observational** [All96, Gal92, Zie96b, Zie96-28]. **Observations** [Yas93, Ode90]. **Observed** [Sti97]. **Observing** [Ber92a]. **Ocean** [Zie96-38]. **Ochi** [Rag91]. **O'Connell** [Zie91j, Zie94t]. **O'Connor** [Hey92]. **Odds** [Zie99x]. **Odeh** [Emp93, Gri90]. **Off** [KD97]. **Off-Line** [KD97]. **O'Hagan** [Cam98, LeP90a]. **Oldford** [Zie95-33]. **Ole** [Har91c]. **Oliver** [Ter92, Coh92]. **Olkin** [Dob96]. **Olson** [Bel95, Zie98-46]. **Omachonu** [Zie99-29]. **Omnibus** [DP91]. **On-Line** [NW93]. **One** [CWWR97, MQ91, Oeh94, RH95, Van92b, Wan94]. **One-** [CWWR97]. **One-Cell** [Oeh94]. **One-Sided** [Van92b]. **One-Way** [Van92b]. **O'Neill** [Zie94q]. **Open** [Jon90, Jon91b]. **Opening** [Bel95]. **Operating** [EMSD91]. **Operation** [Van91, Zie98q]. **Operational** [Kat98]. **Operations**

[HA93, LeP90b, Spr91]. **Operators** [McC90, Owe91]. **Opinions** [Sam90]. **Oppenheim** [Bre90, Zie95-31, Bre90, Zie95-31, Zie97-43]. **Opportunities** [Sri93]. **Optical** [WVYB97]. **Optical-Fiber** [WVYB97]. **Optics** [MA92]. **Optimal** [Bak98, DJ94, Har92b, JV93, MN95, Ngu94, Rag98, RJ97, Spu92, SWC97, Tür94, Bor94, Zie90q]. **Optimality** [Ney94]. **Optimally** [AD96]. **Optimization** [Ano97f, Ano97e, Emp97, Goo95, Gun96a, Hof95, Mar99, O'D99, Zie96-30, Fot95, Lew93, Zie99y]. **Optimizing** [Ott90, Sto92]. **Optimum** [AB97, MM94, Whe93]. **Orav** [LeP90b]. **Ord** [Boo92]. **Order** [Ang90b, AB97, BA96, Far93, Fre95, Lin93a, Lin95a, Sho90]. **Ordered** [CH96a, KTTS90]. **Ordinal** [vT95]. **Ordinary** [ZZ91]. **Ordination** [Sha95]. **Organic** [Ano97f, Ano97e, Emp97]. **Organization** [Zie98-47]. **Organizational** [Zie99q]. **Oriented** [Amm92, Ste99, Rig99, Zie90o]. **Ørnulf** [Kle94]. **Orr** [Sau97]. **Orthogonal** [CL93, DPL$^+$93, HS99, Hol98, Jac92, Jac93, LIV96, Mor98a, Ngu96b, WW92, DPL$^+$94]. **Orthogonality** [Hag96]. **Oscar** [Tom95]. **Ostle** [Bod97, Zie90x]. **Ostrowski** [Zie95a]. **Other** [Col92, Ped98, RJ97, Yas92]. **Ott** [Arm92, Ram91, Ham96, Koo90, Zie94f, Zie99-41]. **Outgoing** [BHS90, MT91]. **Outlier** [CWWR97, PF91]. **Outliers** [Cro94, Bre95b]. **Outlying** [Ano90e, Sim88]. **Output** [STC99]. **Overdetermined** [Bro92]. **Owen** [Gri90, Smi91, Woo92]. **Ozone** [GK93].

P [Arn90, Bas97, Bur91, Cha92, Dun90, Gal93, Had92, Hwa92, Ked98, Lam90, LeP90b, LuV90, Mi99, Not92a, Not92c, Osb97, Pit92, Pro93a, Qiu95, Rao98, Ruk97a, Rus94, Sac93, Sch92d, Sin90b, Sin97, Ste90c, Tho90a, Tim99, Wal92b, War90, Yan96, Yeh93, Zie90-28, Zie90a, Zie90k, Zie91k, Zie92d, Zie92c, Zie92v, Zie92m, Zie92n, Zie93e, Zie93r, Zie93g, Zie93-34, Zie94u, Zie94k, Zie94-36, Zie94-34, Zie95-33, Zie95g, Zie95-42, Zie95d, Zie95n, Zie95-50, Zie96e, Zie96-27, Zie96k, Zie96-52, Zie96g, Zie97j, Zie97n, Zie98h, Zie98-43, Zie98w, Zie99-27, Zie99v, Zie99j, Zie99n, Zie99m, dC99]. **Padhraic** [Zie98c]. **Pagano** [Zie94-30]. **Pahkinen** [Zie96-29]. **Pairwise** [LW97]. **Pamela** [Zie99-52]. **Panchapakesan** [Zie98d]. **Pandit** [Cox93]. **Panel** [NAM$^+$92, Zie90-28]. **Panizzon** [God95]. **Panju** [Zie98-29]. **Pankrantz** [Win93]. **Pannatier** [Zie96-50]. **Pantula** [Zie99d]. **Papers** [Zie99-36]. **Papoulis** [Gro92]. **Paradigm** [Glo99]. **Parameter** [Gru90, HL97, KGK90, MM94, MW98, NAM$^+$92, Won92, Kim91]. **Parameters** [AKO94, Gri97b, Kun93, Sin83, VB94b, Sin92]. **Parametric** [Har91c, Sha98]. **Pareto** [Gri93]. **Park** [Tan98, Zie93x]. **Parker** [Zie91g]. **Parmar** [Zie97-37]. **Parsowith** [Zie96q]. **Part** [AHT91, Sha97c, Zie98w]. **Partial** [Bay92, Coo93, Mar96, Zie96-47]. **Partially** [Jac93]. **Partnership** [Sne90]. **Parts** [Bru97, Zie93k, Gri90]. **Parzen** [Zie99-36]. **Pass** [Zie96-36]. **Paszek** [Mor93b]. **Patel** [Ber97]. **Path** [Bay92, Hal94]. **Patil** [Zie96p]. **Patrick** [Hag96, Hey92, Zie98-40, Zie99-43, Zie99i]. **Pattern** [Boo99, Nem95, Ray93, Ful97, Sim97]. **Patterns** [FL97]. **Paul** [Gat96, Mat98, Rag95, Tho92b, Van92a, Zie96-28, Zie97-38, Zie99q, HSPF92].

Pavlovic [Van91]. **Pazman** [KB94]. **PC** [LaL95, Cam90, Dun90]. **PC-Aided** [LaL95]. **Peace** [Stu94, Zie91r]. **Peacock** [Zie94-38]. **Peak** [HT92]. **Peak-Preserving** [HT92]. **Peck** [Zie99-37, Por93]. **Pegg** [Gri99]. **Pell** [Tob99]. **Pellets** [Tho94]. **Pelosi** [Zie99k]. **Penalty** [Qiu95]. **Graph** [Zie96-45, Zie96-33]. **Japan** [Zie95-29]. **or** [CR91]. **Parallel** [MW90]. **Physical** [Box90, God90, Hah90, HK90, Hoo90, Hun90a, Mac90b, Moo90, Tri90, Wan90]. **Process** [Sto92]. **Peppen** [Bar92b]. **Percival** [Cox96]. **Perez** [Pap95, Sto92]. **Perez-Wilson** [Pap95, Sto92]. **Perform** [Bru96, Sto96]. **Performance** [Dow94, GD94, Got94c, Got94b, Jou94, Luc98, Rut94, Tor94, WB94, Yas93, Kir93]. **Periodic** [Tat96]. **Permutation** [LN97, Nik95]. **Perry** [Jen91]. **Personal** [Bon95, Hal94]. **Personalities** [Zie98z]. **Perspective** [Bon95, Lor93, Zie98-30]. **Persson** [Kel97]. **Persuasive** [Lit91]. **Pete** [Dri91]. **Peter** [Ber92b, Bla92, Bre96, Bru93b, Bur91, Cha93, Cro99, Dri91, Gas94, Hal95, Hil95, Koh90, Mil94, Ram94, Rig99, Sea90, Sha97b, Tso92, Wit94, Yeh93, Zie94b, Zie95-35, Zie97-30, Zie98j, Zie98l, Zie99-38, Zie99-47, Zie99t]. **Petroleum** [Zie90j, Zie99-43]. **Pfeiffer** [Van92a]. **Phadke** [Men91]. **Pharmaceutical** [Zie91r, Zie96-39]. **Pharmacochemistry** [Yeh93]. **Pharmacology** [Tho90a]. **Phase** [HH96]. **Phenomena** [Lin99]. **Phil** [Ko95b]. **Philip** [Gle96, Gri99, Nik95]. **Phillip** [Zie97-39]. **Phillips** [Rag93, Bul91, Dom90, Han97, Job99]. **Philosophy** [Bru97]. **Photographic** [VD94]. **Photoresist** [CR98]. **Photoresist-Coating** [CR98]. **Physical** [Cox96, Hes91, Jen90, Rag91, Sha97a, Wal92a, Zie93c, Zie95-38]. **Physicists** [McC94]. **Physics** [Gal93]. **Piatetski** [Zie98c]. **Piatetski-Shapiro** [Zie98c]. **Piegorsch** [Zie98-42, Zie99f]. **Piepel** [Ano90g]. **Pierre** [Bil94, Zie95z, Bil92, Zie95z]. **Piersol** [Nan94]. **Pierson** [Zie93w]. **Pieters** [Zie90w]. **Pinyuen** [Joh91]. **Pisani** [Loh94]. **Pitard** [Zie95z, Bil92]. **Pitman** [Zie94-32]. **Pitt** [Hal94]. **Plackett** [LD92]. **Plan** [BHS90]. **Planned** [Cha92]. **Planning** [CM93b, CM93a, EM95, Gun93, HO93, Hah93, LST93, Pri98, WC92, Zie97w]. **Plans** [EMSD91, God95, Jac92, Jac93, MT91, Mee91b, Mor91, MT92, Rag98, RM95]. **Plant** [MKA96, Zie95t]. **Plante** [YWMP95]. **Plants** [MPR99]. **Platen** [Hal95]. **Pleasures** [Lei97]. **Plot** [BS99, HCV98, Mil97]. **Plots** [Ber98, Coo93, Coo96a, GK90]. **PLS** [Wol93]. **PLUS** [Han98, Jam96, Zie98-46, Ko95b, Ko95a, Zie99m]. **Pocket** [Aba98]. **Point** [CCC90, LT96, Zie99-49, Boo90]. **Point-Process** [LT96]. **Poisson** [LuV90, CS93, Lam92, Li97, LLP$^+$99, Boo95]. **Policies** [VV94]. **Poling** [Bel99, Zie96k]. **Polyak** [Mi97]. **Polymerization** [CFRH99]. **Polynomial** [MSH94, QY98, RWHH97]. **Pooling** [GS94, RH92]. **Population** [KM99, Ruk98, Zie93j]. **Populations** [Mee90b, Sin83, WN97, Zie92m, Sin92]. **Posterior** [Atk96]. **Power** [Ada96, Bak96, MKA96, MPR99, Per97, Zie95c]. **PQ** [Zie99-50]. **Practical** [Aba98, Bel95, Der90, Dun96, Gri99, Haw90, Lar95, Nik95, Tob99, Bay95,

Bli91, Goi96, Gre98, Gun96b, Han97, Hey92, Jen90, Jen92, McL95, Mor99b, San99, Zie95-27, Zie96-29, Zie97t, Zie98-33, Zie99-27, Zie99z, Zie99-28]. **Practice** [Arn90, Bru97, Dog99, Moo96, Ram93, Sam99b, Ste99, Wol93, Zie94y, Zie98e, Bil92, Col93, Gas97, Lei92, Lyn94, Sha93, Zie95z]. **Practices** [Sha92]. **Practitioners** [Kra92, Jon93]. **Prat** [Zie98-34]. **Pravin** [Pet99]. **Pre** [Pap95]. **Pre-Experimentation** [Pap95]. **Precision** [CB93]. **Predicting** [GJMS+95, WBS+92]. **Prediction** [CR91, CM99, DM99a, DM99b, EM99, Gib99, Gil99, KLR91, LN96, MMY93, Roe91, Sch92b, Van99, VM91, Zie95t, DSSU98, vdVtBM97, Bor95a, Ode90]. **prediction-variance** [Bor95a]. **Predictions** [TC90]. **Predictive** [Law95]. **Predictors** [ZZ91]. **Preliminary** [Mor91]. **Prem** [Zie93m]. **Prescott** [SDP+95]. **Prescriptions** [Eas90]. **Presence** [Bri96, Cre97, FRY96, GS95, JV93, WI94]. **Presenting** [Lit91]. **Preserving** [HT92, JS99]. **Press** [Gue90]. **Prevention** [Bru91]. **Price** [Ada91, Maz93]. **Priestly** [Zie98g]. **Primary** [Wal92b]. **Primer** [Ada92, Car90a, Rab92, Ram99, Rea93, Mil98, Nem97, Zie94b]. **Principal** [Lei93]. **Principle** [Wol95]. **Principles** [Boo93, Der90, Gue90, Han93, McC94, Min93, Sha92, Zie97b, Zie99-47, Zie93-33, Gol90, Job99, Lin90, Mil91, Oli97, Zie90r, Zie94-30, Zie99-29]. **Prior** [ST90a]. **Priscilla** [Kin97]. **Probabilistic** [LSBW95b, LSBW95a, Law96, Lyn95, Zie94-28, Zie98b, Jon92, Pap96]. **Probabilities** [Atk96]. **Probability** [Ale95, Bab98, GK90, Gun94a, Gut92, Hag90, Huz95, Joh91, Jon91a, MT91, Rag91, Rig93, SGW96, Taa99, Tho99, USM99, Wol92, Zad95, Zie91k, Zie92a, Zie96u, Jon90, Lei97, Rab92, Zie95-42, Zie98a, Bax92, Bru93a, Bry99, Cha98, Dob96, Gal93, Gro92, LeP90a, Lei91, MA92, Nar93, Rob90, Van92a, Wal92a, Was91, Zie90s, Zie91m, Zie92l, Zie94-31, Zie94-32, Zie95-28, Zie96-30, Zie99-30]. **Problem** [Bog92, Bru95, Fri97, HP97, Hey93, MA92, Mor92, MS95, Pit92, Pro93a, ST90a, Zie97a, Don90, Zie96-31]. **Problem-Solving** [Pit92]. **Problems** [CR98]. **Procedural** [Bla92]. **Procedure** [Mee90a, PF91]. **Procedures** [NW93, RH92, ST90a]. **Proceedings** [Bro90b, Zie95-29, Zie98-34]. **Process** [Acr97, Ada93, Ada96, Arm93, Bak96, Boo90, BL97, BK92a, BK92b, Boy96, Cab94, CFRH99, CS93, Col93, DP91, Edg98, FB94, Gan95, Gan97, Gho94, God95, Gri98, GSH98, Gun96a, Hal94, JV93, Kal93, Kra90, LT96, Lew92, Mac92, McC98, McG94, McL95, MS95, O'D99, OUH93, Pan96, Run90, SG99, Tat97, Tuc92, TFV93, VTFD92, VV92, Vuk98, WG92, Yas95, Zha98, Zie92r, Zie93-38, Zie94r, Zie94-34, Zie96-37, Zie96-41, Zie96f, Zie97-31, Zie98q, Zie98-43, Zie98-40, Zie99-33, Bri91, Kle94, Zie99a, Cha95, Dog93, Han93, Pla90, Ram91, Zie97u, Zie97v]. **Processes** [AWS94, Bax95, DH92, Fel94, HNF97, Kir92, Lei91, Luc94, MB98, NM95, Rag91, Rag93, Sen97, Van96a, WMP94a, WMP94b, Wes90, ZP94, Boo95, Fre93, Fre97, Glo97, Ked96, Ked98, Koe92, Kra92, Pit92, Sea90, SN95, Sto92, Weh91, Wen93, Zie93f, Zie94-44, Zie97k]. **Processing** [Gru97, Rie94b, Sen95, Rie97, Sen94a]. **Producibility** [Cab94]. **Product**

[AAK99, Alt96, BH93, Gun96a, Nel95, Zie92i]. **Production** [Cro92, Sch95, She90b]. **Productivity** [Hal98, Pro90, Zie96-52]. **Products** [Bis97, Zie95k]. **Profession** [Sne98]. **Professional** [Gun96b]. **Profile** [FB94, Len93]. **Profit** [Zie94-33]. **Profitability** [HH96]. **Programming** [Bro90a, LaL92, RM95, Zie96-36, Zie98h, Bax95, Bat99, Zie99-31]. **Progressively** [VB94b]. **Project** [Zie99-28]. **Projection** [LD92]. **Proof** [SW95, USM99]. **Proof-Loading** [SW95]. **Propagation** [HA93]. **Proper** [Wil90a]. **Properties** [Bax90, FHT90, Hun90b, LD92, LuV90, LS90b, LS90c, LG99, MH90, Ste87, WM90, Bor95a, Ste90b, Sin90a]. **Proportional** [TWN98]. **Proportional-Integral** [TWN98]. **Proschan** [Cly94]. **Prototype** [BS97]. **Prove** [Zie99-32]. **Provost** [Cha92]. **Proximity** [Lee99]. **Pruett** [Zie94r]. **Pukelsheim** [Bor94]. **Purves** [Loh94]. **Puterman** [Bax95]. **Puzey** [Aba98]. **Pyzdek** [Zie93v, Car90b, Car92, Hea94, Spe96a, Wan94, Hea94, Wan94].

Q [Deh90, Jon93, Nel98, Sam99b]. **QFD** [Coo96b]. **QSAR** [Bur91]. **Quadratic** [CCC90, MT92, Spu93]. **Qualimetrics** [Zie98w]. **Quality** [Aba98, Ada92, Ada94, Ano91f, AHT91, Bel95, Bem96, Bos92, Bru93b, BHS90, Car90b, Car93, Cha92, Die92, Dun96, Dun97, Edg92, Fre99, Fri97, Gan97, GR97, Gho94, Gri90, HH96, Haw91b, Hoc94, Jai95, KD97, Kal98, Kin93, Lam90, LC94, Lew92, Mar94, Mas99, McG94, McL95, MT91, Mil91, Mil94, NW93, O'D97, Oli98, Pan96, Pla90, Pro90, Pro92b, Pro92a, Ram91, Rea93, Rol93, Ros96, Sac93, Sar94b, Sau92, Sea94, Spa99, Tan98, Tor99, WVYB97, Won98, Wyc96, Zei94, Zie90l, Zie90t, Zie91p, Zie92w, Zie93l, Zie93-37, Zie93q, Zie93-36, Zie93-35, Zie94-44, Zie94-43, Zie95-45, Zie96o, Zie96q, Zie96-52, Zie96-46, Zie97-39, Zie97-32, Zie97o, Zie97a, Zie99-50, Zie99o, Zie99y, Zie99n, dC99, Zie99-33, Bre90, Car92, Lew93, Neu99, Smi91, Zie92i, Zie93p]. **Quality** [Zie93a, Zie93-34, Zie96k, Zie96-51, Zie96z, Zie97-34, Zie98-43, Zie99-29, BR95, Ben93, Bre96, Coo96b, Dog99, Hwa92, Lew92, Maz98, McC90, McC91, Men91, Pie90b, She90a, She90b, Sin90b, Spe96a, Wal92b, Zie93w, Zie93v, Zie93u, Zie94-33, Zie95-30, Zie95-31, Zie96-32, Zie97w, Zie98-35, Zie99-33]. **Quality-Monitoring** [NW93]. **Quantal** [Cra94]. **Quantified** [Dav99]. **Quantiles** [YE94]. **Quantitative** [Bay99, Gro99, STC99, Sch94b, Che92, Pro90, Zie99-34]. **Quantities** [Baj98]. **Quark** [HS97]. **Quasi** [Zie96-27, Bor98]. **Quasi-Likelihood** [Bor98]. **Quasi-Monte** [Zie96-27]. **Quesenberry** [Ano93f, FMQ92, dC99]. **Questions** [Zie97q]. **Queueing** [Bax92, Gla98, Sys99]. **Quick** [Zie96-33, Zie97x].

R [Aba98, Ada92, Ada94, Arm97, Baj98, Bar92a, Bel95, Bel99, Bil91, Bla94, Bor97a, Bre90, Bri91, Bzi97, Che92, Coh92, Dea91, Dea97, Der90, Dri92, Eas99, Emp93, Fre93, Gas97, Gho93, Gho94, Gol95, Got94a, Gri90, Gun99, Hab92, Ham96, Hes91, Hoc94, Hor98, Jan94, Jen90, Jen93, Kia92a, Kia93a, Kir92, KY91, Kra90, Lit91, MA92, McC98, McG94, Mil98, Moo99, Mor99b, Mor97a, Nem92, Pan92, Per97, Pfa92, Pie90a, Pit92, Pit96, Rag93, Ram99,

Ram91, Rie94b, Rut93, Sco90, Sco92, She90a, Sho90, Sin90a, Sin90b, Ste90c, Ste98, Ter92, Thi91, Tob99, Wal92a, War90, Wat96, Weh93, Wei90, Wei94, Wil98, Won94, Zie90-28, Zie90t, Zie90w, Zie90k, Zie91q, Zie91k, Zie92k, Zie92c, Zie92v, Zie92n, Zie92o, Zie92u, Zie93c, Zie93-28, Zie93p]. **R** [Zie93v, Zie93r, Zie93-36, Zie94e, Zie94k, Zie94j, Zie94-31, Zie94l, Zie94-44, Zie94-43, Zie94-33, Zie94z, Zie94q, Zie95-33, Zie95-31, Zie95n, Zie95-28, Zie95-50, Zie96d, Zie96e, Zie96-44, Zie96h, Zie96-40, Zie96-52, Zie96-48, Zie96-29, Zie96r, Zie96-36, Zie96v, Zie97b, Zie97-27, Zie97-42, Zie97v, Zie97g, Zie97k, Zie98-45, Zie98s, Zie98q, Zie98-44, Zie99-47, Zie99s, Zie99t, Zin93]. **R&R** [VV99]. **Rabe** [Lee99]. **Rabe-hesketh** [Lee99]. **Rade** [Zie91c]. **Raghavarao** [Sea93]. **Ragsdale** [Zie98-39]. **Raheja** [Sha92]. **Rahim** [Zie99y]. **Raj** [Bas90]. **Raja** [Tim99]. **Ralph** [Goi96]. **Ramasamy** [Zie98c]. **Ramaswamy** [Zie97k]. **Ramon** [Hei90, Zie99-35]. **Ramsay** [Geo98]. **Ramsey** [Zie96-52]. **Rand** [Hor98]. **Random** [Ann99, Ano99f, BT89, Gol90, JV93, JFM99, Khu92, KK99, Lei91, Lin99, MJ91, Oma91, PM99, PH99, RH95, Sen97, Taa91, Van92b, VV99, WT98, BT98, Bax96a, Gal95, Nai96]. **Random-Effects** [BT89, Van92b, VV99, BT98]. **Randomization** [Nik93, Zie98-36, Zie98-37]. **Randy** [Tob99]. **Range** [CC99]. **Rank** [Gro96, Tim99, Gov92]. **Rao** [Zie91k, Zie93-28, Zie94v, Zie98g, Eas99, Rie94b, Sin90b, Wei94, Zie90k, Zie91k, Zie95l, Zie96p]. **Raoul** [KR93]. **Rasmussen** [Sau94]. **Rate** [Hir96, Hul92, MPR99]. **Rates** [GS92, GS94, TW96]. **Rather** [Zad95, Ano97f]. **Ratio** [BBT90, MS90, Sin83, SGW96, Sin92]. **Rationale** [Nay98]. **Ratios** [Zie99x]. **Ratkowsky** [Zie94m, Zie91i]. **Ratliff** [Zie94g]. **Raudenbush** [Cal94]. **Raun** [Zie90d]. **Rausand** [Van96b]. **Rauwendaal** [Zie95-34]. **Rawlings** [Zie99d, vN90]. **Raymond** [Bel95, Gun96a, Rob90, Zie91d, Zie99-30]. **Rayner** [Kin91, PBR92]. **Reaction** [AB97]. **Read** [Zie98o, Zie98p, Ber97, Zie90h, Zie92g]. **Readings** [Han90]. **Real** [GSH98, KMP95, Zie94-34]. **Real-Time** [GSH98, Zie94-34]. **Really** [Arm90]. **Reanalysis** [MSF95]. **Reasoning** [Jon92, Lor99]. **Reavis** [Zie96k]. **Recognition** [Ful97, JR91, Nem95, Boo99, Ray93]. **Rectification** [GS92]. **Recurrence** [Nel95]. **Recurrent** [LN95]. **Recursive** [Ano91e, Gri97b, Haw91a]. **Red** [Zie95y]. **Redesign** [Zie97u]. **Redman** [Mar94]. **Reduce** [DJ94]. **Reduced** [Tim99]. **Reduced-Rank** [Tim99]. **Reduction** [Jol90, Lew93]. **Regimes** [MQ91]. **Region** [CCC90]. **Regions** [AAK99]. **Regression** [Ano91e, Ano91f, Atk96, BB95, Ber98, Bre95a, CS92, Coo96a, Dal90, ET96, Eub90, Fai91, Far97, FF93b, FF93a, Gle96, Gol95, Gra98, Gun99, HM93, Haw91a, Haw91b, HLD98, Iye90, Kaf94, Kia90, Kia92b, Kia95a, Kia95b, Lam92, Lau94b, Law98, MQ91, Mar96, ME99, MS90, MER91, Mil90, Osb97, PF91, Peñ91, Por93, Pro92a, Qiu95, QY98, Sch96a, SD90, STR99, Spu93, TW90, WVYB97, Win93, Zie90b, Zie91i, Zie91l, Zie91d, Zie96x, Zie96c, Zie97-44, Zie99d, DSSU98, vN90, Ale98, Ber91, Bor97b, Cuc92, Eub93, Fai94, Gol93, Sch92a, Tim99, Wei90, Zie92o, Zie98-27, Alt99, Ang91b, Bar95, Cal98, Chi91, Fox97, Gra94, Maz93, Moo99, Pet99, Zie93x, Zie94-35]. **Regression-Adjusted** [Ano91f, Haw91b]. **Regression-Based** [MS90].

Regressions [Moo99]. **Regressors** [vdVtBM97]. **Reid** [Zie92s, Zie93-30]. **Reinhard** [Spe91]. **Reinsel** [Tim99, Tim95, Zie95-46, Zie97l]. **Rejection** [CWWR97]. **Rejoinder** [WMP94b]. **Reklaitis** [Mar99]. **Related** [Gra98, Hab90, HW90b, HW90a, Hir90, Jac95, Loh92, Nai90b, Woo91, YDB90]. **Relations** [Zie91l]. **Relationship** [TI99]. **Reliability** [AHT91, Bar92b, Bar92a, BCL98a, BCL98b, Bry92, Bry99, Car90a, Dog99, EMS98, Geo94, Gle91, Gri99, Han97, Hey92, JD92, Kim91, MW90, MKA96, ML95, Nel98, Pap96, Rag98, RM95, Rig93, Rob98, Sch98a, Sen98, Sha93, Sin90b, Tor95, Tor99, Van91, Van96b, Wal92b, WJ92, Zie91p, Zie97r, Sen99b, Boo90, Die92, Fre99, Gri97a, McC99, Sam90, Soy95, Zie96-34, Zie96e, Bax96b, Car96, Fox94, Gru95, Hey98, Kha95, Law96, Lee93, Lyn95, Lyn97a, Pla96, Rig92b, Sam99a, Sch92c, Sch93a, Sch94a, Zie96-35]. **Reliability-Centered** [Zie96-35]. **Reliability-Maintainability** [JD92]. **Relyea** [Jen92]. **Rencher** [Boo98, Mat96]. **René** [Spo90]. **Renewals** [LT96]. **Repairable** [AHT91, LT96, SP95]. **Repairable-Systems** [SP95]. **Repairs** [Nel95]. **Repeatability** [OUH93]. **Repeated** [Kia94, Lin92, LN96, Sha97c, Tim96, Zie93b]. **Repeated-Measures** [LN96]. **Repetitive** [GS95]. **Replicated** [Jac93, Lwi94]. **Reply** [DGTZ97b, Got94b, LSBW95a, MSB96b, OM96b, RD95b, Ste96b]. **Report** [Kaf99, Mor97b, Mor98c, Nai90a, Nai91a, Nai92, Var94a]. **Reporting** [Woo91]. **Reproduction** [VD94]. **Resampling** [HR92, Nik95, HR94, Cha93]. **Resampling-Based** [Cha93]. **Research** [Bor97a, Kaf94, Sch95, Spr91, Sri93, Zie91r, Zie92f, Zie92u, Zie93u, Zie95-44, Zie96w, Zie97w, Zie98v, Zie99d, Zie99-52, Zie99g, Zie99-48, vN90, Ing92, Sri93, Zie90x, Zie94n, Zie95x, Zie98r]. **Residual** [Coo93, PF91, Sch91d]. **Residuals** [Ano91e, Haw91a, MQ91]. **Residue** [McA90]. **Resistant** [CWWR97]. **Resnick** [Wen93]. **Resolution** [Bis94, BL97, LIV96, SCF97]. **Resolutions** [DL90a]. **Resolve** [Fed96, JD96, MSB96a, MSB96b, Tob96]. **Resource** [Coh92]. **Resources** [Got94a]. **Response** [Alt99, Ano99f, BCL98b, BA96, BK92b, Bre91b, CCC90, CM93a, Cra94, DM99b, DL90b, Far97, FF93a, HW90a, Khu92, LS90c, MME98, Pro92a, RAA90b, SE93, SC93, VM91, Gun96a, Zie97y]. **Response-Surface** [DL90b]. **Rest** [Hal94]. **Restricted** [Sho90]. **Results** [Zie96-33]. **Retherford** [Zel94]. **Reuven** [Goo95]. **Reversal** [GS94]. **Review** [Aba98, Acr97, Ada91, Ada92, Ada93, Ada94, Ada96, Ajm99, Alb93, Ale91, Ale95, Ale98, Ale99, All96, Alt96, Alt99, Amm92, And90, Ang90a, Ang90b, Ang91a, Ang91b, Ang91c, Ang92, Ara92, Arm92, Arm93, Arm97, Arn90, Aye98, Bab98, Baj98, Bak98, Bal93, BR95, Bar91, Bar92b, Bar92a, Bar95, Bas90, Bas97, Bas99, Bat99, Bax92, Bax95, Bax96b, Bax96a, Bay92, Bay95, Bay99, Beg90, Bel95, Bel99, Bem96, Ben93, Ber91, Ber92a, Ber96b, Ber97, Ber92b, Bie92, Bil91, Bil92, Bil94, Bla94, Bla92, Bli91, Bod97, Bog92, Boo90, Boo95, Boo92, Boo93, Boo94b, Boo94a, Boo97, Boo98, Boo99, Bor97a, Bor94, Bor97b, Bor95b, Bor97c, Bor98, Bos92, Bow91, Boy90, Bre95b, Bre97, Bre90, Bre96, Bri91, Bri96, Bro90a, Bro90b, Bro92, Bru91, Bru92a, Bru92b]. **Review** [Bru93b, Bru93a, Bru94, Bru95, Bru96, Bru97, Bry92, Bry99, Buc90,

Bul91, Bul96, Bur91, Bzi97, Cab94, Cab98, Cal94, Cal98, Cam90, Cam96, Cam98, Car90a, Car90b, Car92, Car93, Car95, Car96, Car97, Cha95, Cha92, Cha98, Cha93, Che92, Che94, Che98, Che91, Chi91, Chr97, Chu91, Cly94, Coa94, Cob91, Coh92, Col92, Col93, Coo96b, Cox93, Cox96, Cra94, Cro94, Cro99, Cry90, Cuc92, Czi92, Das93, Dav99, DeV99, Dea91, Dea94, Dea95, Dea96, Dea97, Deh90, Der90, Dic91, Dic97, Die92, Dob96, Dog93, Dog99, Dom90, Don90, Dov93, Dow95, Dre91, Dri91, Dri92, Dun90, Dun96, Dun97, Eas90, Eas99, Edg92, Edg98, Elt90, Emp92, Emp93, Emp97, Emp99, Ens95, Eub90, Eub93, Fai91, Fai94, Fal99, Fam95, Fam97, Fam99, Far90]. **Review** [Far92, Far93, Fot95, Fot96, Fox91, Fox94, Fox97, Fox98, Fre92, Fre99, Fre93, Fre94, Fre95, Fre97, Fri97, Ful95, Ful97, Gal95, Gal92, Gal93, Gan97, Gas97, Gas94, Gat96, GR97, Geo94, Geo98, Gho93, Gho94, Gib91, Gil92, Gla98, Gle91, Gle96, Glo93, Glo95, Glo97, Glo99, God93, God95, Goi96, Gol99, Gol95, Gol93, Gol98, Gol90, Goo91, Goo92a, Goo95, Goo92b, Got92, Got94a, Gov92, Gra90, Gra94, Gra98, Gre94, Gre98, Gri90, Gri96, Gri97a, Gri99, Gri98, Gri95, Gro92, Gro96, Gro99, Gru90, Gru95, Gru97, Gue90, Gun90, Gun96a, Gun99, Gun94b, Gun94a, Gun96b, Gut90, Gut92, Hab92, Had92, Hag90, Hag91, Hag96, Hal95, Hal98, Hal94, HH96, Ham96, Han90, Han93, Han97, Han98, Hap91, Hap92, Har91a, Har91b, Har91d, Har91c]. **Review** [Har92a, Has91, Haw90, Hea94, Hec90, Hec95, Hec96, Hec99, Hei90, Hem99, Hes91, Hes93, Hes97, Hey92, Hey98, Hey93, Hig98, Hil95, Hin97, Hoc94, Hof95, Hor98, Hul92, Huz95, Hwa92, IHMT95, Ing92, Iye98, Iye90, Ize90, Ize91, Jac95, Jai95, Jam96, Jan94, Jen90, Jen91, Jen92, Jen93, Job99, Joh91, Jol90, Jol93, Jol96, Jol97, Jon90, Jon91b, Jon91a, Jon92, Jon93, Kah94, Kal93, Kal98, Kan95, Kat91, KR93, KB94, Kat98, Ked96, Ked98, Kel97, Kha95, Kia90, Kia92a, Kia92b, Kia93a, Kia93b, Kia94, Kia95a, Kia95b, Kim91, Kin91, Kin93, Kin97, Kir92, Kir93, Kle94, Ko95b, Ko95a, Koe92, Koh90, Koh94, Koo90, KY91, Kot92, Kra90, Kra92, Kus92, Kus98, Kus93, LaL92, LaL95, Lal99, Lam90, Lar95, Lau94b, Law95, Law92]. **Review** [Law98, Law96, LC94, LC98, LeP90a, LeP90b, Lee90, Lee93, Lee94, Lee99, Lei91, Lei92, Lei93, Lei97, Lei99, Len90, Len93, Len95, Lew92, Lew93, LH97, Lin99, Lin92, Lin90, Lit91, Liu92a, Liu92b, Liu99, Loh92, Loh94, Lor92, Lor93, Lor99, LuV90, Lyn94, Lyn95, Lyn97a, Lyn97b, Lyn99, Mac90a, Mad96, Mad98, Mag90, Mag96, Mar97, Mar94, MA92, Mar99, Mas99, Mat96, Mat97, Mat98, Maz93, Maz98, McA90, McC90, McC91, McC98, McC94, McC99, McG94, McL95, Mee91a, Mee91b, Men91, Mi97, Mi99, Mil91, Mil94, Mil99, Mil90, Mil98, Min93, Moo91, Moo96, Moo99, Mor93a, Mor99a, Mor92, Mor99b, Mor97a, Mor93b, Mul97, Mye91, Mye96, Nai94, Nai96, Nan94, Nar93, Nay98, Nel98, Nem92, Nem95, Nem97, Neu99, Nik93, Nik95, Nip92, Not92a, Not92c, Not92b, O'D97]. **Review** [O'D99, Oli97, Oli98, Ord96, Osb97, Ott90, Owe91, Owe96, Pan92, Pan96, Pap95, Pap96, Par92, Pat91, Ped98, Per92, Per98, Per97, Pet99, Pfa92, Pfa99, Pie90b, Pie90a, Pig91, Pit92, Pit96, Pla90, Pla96, Pol93, Por93, Por97b, Por97a, Pos98, Pot93, Pri93, Pri98, Pro90, Pro92b, Pro93a, Pro93b, Pro94,

Pro96, Qiu95, Rab92, Rag91, Rag93, Rag95, Ram99, Ram93, Ram91, Ram94, Ram96, Rao98, Ray93, Raz91, Rea93, Rie94b, Rie94a, Rie97, Rig92b, Rig92a, Rig93, Rig99, Rob90, Roh91, Rol93, Roz93, Ruk97a, Ruk97b, Ruk98, Run90, Rus94, Rut93, Sac93, Sai96, Sam90, Sam99b, Sam99a, San98, San92, San99, Sar90, Sar93, Sar94b, Sar94a, Sau92, Sau94, Sau97, Sau98, Sch91a, Sch92a, Sch96a, Sch91b, Sch95, Sch92c, Sch93a, Sch94a]. **Review**
[Sch96b, Sch92d, Sch93c, Sch93b, Sch94b, Sch96c, Sco90, Sco91, Sco92, Sea90, Sea91, Sea93, Sea94, Sen99a, Sen94b, Sen94a, Sen95, Sen97, Sha92, Sha93, Sha95, Sha97c, Sha97b, Sha97a, Sha98, She90a, She90b, Sho90, Sim97, Sim91, Sin90a, Sin90b, Sin97, Sin98, Smi91, Smi93, Soy95, Spa99, SN95, Spe96a, Spe91, Spo90, Spr91, Sri92, Sri93, Ste90a, Ste91, Ste90c, Ste98, SG99, Ste99, Sti97, Sto96, Sto92, Str96, Stu94, Sys99, Taa91, Taa99, Tam96, Tan98, Tan93, Ter92, Thi91, Tho99, Tho90a, Tho93, Tho90b, Tho92b, Tim95, Tim96, Tim99, Tob99, Tom95, Tor95, Tor99, Tro97, Tsa91, Tso92, Van92a, Van91, Van96b, Ver90, Vin92, Voe94, Vuk98, Wad99, Wal92a, Wal92b, Wan94, War90, Was91, Was97, Wat90, Wat96, Web90]. **Review**
[Weh91, Weh93, Weh95, Wei90, Wei94, Wel90, Wel93, Wen93, Wen94, Wes92, Wha95, Whe93, Wil90a, Wil90b, Wil98, Win90, Win93, Wit94, Wol91, Wol96, Wol92, Won94, Won98, Woo91, Woo92, Woz91, Wu99, Wyc96, Yak97, Yan96, Yan97, Yeh93, Yin91, Zei94, Zel94, Zha92, Zie90l, Zie90p, Zie90x, Zie90i, Zie90m, Zie90o, Zie90v, Zie90h, Zie90q, Zie90j, Zie90z, Zie90e, Zie90y, Zie90s, Zie90d, Zie90f, Zie90n, Zie90t, Zie90r, Zie90w, Zie90u, Zie90b, Zie90c, Zie90a, Zie90k, Zie90g, Zie91g, Zie91n, Zie91i, Zie91m, Zie91p, Zie91l, Zie91k, Zie91f, Zie91e, Zie91a, Zie91c, Zie91j, Zie91d, Zie91b, Zie91h, Zie91o, Zie92b, Zie92j, Zie92f, Zie92a, Zie92t, Zie92h, Zie92g, Zie92d, Zie92q, Zie92k, Zie92e, Zie92c, Zie92x, Zie92i, Zie92r, Zie92w, Zie92v, Zie92p, Zie92m]. **Review**
[Zie92l, Zie92n, Zie92o, Zie92u, Zie92s, Zie93-30, Zie93e, Zie93c, Zie93j, Zie93t, Zie93b, Zie93-28, Zie93-31, Zie93o, Zie93w, Zie93l, Zie93-37, Zie93p, Zie93v, Zie93h, Zie93d, Zie93x, Zie93-33, Zie93r, Zie93-29, Zie93m, Zie93z, Zie93-27, Zie93-38, Zie93a, Zie93u, Zie93q, Zie93k, Zie93g, Zie93f, Zie93i, Zie93s, Zie93-32, Zie93-36, Zie93n, Zie93-34, Zie93-35, Zie93y, Zie94o, Zie94u, Zie94e, Zie94h, Zie94f, Zie94k, Zie94-42, Zie94d, Zie94w, Zie94r, Zie94t, Zie94x, Zie94-28, Zie94-29, Zie94j, Zie94a, Zie94v, Zie94-30, Zie94-41, Zie94-39, Zie94y, Zie94-31, Zie94g, Zie94l, Zie94-44, Zie94b, Zie94s, Zie94-32, Zie94-40, Zie94-38, Zie94-43, Zie94-33, Zie94-36, Zie94-37, Zie94-27, Zie94z, Zie94i, Zie94p, Zie94c, Zie94m, Zie94n, Zie94-34, Zie94q, Zie94-35, Zie95q, Zie95-48, Zie95p, Zie95-30, Zie95u, Zie95r, Zie95-33]. **Review**
[Zie95g, Zie95-42, Zie95-29, Zie95d, Zie95-41, Zie95i, Zie95t, Zie95-35, Zie95-45, Zie95-31, Zie95o, Zie95-38, Zie95e, Zie95-32, Zie95b, Zie95h, Zie95-40, Zie95z, Zie95s, Zie95y, Zie95v, Zie95f, Zie95l, Zie95n, Zie95j, Zie95x, Zie95w, Zie95-37, Zie95-47, Zie95-46, Zie95-28, Zie95m, Zie95-39, Zie95-36, Zie95-27, Zie95-34, Zie95k, Zie95c, Zie95a, Zie95-44, Zie95-43, Zie96m, Zie96-47, Zie96-34, Zie96-32, Zie96o, Zie96q, Zie96b, Zie96-28, Zie96t, Zie96d, Zie96-45, Zie96w, Zie96-30, Zie96n, Zie96-37, Zie96-41, Zie96e, Zie96-31,

Zie96-44, Zie96-50, Zie96j, Zie96-43, Zie96i, Zie96h, Zie96-40, Zie96-27, Zie96a, Zie96x, Zie96-33, Zie96-35, Zie96k, Zie96-51, Zie96g, Zie96-48, Zie96-29, Zie96-39, Zie96-42, Zie96p, Zie96-38, Zie96r, Zie96s, Zie96c, Zie96u, Zie96l, Zie96-46, Zie96f, Zie96z, Zie96-49, Zie96-36, Zie96v, Zie96y, Zie97-39, Zie97b]. **Review** [Zie97h, Zie97-32, Zie97-27, Zie97-38, Zie97m, Zie97-29, Zie97s, Zie97r, Zie97-34, Zie97-28, Zie97l, Zie97e, Zie97u, Zie97f, Zie97x, Zie97p, Zie97-36, Zie97-33, Zie97-42, Zie97-35, Zie97o, Zie97v, Zie97c, Zie97d, Zie97t, Zie97-37, Zie97-43, Zie97q, Zie97j, Zie97-41, Zie97z, Zie97g, Zie97-30, Zie97a, Zie97w, Zie97-31, Zie97k, Zie97i, Zie97y, Zie97-40, Zie97n, Zie98o, Zie98-42, Zie98-45, Zie98-48, Zie98-39, Zie98h, Zie98-34, Zie98-41, Zie98-32, Zie98-27, Zie98a, Zie98-38, Zie98t, Zie98s, Zie98y, Zie98j, Zie98n, Zie98-35, Zie98q, Zie98p, Zie98-29, Zie98-47, Zie98v, Zie98-31, Zie98-33, Zie98-46, Zie98c, Zie98f, Zie98-43, Zie98l, Zie98m, Zie98-36, Zie98-44, Zie98-28, Zie98-40, Zie98g, Zie98-37, Zie98-30, Zie98i, Zie98r, Zie98x, Zie98d, Zie98e, Zie98k, Zie98z, Zie98b, Zie98w, Zie98u, Zie99-27, Zie99l, Zie99-42, Zie99k, Zie99-38]. **Review** [Zie99-31, Zie99-47, Zie99w, Zie99f, Zie99-45, Zie99-46, Zie99z, Zie99-49, Zie99-43, Zie99u, Zie99i, Zie99-28, Zie99-34, Zie99v, Zie99-29, Zie99-33, Zie99-37, Zie99e, Zie99-39, Zie99j, Zie99-36, Zie99s, Zie99c, Zie99-51, Zie99d, Zie99t, Zie99p, Zie99q, Zie99r, Zie99-35, Zie99-50, Zie99a, Zie99b, Zie99o, Zie99y, Zie99n, Zie99-44, Zie99m, Zie99g, Zie99-48, Zie99h, Zie99-30, Zie99-41, Zie99-32, Zie99-40, Zie99x, Zin93, dV92, dV93, dC99, vN90, vT91, vT95]. **Reviews** [Pro92a, Zie90-28, Zie90-27, Zie91q, Zie91r, Zie94-45, Zie95-49, Zie95-50, Zie96-52, Zie97-44, Zie99-52]. **Reweighted** [Mar96]. **Reyment** [Lyn97b]. **Rhinehart** [Jan94]. **Rhyder** [O'D99]. **Rice** [Zie95v]. **Richard** [Ara92, Bay99, Boo93, Bow91, Bro92, Bry99, Fox97, Glo99, Gru95, Gut92, Hil95, Jon91a, Jon92, Kin93, Kle94, Kot92, Kra90, Lei97, Lor99, McC99, Nem95, Pot93, Pro93a, Sar90, Sco91, Sen94b, Sha97b, Smi93, Tho90b, Zie91j, Zie94o, Zie94t, Zie99c, Zie99h]. **Richardson** [Gas97]. **Ricky** [McL95]. **Ridge** [Pet93]. **Rieder** [Zie97z]. **Riedwyl** [Haw90]. **Right** [Ada91]. **Rijckevorsel** [Jol90]. **Rindskopf** [Wat90]. **Rinne** [Jai95]. **Ripley** [Ful97, Jam96, Koe92]. **Rising** [Zie90w]. **Risk**
[Geo94, Zie94q, Zie95m, Zie98y, Zie99-28, Zie99-34, Zie97-29, Liu99, Zie91n]. **Risks** [ACV99]. **Rivoirard** [Cam96]. **Road** [Zie93i]. **Roadmaps** [Zie95-32]. **Robert** [Arm93, Aye98, Ben93, Bow91, Bri96, Bru92b, Cha98, Gan97, Got92, Gri95, HH96, Har91a, Jan94, Liu92b, Loh94, Pan92, Pro90, Pro92b, Rig92b, Sar93, Tam96, Wil90b, Win90, Won98, Zel94, Zie90-28, Zie90-27, Zie90c, Zie95-37, Zie96f, Zie98l, Zie99-42, Zie99v, Zie99-52, dV92, Zie99j]. **Roberto** [Zie96l]. **Roberts** [Zie90-27, Zie93h, Zie94-37, Zie97w]. **Robertson** [Sho90]. **Robin** [Por97a]. **Robot** [OUH93]. **Robust** [Alt96, CV97, EH96, Hor98, IHMT95, LN95, Li97, MSH94, Men91, Pie90b, STW91, Tat97, WVYB97, WT98, Zie91l, Zie93k, Zie98-47, Fai91, Har91a, Mi99, Pri98, Tan98, Zie97z]. **Robustness** [BL97, TWN98, Zie94-29, Boo99, Roh91]. **Rock** [Zie90m]. **Roe** [Gal93]. **Roebuck** [Sch91a]. **Roger** [Ang91c, Bax96b, Ber92a, Loh94]. **Rogerson** [Zie97-30]. **Roland** [Dun96, Zie91h]. **Role** [Zie90y]. **Rolf**

[Emp97, Kel97]. **Ron** [Fre99, Mas99]. **Ronald** [Cab94, Cha92, Dea97, Gri96, Han93, Hem99, Kah94, Mor92, Nip92, Rob90, Zie98h, Zie98-27, Zie99-30]. **Ronchetti** [Zie94-29]. **Root** [Zie94-36]. **Rosenbaum** [Zie96-28]. **Rosenfeld** [Zie99q]. **Rosenkrantz** [Taa99]. **Ross** [Len93, Zie99-29, Bab98, Fre97, Kus92, Lor92, O'D97, San92, Zie95n, Zie97-39, Zie97-28, Zie98a]. **Rossi** [Zie98l]. **Rossman** [Mul97]. **Rotatability** [DP90]. **Roughness** [Qiu95]. **Rousseeuw** [Had92]. **Route** [Kal93]. **Routines** [IHMT95]. **Row** [Tür94]. **Row-Column** [Tür94]. **Roxy** [Zie99-37]. **Royall** [Glo99]. **Ruanaidh** [Rie97]. **Rubinstein** [Goo95]. **Rudas** [Zie99x]. **Rudolf** [Ale91, Alt99, Dav99]. **Rule** [VB94a]. **Rules** [Wad99]. **Run**
[AWS94, Fel94, God93, Luc94, Mor99a, Ngu96b, WMP94a, WMP94b, Zie92i]. **Run-Length** [AWS94, Fel94, Luc94, WMP94a, WMP94b]. **Runger** [Zie99l, Ale95]. **Runs** [Cro92, WW92]. **Ruppert** [Arm97, Wei90]. **Russek** [Zie99t]. **Russek-Cohen** [Zie99t]. **Russell** [Jan94, Zie99t]. **Rustagi** [Fot95]. **Ryan** [Coo96b, Lam90, Osb97].

S
[Aba98, Alb93, Arn90, Bas90, Bat99, Bli91, Bre90, Bru96, Buc90, Bzi97, Cal94, Cam90, Cha93, Chu91, Col92, Cuc92, Fot95, Fox98, Fre99, Fre93, Fre94, Gas97, Gre98, Gue90, Gun94b, Hin97, Huz95, IHMT95, Iye90, Kal98, Kia92a, Kin97, Ko95b, Ko95a, Koh94, Kus92, Lee93, Lee99, Len95, Mac90a, Mas99, Maz98, McC90, Moo96, Nai94, Nan94, Oli98, Pat91, Pig91, Ram96, Rea93, Sam99b, San92, Sco90, Sea94, Sto96, Taa91, Tho90a, Wal92b, Was97, Wol92, Yan97, Zha92, Zie90-27, Zie90h, Zie90u, Zie92g, Zie92k, Zie92m, Zie93r, Zie93k, Zie93s, Zie94h, Zie94-28, Zie94-29, Zie94-39, Zie94-45, Zie94p, Zie94c, Zie94q, Zie95d, Zie95-38, Zie95-32, Zie95-40, Zie95l, Zie95j, Zie96k, Zie96-48, Zie96-39, Zie97-34, Zie97-28, Zie97-41, Zie97-30, Zie98o, Zie98-38, Zie98p, Zie98-29, Zie98-33]. **S** [Zie98-46, Zie98l, Zie98m, Zie98d, Zie98w, Zie99z, Zie99s, Zie99o, vT95, Han98, Hes93, Jam96, Ko95b, Ko95a, Zie98-46, Zie99m, Zie98-38]. **S-PLUS** [Han98, Jam96, Zie98-46, Ko95b, Ko95a, Zie99m]. **Sacco** [Zie98b]. **Sachs** [LC98]. **Safeguards** [War90]. **Safety** [Boo90, Tor99]. **Sahai** [Zie96-43]. **Saichev** [Sha97a]. **Sall** [Zie99r]. **Sally** [Nai96]. **Salsburg** [Zie93-31]. **Sample** [CWWR97, CCC90, HP97, HC91, Hul92, Mad98, Ste87, Wil90a, Zie94c, Ste90b, Emp93, Min93, Sea93]. **Sampled** [ME99]. **Samples** [Mor93a, Sin83, Sin92]. **Sampling**
[Bil92, Bil94, BL94, GS92, HR92, HL95, Hea90, Hes95, KD97, LS90a, McA90, MT91, Mor99b, Mor91, MT92, PH99, RAA90a, RAA90b, Ste87, Woo90, Zie93-33, Zie95z, HR94, Ste90b, Bru96, Por97b, Ruk98, Sto96, Tan93, Zie90r, Zie90k, Zie93j, Zie93-32, Bil94, Zie92m, Zie93y]. **Samprit** [Maz93]. **Samuel** [Ber96b, Bru94, Car93, Cha95, Col92, Fam95, Loh92, Pos98, Zie98k, Zie98z, Zie99-31]. **Sander** [Zie96e]. **Sanders** [Per97, Fre92]. **Sandifer** [Zie99k]. **Sandra** [Hei90, Zie99-35]. **Sanford** [Gol95]. **Sanjit** [Sen94a]. **Santner** [Sim91, Tam96]. **SAS** [Ale91, Hec90, Ste99, Tho92b, Zie95u, Zie95b, Zie96-45, Zie96i, Zie96x, Zie96-33, Zie97-38, Zie97-36, Zie98h, Zie99-31, Zie99-47, Zie99r,

Zie99g, Zie99-48, Zie96w, Zie96x, Zie97m, Zie97-36, Zie97x, Zie97p, Hei90, LaL92, Zie92n, Zie92o, Zie93z, Zie95-32, Zie96-36]. **SAS-Oriented** [Ste99]. **SAS/Graph** [Zie96-45, Zie96-33]. **SAS(R)**
[Hec96, Zie96d, Zie96w, Zie97-32, Zie97m, Zie98r, Zie97-27, Zie99-35]. **Sastry** [Zie99d]. **Satellite** [CC95]. **Satisfaction**
[Zie97i, San98, Zie95w, Zie97s, Zie98-31]. **Saturated**
[HO95, Kun97, Lin93a, Lin95a]. **Saunders** [RN91, Zie95p]. **Saville** [Mil98, Zie93-29]. **Sawyer** [Zie98v]. **Scale** [HP97, MM94]. **Scaled** [KS93]. **Scaling** [Jol96]. **Scatterplots** [Deu96]. **Schader** [Zie90g]. **Scheaffer** [Zie95-28, Jon91a]. **Scheiner** [Zie95j]. **Schemes**
[Bax90, DP91, FHT90, Hun90b, LS90b, LS90c, Luc98, LG99, MH90, SWC97, TWN98, WM90, Yas92, Yas93]. **Scherkenbach** [Zie93i]. **Schiff** [Goi96]. **Schilling** [Ram91]. **Schimek** [Zie98-41]. **Schleifer** [Law98]. **Schlotzhauer** [Hei90, Zie99-35]. **Schmidt** [Pan92, Zie96-48, Nem92, Zie94h]. **Schneider** [Zie94r]. **Schofield** [Zie98u]. **Schucany** [Zie97-34]. **Schuler** [Zie93p]. **Schum** [Zie98b]. **Schürmann** [Sim97]. **Schurz** [Hal95]. **Schwartz** [Zie98-43]. **Science** [Alm95, Bax92, Bro90b, Gla98, KY91, Nem95, Zie91g, Bow91, Gut90, Nar93, Zie95-38, Zie96-39, Zie98z, Zie99z]. **Sciences**
[Zie90h, Zie92g, Zie98o, Zie98p, Cro99, Got92, Hes91, Jen90, Lyn97b, Rag91, Ram94, Ram96, Rus94, Sha97a, Wal92a, Wat96, Zie90z, Zie91r, Zie92d, Zie92l, Zie93-28, Zie94o, Zie94w, Zie94-40, Zie96t, Zie96-38]. **Scientific** [Gib91, Tho90a, Zie96-27, Bro92]. **Scientists** [Box90, Gut92, Hah90, HK90, Hoo90, Hun90a, Mac90b, Moo90, Taa99, Tri90, Wan90, God90, Bar91, Bzi97, Rob90, Tho99, Zie93c, Zie94-31, Zie96-42, Zie99p, Zie99-30]. **Score** [Goo95]. **Scorecard** [Zie98-45]. **Scott** [Cal98, Zie90-27, Zie94k, Zie96c, Ram93]. **Scram** [MPR99]. **Screening** [Mee90a, Tam96, WBS$^+$92]. **SDE** [Hal95]. **Searle** [Gho93, Zie99s]. **Seasholtz** [Tob99]. **Seber** [Ber91, Por97b]. **Second** [BA96, Dri91, Gra94]. **Second-Order** [BA96]. **Seeber** [Zie96-40]. **Seeing** [BB95, Fam97]. **Seheult** [Die92]. **Seismic** [Ano00, SBD98]. **Selected** [Roe91, Zie99-36]. **Selecting** [ES94, Zie95-33]. **Selection**
[BL94, CHW97, Len95, Sch92a, Tam96, Zie94-27]. **Self**
[Car97, Kal93, Kia95a]. **Self-Instructional** [Kal93]. **Self-Learning** [Car97, Kia95a]. **Selvin** [Zie95-36, Zie95-27]. **Semiparametric** [Zie99-27]. **Semivariogram** [ZZ91]. **Sen** [Chi91, Zie94u]. **Senn** [Zie94n, Zie99-39]. **Sense** [Das93]. **Sensitivity** [ET96, Goo95, Ney94, STC99, Tho94, YE94]. **Sequences** [Hol98]. **Sequential** [Ber92a, SGW96, Zie94u, Zie94-37]. **Serial** [MQ91, Zie94z]. **Serially** [Yas93]. **Series**
[Ang92, BH97, Boo94b, Boo97, Cab98, Chu91, Dic91, Dow95, Elt90, Ens95, Fre95, Har92a, Jol93, Li97, MW90, Nip92, Ord96, Rag98, RM95, Sha97b, Ste91, Tim95, Tso92, Viv91, Wel90, Win90, Zha92, Zie90c, Zie92v, Zie94t, Zie94x, Zie95l, Zie95-46, Zie97l, Zie97-42, Zie98f, Zie98g, Boo92, Dic97, Ped98, Per98, Zie92p, Zie95e, Zie97-40]. **Series/Parallel** [MW90]. **Service** [Zie97k]. **Services** [Gun96b]. **Sets** [Kan95, Zie95a]. **Setting** [Cam98]. **Settle** [Zie99-52]. **Several** [Spu92]. **Severity** [BCL98a, BCL98b, Rob98, Sch98a].

Sevin [Gun90]. **Seymour** [Law95]. **Shachter** [Len93]. **Shanubhogue** [Bas97]. **Shao** [Hes97]. **Shape** [KGK90, Won92]. **Shapiro** [Zie98c, Col92, Goo95, Zie94-39]. **Sharma** [Mar97]. **Sharon** [Zie99-30]. **Shayle** [Gho93]. **Shearer** [Gun96b]. **Sheather** [Har91a]. **Shecter** [Rea93]. **Sheila** [Bel99, Zie97s]. **Shein** [Dea95]. **Shein-Chung** [Dea95]. **Sheldon** [Bab98, Fre97, Lor92, O'D97, Zie98a, Zei94]. **Shelemyahu** [Fre99, Rig93]. **Shelley** [Sau94, Zie98-38]. **Shenton** [Sin90a]. **Sherlock** [Sch91a]. **Shewhart** [Ada96, BC95, HD95, PD95, RD95b, SWG95, RD95a]. **Shewhart-Type** [BC95, HD95, PD95, RD95b, SWG95, RD95a]. **Shiavi** [Sen94b]. **Shiffler** [Zie95-50]. **Shift** [HC91]. **Shihadeh** [vT95]. **Shilliff** [Zie93-34]. **Shipley** [War90]. **Shipp** [Zie96-33]. **Shirland** [Sar94b]. **Shirley** [Ing92]. **Shiue** [Zie96-27]. **Short** [Cro92, Mor99a, God93]. **Should** [Car90b, Car92, Geo94]. **Shrinkage** [Fam99]. **Shumway** [Win90, Zie90c]. **Sided** [BT89, Van92b, BT98, Ode90]. **Sidney** [Wen93]. **Siegel** [Zie97-33]. **Sigma** [Cab94]. **Signal** [Gru97, Rie97, Sen94b, Sen94a, Sen95, Rie94b]. **Signals** [Ano00, Kun93, ME99, SBD98]. **Significance** [Nay98, Zie99-40]. **Sikorski** [Mor93b]. **Silverman** [Die92, Geo98, Qiu95]. **Similarities** [Gol98]. **Similarity** [Jol97, Koh90]. **Simiu** [Zie95o]. **Simon** [Han90, Har91a, Zie91b]. **Simonoff** [Yan97]. **Simple** [Bru91, DJ94, LN95]. **Simpson** [Dri92]. **Simulated** [Deu96]. **Simulation** [Boo94b, Dea91, Dow94, GD94, Got94c, Got94b, Jou94, Par92, Rut94, Tor94, WB94, Law92, Lor92, Zie98-32, Bre97, Dea94, LeP90b, Lor93, Zie97-29, Zie97-28]. **Simulations** [Ste87, Ste90b, Zie97n]. **Simultaneous** [CM99, Dal90, DM99a, DM99b, Gib99, Gil99, Mee90b, MER91, Spu93, Van99, Wes90]. **Sincich** [Zie94-40]. **Singh** [Zie90-28]. **Single** [Sch91c]. **Single-Stress** [Sch91c]. **Singpurwalla** [Zie96h, Zie98l]. **Sinha** [Roh91, Zie93j]. **Site** [Dow94, GD94, Got94c, Got94b, Jou94, Rut94, Tor94, WB94]. **Situations** [BC95, HD95, PD95, RD95a, RD95b, SWG95, Tsa91]. **Siu** [Nay98, Zie99-40]. **Sivia** [Fox98]. **Six** [Bog92, Cab94]. **Size** [Emp93, HC91, Hul92, Ngu96b, Sea93, Zie94c, Zie90z, Wil90a]. **Sizes** [Kva96]. **Skiadas** [Zie96a]. **Skip** [Bru96]. **Skip-Lot** [Bru96]. **Small** [Ano90f, DL90b, SS89, WW92, Zie95a]. **Small-Disturbance** [Ano90f, SS89]. **Smeyers** [Zie98w]. **Smeyers-Verbeke** [Zie98w]. **Smith** [Bar92a, Cro99, Deh90, Fox91, Gun99, KY91, Sam99b, Ter92, Zie95g, Zie96s, Zie97-34, Zie98h]. **Smooth** [Kin91]. **Smoothing** [Ale99, DeV99, Deu96, HT92, Yan96, Zie98-41, Yan97]. **Smyth** [Zie98c]. **Snell** [Dri92, Zie91q, Zie92s, Zie93-30]. **Soares** [Zie98s, Zie95r]. **Social** [Got92]. **Society** [Lew92, Wen94, Zie99-33]. **Software** [DM98, Sam99a, Soy95, Zie95-32, Zie95s, Zie96-50, Zie98t, Zie96d, Zie96-45, Zie96-33, Zie99-31, Zie99-47]. **Soil** [Coh92]. **Solution** [Hal95]. **Solving** [Don90, Fri97, MA92, Pit92, Zie96-31, Bog92, Bru95, Hey93, Mor92, Pro93a, Zie97a]. **Som** [Mor99b]. **Some** [ACV99, Bak96, CL93, DP91, FF93b, FF93a, HM93, KM94, LN95, Ros96, Tsa91, ZM94]. **Song** [Dea95]. **Song-Gui** [Dea95]. **Source** [AHT91]. **Southern** [GK93]. **Space** [Zie92p, Zie94z, Cox93].

Spagon [Zie98-40]. **Spall** [Wel90]. **Span** [Kim91]. **Sparsity** [Kun97]. **Spatial** [GC91, Koe92, Nip92, TH93, VD94, Zie94-41, Zie96-50, Zie98-38, Zie98-33, ZZ91, dV93, Cob91, Got92, Zie97-30]. **Spatially** [HNF97, Zie99t]. **SPC** [Boo94a, Hea94, Hem99, Jen92, Pro93b, Wan94, Zie94r, Cro92, HP92, NM95, God93, Mil94, Hal98, Hal94, Kra92, Kus93, Mor99a, Owe91, Pro94, Sar93, Woo92, Zie95-35, Zie95-34, dC99]. **SPC/TQM** [Pro93b]. **Special** [AWS94, Fel94, Hea94, Kra92, Luc94, WMP94a, WMP94b, Zie91p]. **Special-Cause** [AWS94, Fel94, Luc94, WMP94a, WMP94b]. **Specifications** [Bak98, Zie97-31]. **Specified** [LIV96]. **Spector** [Ko95b, Zie92n]. **Spectral** [Hag96, Kii92, Lau94a, Nan94, Per92, Per98, Cox96]. **Spectroscopy** [Zie95y, Goo92b]. **Spectrum** [Cox93, Gru90]. **Speech** [JR91]. **Speed** [Ste91]. **Spherical** [Bor95a]. **Spiegelhalter** [Ful95, Gas97]. **Spiegelman** [Zie92c, Zie94k]. **Spizzichino** [Gru95]. **Spline** [ME99, Gal92]. **Splines** [Zha94, Ize90]. **Split** [BS99, HCV98, MB98]. **Split-Lot** [MB98]. **Split-Plot** [BS99, HCV98]. **Sposito** [Bro90a]. **Spreadsheet** [Zie98-39]. **Sprent** [Gas94, Zie90a]. **Spurrier** [Mag96]. **Squared** [Kin97, VM91]. **Squares** [BBT90, Mar96, Mor98a, Thi91, Bay92]. **Srivastava** [Bil91, Chi91, Zie90s]. **Stability** [RH92]. **Staff** [Zie96w, Zie96x, Zie97m, Zie97-36]. **Stage** [HLD98, ST90a, Sto92]. **Stahel** [Zie93k, Zie94-29]. **Stamatis** [Sch96b]. **Stamping** [JS99]. **Standard** [BA96, Spu92, Tat97, TW96, Tsa91]. **Standard-Error** [TW96]. **Standards** [Cam98]. **Stanely** [Cha93]. **Stanford** [Zie95-38]. **Stangl** [Zie97d]. **Stanislav** [Zie99-46]. **Stanley** [Ing92, Zie94s]. **Stanton** [Che92]. **Stapleton** [Dea96]. **Start** [Bor97a, Zie97x, Zie99r]. **Started** [Zie98v]. **Stat** [Amm92]. **STATA** [Bie92]. **State** [Cox93, Zie94z, Zie92p]. **State-Space** [Zie94z]. **Stationary** [CCC90, Luc98, Zha98]. **Statistic** [Ano00, SBD98]. **Statistical** [Ada94, Ada96, Alt99, Amm92, Bar91, Bas99, Bel95, Ber96a, Boo98, Boo99, BK92a, BK92b, Bre95b, Bro90a, Bru91, Bru92a, Cam98, CFRH99, CHB90, Cha98, Cly94, CR96, CC95, Cro99, Cry90, Das93, Dea96, Der90, Dic97, DP91, DGTZ97a, DGTZ97b, Dun97, EM99, FF93b, FF93a, FB94, Ful95, Gas94, GR97, Glo95, Gun94a, Hal94, Han93, Hap92, Har91c, HM93, Hei90, Hes91, Hin97, Hul97, Kal93, KMP95, KB94, Kat98, Kia92a, Ko95a, LaL95, LSBW95b, LSBW95a, Law92, Law96, Len93, Len95, Lor93, LPY97, Mac92, MA92, Mat97, McL95, Mee91b, Mi99, Nem97, OM96a, OM96b, Oli97, Per97, PE97, Pro92b, Ray93, Rig93, Roh91, Ruk97b, Sai96, Sau92, Sau98, Sch95, Sen94b, Sen95, Sha98, Sho90, Sim97, Sim91, Spe96b, Sri93, Swe96, Tam96, TI99]. **Statistical** [Tho90b, Tuc92, TFV93, Tuc96, VTFD92, VV92, Van96b, WG92, War90, Win90, WH97, Woo91, Zha98, Zie90p, Zie90h, Zie90z, Zie90y, Zie90a, Zie91a, Zie91j, Zie92b, Zie92g, Zie93z, Zie93-38, Zie93s, Zie94e, Zie94f, Zie94-28, Zie94-29, Zie94j, Zie94a, Zie94-34, Zie95-29, Zie96j, Zie97p, Zie97o, Zie97-44, Zie98o, Zie98-35, Zie98q, Zie98p, Zie98d, Zie98z, Zie99-31, Zie99u, Zie99c, Zie99p, Zie99-35, Zie99n, Zie99g, Zie91r, Acr97, Ada93, Ang91c, Arm93, Bar92a, Bas97, Beg90, Boo94a, Bor97b, Bow91, Boy90, Bru93b, Bry92, Bzi97, Che91,

Coa94, Coh92, Col93, Dov93, Edg98, Fal99, Fri97, Gho94, Glo99, Got94a, Gru97, Has91, Hec99, Hes93, Hey93, Hil95, Jac95, Jai95, Jon91b, Jon93, Kan95, Kat91, Kin93, Kle94, Koe92, Koo90, Kra90, Lam90, Lei99, Lor99, McG94]. **Statistical** [Mil99, Mil98, Moo91, Mor93b, Nay98, Nel98, O'D97, Ott90, Per92, Pfa99, Pig91, Pol93, Por97a, Pro93a, Ram96, Run90, Sar94b, Sha93, Spa99, Spe91, Vuk98, Weh95, Won94, Wu99, Wyc96, Zel94, Zie90v, Zie90t, Zie90u, Zie91r, Zie91o, Zie92q, Zie92r, Zie92s, Zie93-30, Zie93-28, Zie93-29, Zie93-27, Zie94-39, Zie94-38, Zie95-38, Zie95-37, Zie95-39, Zie95-36, Zie96-37, Zie96-41, Zie96-40, Zie96-39, Zie96-38, Zie97-32, Zie98-41, Zie98-40, Zie99-38, Zie99-37, Zie99-39, Zie99-41, Zie99-40, vT95]. **Statistician** [Aba98, Don90, Not92c, Zie96-31, Zie98-30]. **Statisticians** [Arm90, Box90, God90, Hah90, HH98a, HH98b, HK90, Hoo90, Hun90a, LeP90b, Mac90b, MTV98, Moo90, Nem98, Tri90, Wan90, Eas90]. **Statistics** [Ale91, Ale95, Bal93, Bax92, Bax96a, Ber92b, Bod97, Bro90b, Bry99, Bul96, Cly94, Cro99, Dri92, Dun90, Far92, Fox91, Fre99, Gal93, Gue90, Ham96, Har91c, Haw90, Jam96, Jen90, Kel97, LC98, Lee94, Lin99, Lit91, Liu92a, Mag96, Mi97, Mul97, Nar93, Nem92, NO96, Pan96, Rie94b, Rob90, Sar94a, Sau94, Sau97, Sch96a, Sin90b, Smi93, Sne98, Spr91, Ste98, Ste96a, Ste96b, Ste99, Taa99, Wal92a, Was91, Wat90, Wei94, Yeh93, Zie90k, Zie91m, Zie91k, Zie92a, Zie92l, Zie93c, Zie93k, Zie94h, Zie94v, Zie94-31, Zie94-45, Zie94g, Zie95v, Zie95n, Zie95-28, Zie95-50, Zie96d, Zie96-30, Zie96h, Zie96-52, Zie97o, Zie97c, Zie97z, Zie98h, Zie98j, Zie98n, Zie98l, Zie98k, Zie99k, Zie99b, Zie99-30, dVU96, Zie90-27, Zie95-50, Zie96-52, Ajm99, Ang90b, Arm92, Arn90, Ben93]. **Statistics** [Bli91, Bro90b, Buc90, Bul91, Dom90, Dre91, Fam97, Far90, Far93, Fot95, Goi96, Goo91, Gra94, Gri96, Gro92, Gun90, IHMT95, Jan94, Joh91, Lal99, Lit91, Mee91a, Moo96, Rig92b, Sch91a, Str96, Wei94, Wil90b, Wol92, Woz91, Yan97, Zie90s, Zie91b, Zie93e, Zie93m, Zie94d, Zie94y, Zie95b, Zie95f, Zie95c, Zie96p, Zie97-43, Zie98-34, Zie98-33, Zie98x, Zie98e, Zie99-27, Zie99l, Zie99w, Zie99f, Zie99r, Bie92, Boo93, Bri96, Bru95, Eas99, Fre92, Gat96, Gib91, Glo97, Goo92b, Har91b, Hes91, Ing92, Kot92, Lar95, Lei92, Loh94, Lyn94, Mye91, Rus94, Wen94, Wil98, Zie90x, Zie90w, Zie92t, Zie92u, Zie93-31, Zie94-42, Zie94-41, Zie94-40, Zie94-43, Zie95-41, Zie95-40, Zie95-50, Zie96-43, Zie96-52, Zie96-42, Zie97-34, Zie97-33, Zie97-35, Zie98-42, Zie99-42, Zie99-45, Zie99-43, Zie99-44]. **Statistics** [dV93]. **Stats** [Zie99m, Zie98-38]. **Staudte** [Har91a]. **Stechel** [Zie96-40]. **Stechel-Berger** [Zie96-40]. **Stefanski** [Arm97]. **Stein** [HH96, Oma91, Won98]. **Stenger** [Zie93-32]. **Step** [Hec96, MT92, Sar94a, Zie95b, Zie99-52]. **Step-by-Step** [Hec96, Zie95b, Zie99-52]. **Step-Loss** [MT92]. **Stepanski** [Zie95b]. **Stephanie** [Zie99q]. **Stephen** [Bay95, Bru95, Cal94, Nem92, Spa99, Zie90y, Zie94s, Zie94n, Zie99-28, Zie99-39]. **Stephens** [Bru96, Sto96]. **Stepping** [Ano90e, Sim88]. **Steps** [Bog92]. **Stepwise** [VS98]. **Steve** [Zie95-36, Zie95-27]. **Steven** [Kus93, Pan92, Por97b, Sar93, Sen95, Zie93y, Zie99m]. **Stevens** [Bal93]. **Stinson** [Zie98-47]. **Stochastic** [Ano97e, Bax95, Fre94, Goo95, Huz95,

Ked98, LH97, Luc98, Rag91, Rag93, SN95, Tor99, Weh91, Weh93, Wen93, Zie96a, Fot96, Fre93, Fre97, Ked96, Kir92, Mad96, Zie96-44, Zie99-46]. **Stock** [Zie97-36]. **Stokes** [Zie96i, Zie98v]. **Straight** [Aye98]. **Straker** [Zie97a]. **Strata** [Zie90h]. **Strategic** [Zie99-47]. **Strategies** [KTTS90]. **Strategy** [STR99]. **Stratton** [Zie99a]. **Strength** [WJ92]. **Stress** [DH92, Sam99a, Sch91c, WJ92]. **Stress-Strength** [WJ92]. **Strip** [Mil97]. **Strip-Plot** [Mil97]. **Stroup** [Zie97-27]. **Structural** [Ang92, Gri97a, Hec96, Zie97b]. **Structure** [LBB96, Rag95]. **Structures** [OUH93, Sha97c]. **Stuart** [Stu94]. **Studentized** [PF91]. **Studies** [BL97, KTTS90, Nem95, RH92, VV99, Zie96h, Zie98l, Zie98-40, Zie99f, Gle91, Jen93, Zie90i, Zie94p, Zie94c, Zie96b, Zie96-28, Zie99-37]. **Study** [Kaf94, RH95, Sto92, YE94, Ang91b]. **Studying** [Moo99]. **Subba** [Zie98g]. **Subhash** [Mar97]. **Subir** [Zie91o]. **Subject** [USM99, Yas95]. **Subjective** [Kat98, Zie95-42]. **Subrahmaniam** [Wel93, Rab92]. **Subset** [Bre95a, Roe91, Sch92a]. **Subset-Selected** [Roe91]. **Subsets** [STR99]. **Subspaces** [CC95]. **Subsystems** [MW90]. **Success** [Zie97v, Neu99]. **Sudhakar** [Cox93]. **Sudman** [Zie93r]. **Sufi** [Elt90]. **Suhir** [Tho99]. **Sum** [SGW96]. **Summary** [HH98b]. **Summed** [BBT90]. **Summers** [Maz98]. **Sung** [Tan98]. **Supersaturated** [ACV99, LW97, Lin93b, Lin95b, Ngu96a]. **Supplement** [Gun90, Zie92g]. **Supportability** [Lyn95]. **Surface** [BA96, CCC90, DL90b, Gun96a, Khu92, MME98, MMY93, Pro92a, SE93, VM91]. **Surfaces** [And90, Zie90e, Zie97y]. **Survey** [Min93, Zie90-28, Zie96-47, Zie96g, Zie97q, Zie99-52, Coh92, Zie90-28, Zie93-33, Zie93-32, Zie98-43, Zie99-48]. **Surveys** [Zie99-52, Zie90-28, Mad98, Sau97, Zie93t, Zie93r, Zie96-29, Zie99v, Zie99q]. **Survival** [CR93, Gol99, WL91, Zie93-27, Zie95x, Zie96b, Zie97r, Zie98r, Car97, Rao98, Zie97-38, Zie97-37, Zie98-44]. **Survivors** [Zie98-44]. **Susan** [LC94]. **Suter** [Zie95m]. **Sutherland** [Kin93]. **Sweeny** [Pan96]. **Sweeting** [Bar92a]. **Swift** [Zie99-29, Boo94b, Dun97]. **Sybil** [Zie91g]. **Sylvie** [Bor97b]. **Symmetric** [Loh92]. **Symposium** [Bro90b]. **Synthesis** [Emp97, Len93, Ano97f, Ano97f, Ano97e, Emp97, Zie95-44]. **System** [Ano98e, DP97, EMSD91, Gri97b, Hec96, Hei90, Kva96, Rag98, RM95, Taa91, Viv91, Zie92n, Zie92o, Zie93z, Zie95b, Zie97-27, Zie97-36, Zie99-35, Ale91, Hec90, Zie95u, Zie96w, Zie96i, Zie96x, Zie97-32, Zie97-38, Zie97m, Zie99-48, Bar92b, Van96b]. **System-Based** [EMSD91]. **Systematic** [CM93b, CM93a, FL97, Gun93, HO93, Hah93, LST93, Lin95b]. **Systems** [Ano97e, AHT91, Bil94, Cox93, Dog99, Goo95, Gri99, Jon92, LT96, Law92, LH97, MW90, Sam99a, SDP$^+$95, SP95, Tor95, Zie99-50, Bro92, Cry90, Fot96, Kir93, Koh90, Rag95, She90a, She90b, Smi93, Van91, Weh93, Dea91].

T [Aba98, Ang91a, Bar92a, Bzi97, Cox96, Cra94, Gal95, Gol99, Hag91, Hey92, Job99, Liu92b, Mi99, Not92a, Not92c, Oli98, Ott90, Owe91, Por97a, Pro94, Rus94, Sac93, Sam99a, She90b, Sho90, Str96, Wen94, Zie90e, Zie93v, Zie93-27, Zie94g, Zie94l, Zie94-40, Zie95y, Zie95l, Zie96u, Zie98-38, Zie98g,

Zie99n, Zie99x]. **Tabak** [Weh91]. **Taber** [Zie97g]. **Tables** [Ano90e, Nel93, Sim88, Zie90u, Zie97o, Alb93, Zie99x]. **Taguchi** [Coo96b, Edg92, Pie90b, Pro92b, She90b, GD91, NAM+92, NW93, Stu94, Zie91p, Zie97-39]. **Tague** [Zie95-45]. **Tai** [Loh92]. **Takeaki** [Roh91]. **Talbot** [Pit92]. **Talk** [Aye98]. **Tammy** [Zie99-51]. **Tanabe** [Zie99-36]. **Tandberg** [Zie95y]. **Taneja** [Joh91]. **Tanner** [Mee91a, Ruk97b]. **Tanur** [Zie90w]. **Tanya** [Zie99-31]. **Tapiero** [Kal98]. **Tarter** [Wha95]. **Taylor** [Fre94, Dov93, Ful95, Lew93, She90a, Tan93]. **Team** [Mor92, Zie93-34, Jon90, Jon91b]. **Teams** [Zie94l]. **Teboul** [Zie93q]. **Technical** [Dog99, Zie92j, Zie97-36]. **Technique** [KD97, Pap95]. **Techniques** [Bay99, DeV99, Dov93, Fot95, Kva96, Par92, Rao98, Tor95, Zie97-39, Zie98r, Zie99-31, GJMS+95, Bre96, Cox96, LC98, Mar97, Mor99b]. **Technologies** [Sha92]. **Technologists** [Ram99]. **Technology** [Ada92, Bon95, LPR92, Nem95, Mar94, Zie91g]. **Technometrics** [BT98, DPL+94, HR94, Lin95a, Sen99b, Sin92, Ste90b]. **Telephone** [Zie90-28]. **Tenner** [Zie93-37, Zie97u]. **Term** [Zie98-44]. **Terms** [VM91, Zie96o, Zie91a]. **Terraza** [Dow95, Ord96]. **Terry** [San98]. **Test** [AKO94, AAK99, CWWR97, CC99, Col92, EMSD91, ES94, LN97, MQ91, Mee91b, ML95, Ney94, Rag98, RM95, Sin83, WN97, Wol95, Sin92]. **Test-Based** [CWWR97]. **Testing** [Bry92, Cha93, DM98, DH92, GS95, KGK90, KS93, LBB96, Len90, MA92, Mee91b, Nik95, Pol93, Sam90, ST90a, Sch94a, VS96, VS98, WJ92, Zie96-34, Har91a, Hor98, Hul92, Kin97, Spe91]. **Tests** [Bak96, BE94, CB93, CS93, Dow95, EM95, GK90, HC91, Kin91, MEL98, MM94, Nik95, Ord96, Sch91c, SGW96, YE94, ZM94, Ale99, Roh91, Ste90c, Zie94a, Zie98-37]. **Text** [Car97, Kia95a]. **Textbook** [Mac90a]. **Their** [LLP+99, Zie92a]. **Theo** [Zie90p]. **Theoretic** [Str96]. **Theories** [Bil94]. **Theory** [Ang90a, Ang90b, Ano90f, Bax92, Bil92, Bor95b, Chi91, Chr97, Col93, Cry90, Dea95, Dog99, Gri99, Har91b, Jac95, Jon92, Kia92a, Lei92, Mas99, Mor93a, Ram93, Rie94a, Sch96b, Sea90, Sen99a, Sha93, Sin97, SS89, Van96b, Won98, Zad95, Zie90v, Zie92v, Zie92s, Zie93-30, Zie95o, Zie95z, Zie97-35, Zie98-41, Zie98d, Zie98e, Car90a, Hag90, Per92, Sai96, Sen95, Sys99, Wu99, Zie94-45, Mad98, Zie99-49]. **There** [Arm90]. **Theresa** [Zie99k]. **Thermal** [Tho94]. **Thermal-Battery** [Tho94]. **Therrien** [Mag90]. **Thiebaux** [Zie96-38]. **Think** [Bul91, Dom90]. **Thinking** [Che95, Koo90, Zie99-41, Per97]. **Thomas** [Car90b, Car92, Cha92, Edg92, Fri97, Gre94, Hea94, Lam90, Osb97, Ruk97a, Sim91, Spe96a, Tam96, Wan94, Web90, Zie95-30, Zie96-45, Zie99q]. **Thombs** [Mag96]. **Thompson** [Gho94, Por97b, Boo90, Mad98, Pie90a, Zie93y]. **Three** [HL97]. **Three-Parameter** [HL97]. **Thriyambakam** [Kus98]. **Tibshirani** [Gri95, dV92]. **Tichý** [Gri97a]. **Tierney** [Amm92]. **Tijms** [Mad96, Spr91]. **Tim** [Sho90]. **Time** [Ada91, Ang92, Dic91, Dic97, Dow95, Elt90, Gri99, GSH98, Joh90, Jol93, Kal93, LT96, Li97, LM93, LPY97, Nip92, Ord96, Ped98, Per98, Sha97b, Ste91, Tim95, Wel90, Win90, Zha92, Zie90c, Zie92p, Zie94t, Zie94x, Zie95e,

Zie95l, Zie97l, Zie97-40, Zie98f, Zie98g, Boo92, Boo94b, Boo97, Cab98, Chu91, Ens95, Fre95, Har92a, Tso92, Zie92v, Zie94-34, Zie95-46, Zie97-42].
Time-to-Failure [LM93, LPY97]. **Times** [HLS98, Rag98]. **Timm** [Zie99-51]. **Timothy** [Neu99, Zie99t]. **Timpone** [Zie97g]. **Titterington** [LH97, Weh93]. **Toby** [Bre95b]. **Todeschini** [Zie96l]. **Tolerance**
[BT89, CR91, KM99, Mee90b, MER91, Van92b, WI94, BT98, Bak98].
Tolerancing [Bis97]. **Tolley** [Kan95]. **Ton** [Gol98]. **Tong** [Ize91]. **Tonnage** [JS99]. **Tool** [McL95, Zie99d, vN90]. **Toolbox**
[Zie97a, Bel95, SG99, Zie95-45]. **Tools**
[Bor97b, Bre96, FF93b, FF93a, HM93, Mat98, Nem92, Owe91, Pro94, Zie94h, Zie95-31, Bru91, Han93, Zie94l, Zie99-50, Bre90, Ruk97b]. **Top** [HS97].
Topics [Ada96, Hea94, Ver90]. **Total**
[HH96, Pan96, Zie99-29, Zie92w, Zie93-37, Zie93-36, Zie99-50]. **Toxicologists** [Zie93-31]. **Toxicology** [Zie95-41, Zie98-42]. **TQM**
[HH96, Pro93b, Boo94a, Zie95k, Zie94-44]. **Trace** [McA90]. **Trait** [Gol98].
Transformation [CR91, KSJ96, Roc93, TW90, TW92, VB94a].
Transformation-Model [TW92]. **Transformations** [Wei90]. **Treatment**
[LBB96, Spu92]. **Treatments** [Spu92]. **Tree** [Jol97]. **Trend** [AD96]. **Trends**
[Joh90, LT96, MPR99]. **Trevor** [Hes93, Jol96, dV92]. **Trewin** [Zie98-43].
Trials [Zie94n, Zie96b, Zie91q]. **Trimble** [Zie96-51]. **Triola** [Far90]. **Trivedi**
[Pet99]. **Troia** [Zie95r]. **Troubleshooting** [Hem99, Ram91]. **True** [WI94].
Truncated [Rao98, Mor93a]. **Truncation** [MJ91]. **Truth** [Eas99]. **Tsong**
[Kin93]. **Tsong-how** [Kin93]. **Tsui** [Lor99]. **Tu** [Hes97]. **Tuck** [SDP$^+$95].
Tuckwell [Hag90]. **Tufte** [Baj98, Sco92]. **Tukey**
[Zie91f, Zie91e, Zie95-43, Sch93c, Sch93b, Zie91f, Zie91e, Zie93e, Zie95-43].
Tumay [Bre97]. **Tumbelty** [Hal98]. **Tunner** [Ada92]. **Turbulence** [Rag93].
Turkman [Zie94-42, Zie99-45, Zie99-44]. **Turlach** [Hin97]. **Turner** [Bod97].
Tutorial [Fox98]. **Tutorials** [Zie94k, Zie92c]. **Tutz** [Glo95, Zie94e]. **Two**
[AAK99, Ano90e, BT89, BT98, BS99, CWWR97, Car95, DL90a, EM95, FL97, HP97, Hea94, HLD98, HCV98, LIV96, Ode90, RL95, Sch91c, ST90a, Sim88, SS97, VV99, Wes90, WC92]. **Two-Component** [RL95]. **Two-Level**
[BS99, DL90a, FL97, HCV98, LIV96, Sch91c, WC92]. **Two-Sample**
[CWWR97, HP97]. **Two-Sided** [BT89, BT98, Ode90]. **Two-Stage**
[HLD98, ST90a]. **Two-Way** [Ano90e, Car95, Sim88, SS97, VV99]. **Type**
[BC95, HD95, PD95, RD95a, RD95b, Sin92, SWG95, WN97, Yas92, Sin83].

U [Zie96-52, Lei92]. **U-Statistics** [Lei92]. **U.S** [Zie95-29]. **U.S./Japan**
[Zie95-29]. **Ulf** [Kel97]. **Unbalanced** [KM94]. **Uncertainty**
[Cam98, Kah94, Liu92a, ME96, Zie90p, Zie95g, Zie96n, Zie95-47].
Uncontrollable [RH95]. **Undamped** [Kun93]. **Understanding**
[Cro99, SDP$^+$95, Arm92, Lau94b, Pan92, Ram99, Voe94, Zie92x, Zie93-38, Zie96-48, Zie96-49]. **Unequal** [CC99, Dal90]. **Unidentified** [Pan99]. **Unified**
[Sam99a, Sim97]. **Univariate**
[Ber96b, Chu91, Cox96, Fam95, HL95, Zie95b, Bru94, Dow95, Zie99-51].

University [Jon90, Jon91b]. **Unknown** [Dal90, Zie90w]. **Unreplicated** [BH97, LN97, Pan99]. **Update** [Zie98o, Zie98p]. **Upton** [Cob91]. **Urban** [Len95]. **Usama** [Zie98c]. **Use** [Ano91e, Bru91, Dow94, GD94, Got94c, Got94b, Haw91a, Hes91, Jou94, Kun97, Lau94a, Lit91, MMY93, Pro92a, Rut94, Tor94, WB94, Zie90z]. **Used** [CR93, DS93]. **Useful** [CCC90, Ros96]. **User** [Lei93, LIV96, Zie95s, Zie98t]. **User-Specified** [LIV96]. **Uses** [Nel93]. **Ushakov** [Pap96]. **Using** [Ada91, AAK99, Bre95a, BHS90, Dea91, DGTZ97a, DGTZ97b, Gan95, GC91, Gun96a, Hec96, Hoc94, Hul97, JS99, Kan95, Ko95a, Kus93, LM93, Lwi94, Men91, PE97, Sar93, STR99, Ste87, SW95, Tho90b, Van96a, WH97, Yas92, Zie95b, Zie96m, Zie96w, Zie96i, Zie96x, Zie97-32, Zie97-38, Zie97m, Zie97-29, Zie97p, Zie97-36, Zie98i, Zie99-47, Zie99-48, GJMS$^+$95, Ste90b, ZM94, Pan96]. **Uthurusamy** [Zie98c]. **Utility** [Nay98]. **Utts** [Fam97]. **Uwe** [Tor99].

V [Bas97, Cam98, Fre93, Lar95, Oli98, Pap96, Rie94a, Rig99, Sai96, Sam90, Sen97, Yak97, Zie90o, Zie90q, Zie92e, Zie94-42, Zie97h, Zie97-42, Zie98t, Zie99-45, DL90a]. **Vach** [Kia95b]. **Vajda** [Tho90a]. **Valerii** [Rig99]. **Valid** [Sch92b]. **Validation** [Len95, Zie97v]. **Validity** [Nay98]. **Valkó** [Tho90a]. **Valsecchi** [Zie96b]. **Value** [Ang90a, Cha93, Sne98, Zie95o, Zie96y, Zie98-48]. **Valued** [Ped98]. **Values** [Gri90, Kia95b, Nel93, WI94, ZM94]. **Vance** [MLV92]. **Vandeginote** [Zie98w]. **Vandeginste** [Mac90a]. **Vanzetti** [Zie98b]. **Vapnik** [Sai96, Wu99]. **Vardeman** [Spa99, Bru95, Zie95-38]. **Vari** [Pap95]. **Variability** [BH93]. **Variable** [Bay92, CHW97, Coo96a, DH92, Hea90, LS90a, Mee90a, RH95, RAA90a, RAA90b, Woo90, Zie93o, Alt99]. **Variable-Selection** [CHW97]. **Variable-Stress** [DH92]. **Variables** [Ano91f, CS92, ES94, HL95, Haw91b, MT92, OUH93, SD90, SW95, Tho91, Tho92a, Cal98, God95, Zie94-35, vT95]. **Variably** [KS93]. **Variance** [Ano99e, BNC87, Gan95, KM94, Kia93a, Kun97, LBB96, Mee90b, Pot93, RWHH97, SS97, Yas94, Bor95a, ZM94, Emp99, Sch93c, Sch93b, Gho93]. **Variance-Function** [RWHH97]. **Variances** [CC99, Dal90, Spu92, WN97]. **Variate** [Gol90, Kii92]. **Variation** [Lew93, Voe94, Bri96, Cam98]. **Variowin** [Zie96-50]. **Vavra** [San98]. **Vecchio** [Ram99]. **Vega** [Zie98-38]. **Velu** [Tim99]. **Venables** [Jam96]. **Verbeke** [Ste99, Zie98w]. **Verification** [Dav99]. **Vermunt** [Zie98-28]. **Veronica** [Zie98-40]. **versus** [Luc98]. **Very** [KMP95]. **Via** [Ano90e, Sim88, RM95, DSSU98]. **Vic** [Bre95b, Len93, Min93, Zie99-44]. **Victor** [Bru91, Woo91]. **Viertl** [Spe91]. **View** [FF93b, FF93a, HM93, Lam98, LSBW95b, LSBW95a, Sim97]. **VIII** [Zie95-43]. **Vincent** [Bro90a, Zie99-29]. **Vining** [Mil99]. **Vinod** [Zie94v]. **Virgil** [Gre94]. **Vision** [Pro93b]. **Visual** [Baj98]. **Visualization** [Ram93]. **Visualizing** [Hec99, Pfa99, Gun94b]. **Viswanadham** [Kir93]. **Vladimir** [Van91, Wu99]. **Vol** [Cob91, KY91, LeP90b, Nem95, Sch92c, Sin90b]. **Voltage** [HL97]. **Volume** [Ano90l, Ano91k, Ano92i, Ano93k, Ano94i, Ano95i, Ano96i, Ano97k, Ano98j, Ano99k, Ber96b, Fam95, Hea94, Kia92b, Kia93b, LaL95, Sch93a, Tom95, Wan94, Zie90h, Zie90k, Zie91f, Zie91e, Zie91h,

Zie94-45, Zie95-43, Zie96h, Zie98o, Zie98p, Zie98l, Zie98k, vT91, Zie92g]. **Volumes** [Zie96-47]. **Vose** [Zie99-34].

W [Beg90, Boo90, Bru93b, Bru94, Bru97, Cal94, Cha92, Che92, Chu91, Col93, DeV99, Dea94, Fox94, Gas97, Gut92, Har91b, Hin97, Jam96, Kia90, Kia95b, Kin93, LeP90b, Len90, Lin90, Lyn99, Mag90, Mar99, Mi99, Nar93, Pit92, Pol93, Pro96, Qiu95, Ram93, Sam99a, Sch93c, Sch93b, Sha95, Sha97c, Thi91, Wit94, Won94, Woz91, Zie90-28, Zie90-27, Zie90w, Zie90g, Zie91f, Zie91e, Zie92c, Zie93t, Zie93w, Zie93k, Zie93i, Zie94k, Zie94-28, Zie94-29, Zie94g, Zie94-40, Zie95p, Zie95e, Zie96s, Zie97-27, Zie97-34, Zie97f, Zie97-44, Zie98-42, Zie98-41, Zie98y, Zie98m, Zie99f, Zie99-43, Zie99c]. **Wackernagel** [Mye96]. **Wadsworth** [Bar91, Zie99p]. **Wafer** [HNF97]. **Wah** [Lor99]. **Wahba** [Gal92]. **Waksberg** [Zie90-28]. **Walden** [Rus94, Cox96]. **Walford** [Sch96c]. **Walker** [Zie99g]. **Wall** [Has91]. **Wallgren** [Kel97]. **Walpole** [Rob90, Zie94-31, Zie99-30]. **Walter** [Dow95, Ord96, Ped98, Taa99, Wen94, Zie98-42, Zie99f]. **Waltraud** [Tor99]. **Wan** [Ale98]. **Wand** [Yan96]. **Wander** [Van96a]. **Wang** [Dea95, Loh92, Das93, Str96]. **Wardell** [YWMP95]. **Wardrop** [Bri96]. **Warehousing** [Zie99-47]. **Warranty** [KLR91]. **Warren** [Gun90, Zie99t]. **Wasserman** [Kia90, Zie92b, Zie97-44, Zie97-44]. **Waste** [Dow94, GD94, Got94c, Got94b, Jou94, Rut94, Tor94, WB94]. **Water** [Got94a]. **Watson** [McL95]. **Watts** [Mil90]. **Wavelet** [Han98]. **Wavelets** [JS99, Zie97-43]. **Way** [Ano90e, Car95, Sim88, SS97, Van92b, VV99, Far92]. **Waymire** [Kir92]. **Wayne** [Dic97, Ham96, Lew93, Mee91b, Tan93, Woz91, Zie95h, Zie97-29, Zie99z]. **Weak** [Gol93]. **Weakest** [Wol95]. **Weakest-Link** [Wol95]. **Wearden** [Ing92]. **Webster** [Coh92]. **Weerahandi** [PGT95]. **Weese** [Aye98]. **Wegman** [Bro90b]. **Wegscheider** [Zie92c, Zie94k]. **Wei** [Chu91]. **Weibull** [HL97, MSF95, Zie95-48]. **Weight** [Lwi94]. **Weighted** [Bax90, DP91, FHT90, Gan95, Hes95, Hun90b, LWCR92, LS90b, LS90c, MH90, TW90, WM90]. **Weighting** [CR91, Wei90]. **Weir** [Zie90-27]. **Weisberg** [Gol95]. **Welbrock** [Zie99-47]. **Welsh** [Bas99]. **Wendell** [Hey93]. **Werner** [Zie94l]. **Wersberg** [Zie93k]. **Wesley** [Boy90]. **Wesner** [Zie96-51]. **West** [Wes92, Zie97e]. **Westergren** [Zie91c]. **Western** [Pro92b]. **Westfall** [Cha93]. **Wetherill** [Col93]. **Whats** [Zie93-35]. **Wheeler** [Bel99, Bri91, Zie93-38, Ada96, God93, Voe94, Zie92x]. **Where** [LIV96]. **Whitmore** [Zie97r]. **Whittaker** [Goo91]. **Whitten** [Kim91]. **Whys** [Zie93-35]. **Wichern** [Zie99c]. **Wiener** [DH92]. **Wignall** [Ott90]. **Wilcox** [Hor98]. **Wild** [Ber91]. **Wilks** [Ram96, Sco90]. **Willem** [Lor93]. **Willems** [Sch91b]. **Willet** [Koh90]. **William** [Alt96, Alt99, Arm92, Arm93, Buc90, Chu91, Coo96b, Gun94b, Hal98, Hec99, Jon93, Lau94b, Lee94, Nar93, Nel98, Per92, Pfa99, Pig91, Pla90, Rie97, Tor95, Zie90z, Zie92b, Zie97-41, Zie98-47, Zie99-42, Zie99t]. **Williams** [Mor97a, Rag93]. **Willmot** [Zie98-29]. **Wilrich** [Zie99n]. **Wilson**

[Zie94-36, Alt99, Pan96, Pap95, Sto92, Won94]. **Wind** [Ste91]. **Windows** [Zie97j]. **Winning** [Zie96-51]. **Winston** [Zie99z, Zie97-29]. **Wire** [Jen92]. **Witmer** [Che94]. **Wittenmark** [Har91d]. **Witzling** [Lit91]. **Wojbor** [Lin99, Sha97a, Zie99-46]. **Wojtek** [Wol96]. **Wolfe** [Zie99u]. **Wolfgang** [Eub93]. **Wolfinger** [Zie97-27, Zie99t]. **Wollongong** [Zie98u]. **Wood** [Mil98, Zie93-29]. **Woodbury** [Kan95]. **Woods** [Zie96o]. **Woodward** [Gil92]. **Work** [Zie93u]. **Working** [Eas90]. **Workman** [Goo92b]. **Workplace** [Zie94-43]. **Works** [Zie91f, Zie91e, Zie95-43, Tho92b]. **Workshop** [Mul97]. **World** [Rea93, Hoc94]. **World-Class** [Rea93]. **Worthington** [Ste90c]. **Woyczynski** [Lin99, Sha97a, Zie99-46]. **Wright** [Sho90, Zie95-42]. **Writing** [Zie94w, Zie92j]. **Wu** [Car93, LW98]. **Wulich** [Weh91]. **Wynn** [Hwa92, Zie90q].

X [Zie98-44]. **Xavier** [Bax96a]. **Xishi** [Car93]. **XploRe** [Hin97].

Yacov [Liu99]. **Yadolah** [Fai94, Zie92q]. **Yamaguchi** [And90]. **Yandell** [Gre98]. **Yao** [Fot96, Rag95]. **Yarus** [Zie96-44]. **Yates** [Gra90]. **Ye** [Han98]. **Years** [Rag93]. **Yefim** [Dog93]. **Yield** [Sam99a]. **Young** [Cha93]. **Yu** [Gri99]. **Yurij** [Boo99].

Z [Lee94]. **Zacks** [Fre99, Rig93]. **Zaven** [Law92]. **Zayadezny** [Weh91]. **Zbigniew** [Mor93b]. **Zedick** [Zie92f]. **Zeger** [Zie95d]. **Zehna** [Wit94]. **Zeisel** [Zie99-32]. **Zero** [GS92, Lam92, LLP+99]. **Zero-Defect** [GS92]. **Zero-Inflated** [Lam92, LLP+99]. **Zhang** [Sch98b]. **Zhou** [BZM96, Zie98-44]. **Zimmerman** [Kus93, Sar93, Kus93, Sar93]. **Zopounidis** [Zie96a]. **Zucchini** [Ped98]. **Zünd** [Hil95]. **Zupan** [Wol91]. **Zwanziger** [Zie98m].

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[Cab98] Errol Caby. Book review: *Time Series and Dynamic Models* by Christian Gourieroux; Alain Monfort. *Technometrics*, 40(2):158, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270656`.

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